

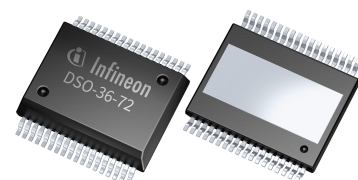
TLE92464EDHP

High accuracy four channel low-side solenoid driver IC

Quality Requirement Category: Automotive

Features

- High current control accuracy
 - $\leq \pm 3$ mA up to 1200 mA initially ($T_J = -40 - 150^\circ\text{C}$, $V_{BAT} = 9 - 16$ V)
 - $\leq \pm 0.8\%$ up to 1200 mA including aging ($T_J = -40 - 150^\circ\text{C}$, $V_{BAT} = 9 - 16$ V)
 - $\leq \pm 1\%$ up to 1500 mA including aging ($T_J = -40 - 150^\circ\text{C}$, $V_{BAT} = 6 - 18$ V)
- Four independent low side channels with integrated MOSFETs ($R_{DSon} = 115$ m Ω)
- Programmable setpoint from 0 mA to 1.5 A
- Load current including dither 1.8 A
- Current in parallel channel mode 2.7 A
- Integrated dither generator with programmable amplitude, frequency and waveform
- 15 bit current setpoint resolution
- Integrated sense resistor $R_{SHUNT} = 140$ m Ω
- Excellent immunity to large load supply voltage changes
- Operation down to 3.5 V at VDD pin
- 32 bit SPI with 8 bit CRC and SPI watchdog
- Sophisticated protection and diagnostic functions for each channel in on and off state
 - Independent thermal shutdown for each channel
 - Diagnostic Function (Open Load, Short Circuit Ground, Overcurrent)
 - Voltage monitoring
 - Overtemperature protection
- Two independent current feedback paths
- Integrated system clock with clock watchdog
- Temperature range -40°C to 175°C
- Small power package PG-DSO-36-72
- Green Product (RoHS compliant)
- Pb-free (RoHS compliant) package
- AEC-Q100 Grade 0 qualified
- ISO 26262 Safety Element out of Context for safety requirements up to ASIL C



Potential applications

- Variable force solenoids (e.g. automatic transmission and e-Axle)
- Other constant current solenoids
 - Idle air control
 - Exhaust gas recirculation
 - Vapor management valve
 - Suspension control

Product validation

Qualified for automotive applications with higher temperature requirements. Product validation according to AEC-Q100, Grade 0.

Product type & package table

Product type	Package	Marking
TLE92464EDHP	PG-DSO-36 Dual-Gauge (300 mil)	TLE92464EDHP

Description

The TLE92464EDHP is a flexible, monolithic solenoid driver IC designed for the control of linear solenoids in automatic transmissions, electronic stability control, active suspension and e-Axle applications.

The TLE92464EDHP is a four channel low-side solenoid driver IC with high current accuracy. The device provides an initial current accuracy of less than ± 3 mA up to 1200 mA current range. Including life time, the current accuracy is less than $\pm 0.8\%$ up to 1200 mA. Over the full temperature, battery and current range (1500 mA in single channel mode, 2700 mA in parallel channel mode) the control error is less than $\pm 1\%$.

The device includes the drive transistors and the current sensing resistors to minimize the number of external components. Target currents from 0 to 1500 mA can be programmed with a resolution of 15 bit. The device supports dither currents up to 1800 mA. The dither generator superimposes a triangular or trapezoidal waveform with programmable amplitude, frequency and shape on the programmed current setpoint. A 32 bit SPI interface is used to control the 4 channels and monitor the status of the diagnostic functions. The SPI communication is secured with an 8 bit CRC and a programmable timeout watchdog.

An active low reset input (RESN) is used to disable all channels and reset the internal registers to the default values. An active high enable pin (EN) enables or disables the output channels without disabling the SPI interface. A fault output pin (FAULTN) signal can be used as external interrupt to the microcontroller whenever a fault is detected.

Table of contents

	Features	1
	Potential applications	1
	Product validation	2
	Product type & package table	2
	Description	2
	Table of contents	3
1	Block diagram	6
2	Pin configuration	7
3	Electrial characteristics and parameters	9
3.1	Absolute maximum ratings	9
3.1.1	Absolute maximum voltage ratings	9
3.1.2	Absolute maximum current ratings	10
3.1.3	Absolute maximum temperature ratings	10
3.1.4	ESD Robustness	11
3.2	Functional range	11
3.2.1	Functional range	11
3.2.2	Parameter above 150°C	13
3.2.3	Thermal resistance	13
4	Functional description	14
4.1	Power supply	14
4.1.1	TDS_Power Supply	14
4.1.2	TDS_Voltage monitoring	14
4.1.3	Electrical characteristics power supply	15
4.2	Input / Output	16
4.2.1	TDS_Clock	16
4.2.2	TDS_Clock Watchdog	17
4.2.3	TDS_I/O Pins	17
4.2.4	Electrical characteristics I/O	18
4.3	IC Operation states	19
4.3.1	TDS_IC Operation states	19
4.4	Channel modes	21
4.4.1	TDS_Channel Modes	21
4.4.2	Channel Modes	21
4.4.3	TDS_Measurement Mode - (4/6CHx)	21
4.4.4	TDS_Additional Information Channel Modes	21
4.5	Power stages	21
4.5.1	TDS_Channel overview - (4CHx)	21

Table of contents

4.5.2	TDS_Parallel channel operation - (4CHx)	22
4.5.3	Electrical characteristics power stages	23
4.6	Current control	23
4.6.1	Current accuracy overview	23
4.6.2	Integrating Current Controller (ICC)	24
4.6.3	Electrical characteristics current control	28
4.7	Dither	29
4.7.1	TDS_Dither configuration	29
4.7.2	TDS_Dither parameter update	30
4.7.3	TDS_Dither PWM synchronization	31
4.7.4	TDS_Only ICC	31
4.7.5	TDS_Dither setpoint synchronization	31
4.7.6	TDS_Only ICC	32
4.7.7	TDS_Deep dither	32
4.7.8	TDS_ICC only	32
4.8	Direct Drive	32
4.8.1	TDS_Direct Drive	32
4.9	Diagnostic functions	32
4.9.1	TDS_Overview	32
4.9.2	TDS_Open Load/Short to Ground (OLSG)	34
4.9.3	TDS_OLSG Warning	36
4.9.4	TDS_Open load (OL)	37
4.9.5	TDS_Short circuit ground (SG)	37
4.9.6	TDS_Overcurrent (OC)	38
4.9.7	TDS_Register/OTP ECC	39
4.9.8	TDS_Built in Self Test (BIST)	39
4.9.9	Electrical characteristics diagnostic functions	39
4.10	Current supervision	40
4.10.1	TDS_Independent current feedback	40
4.10.2	TDS_Average feedback values	41
4.10.3	TDS_Update/Freeze Mechanism	42
4.10.4	TDS_Iavg16, minimum/maximum current/PWM feedback	43
4.11	Protection functions	44
4.11.1	TDS_Overtemperature protection	44
4.11.2	TDS_Overcurrent protection	44
4.11.3	Electrical characteristics protection functions	45
5	Serial peripheral interface (SPI)	46
5.1	Description of interface	46
5.1.1	TDS_General information	46
5.1.2	TDS_Cyclic redundancy check (CRC)	46
5.1.3	TDS_Timing Diagram	47
5.1.4	Electrical characteristics SPI interface	47

Table of contents

5.2	Description of protocol	49
5.2.1	TDS_Data flow	49
5.2.2	TDS_SPI watchdog	49
5.2.3	SPI frame definition	49
5.3	Register description	53
5.3.1	Overview of Register Types	53
5.3.2	Central registers	54
5.3.3	Channel registers	74
6	Application information	94
6.1	TDS_Application information	94
7	Package dimensions	95
7.1	TDS_Package dimensions	95
	Revision history	96
	Disclaimer	97

Block diagram

1 Block diagram

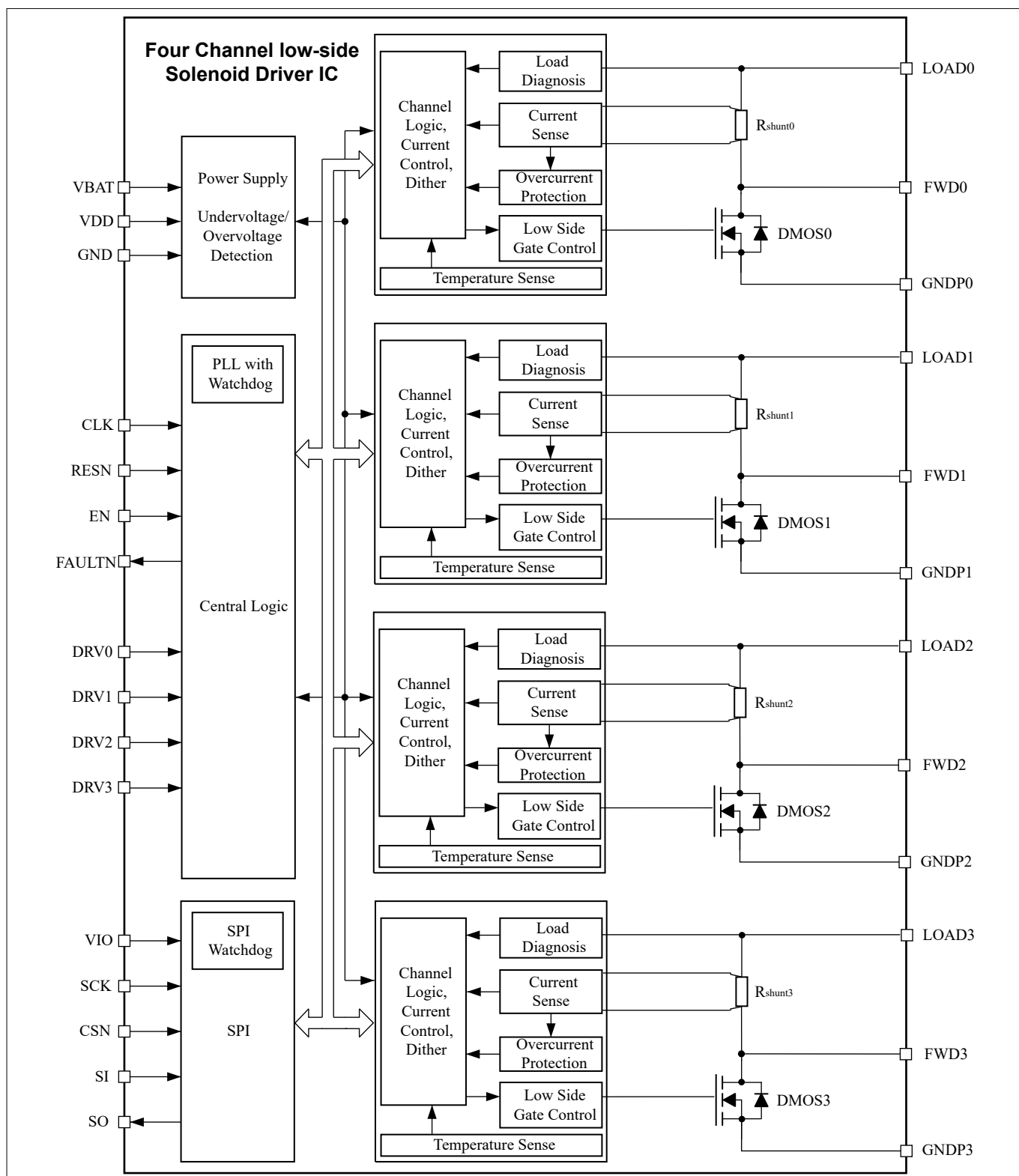


Figure 1 Block diagram

Pin configuration

2 Pin configuration

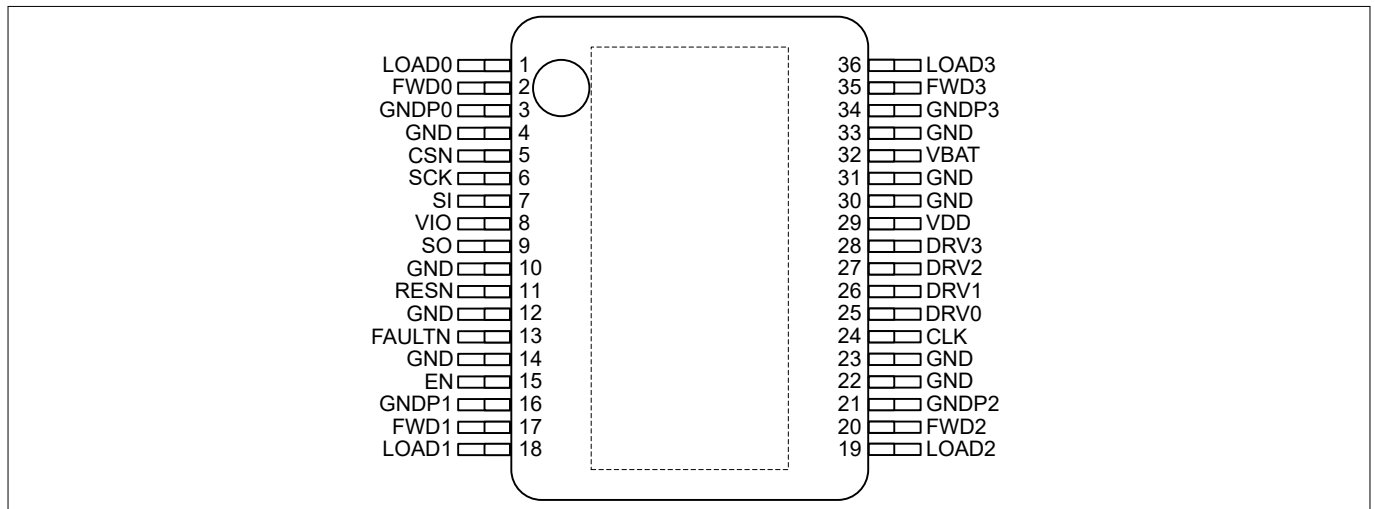


Figure 2 Pin assignment

Pin definitions and functions

Table 1 Pin definition and functions

Pin	Symbol	Function
1	LOAD0	Output; for channel 0.
2	FWD0	Free wheeling diode; for channel 0.
3	GNDP0	Ground; for channel 0 power stage.
4	GND	Ground; connect to GND.
5	CSN	SPI chip select input; digital input: 3.3 V or 5.0 V logic levels.
6	SCK	SPI clock input; digital input: 3.3 V or 5.0 V logic levels.
7	SI	SPI input; digital input: 3.3 V or 5.0 V logic levels.
8	VIO	Supply SPI Slave Out (SO) pin; connected to 3.3 V or 5.0 V supply.
9	SO	SPI output; push pull output compatible to 3.3 V or 5.0 V logic levels.
10	GND	Ground; signal ground. Internally connected to cooling tab.
11	RESN	Control input; digital input: 3.3 V or 5.0 V logic levels. Active low reset input.
12	GND	Ground; signal ground. Internally connected to cooling tab.
13	FAULTN	Status output; open drain output. In case not used, keep open.
14	GND	Ground; connect to GND.
15	EN	Control input; digital input: 3.3 V or 5.0 V logic levels. Active high enable input.
16	GNDP1	Ground; ground connection for channel 1 power stage.
17	FWD1	Free wheeling diode; for channel 1.
18	LOAD1	Output; for channel 1.
19	LOAD2	Output; for channel 2.

(table continues...)

Pin configuration

Table 1 (continued) **Pin definition and functions**

Pin	Symbol	Function
20	FWD2	Free wheeling diode; for channel 2.
21	GNDP2	Ground; ground connection for channel 2 power stage.
22	GND	Ground; connect to GND.
23	GND	Ground; signal ground. Internally connected to cooling tab.
24	CLK	Clock input; Main system clock.
25	DRV0	Direct drive input for channel 0: 3.3 V or 5.0 V logical levels.
26	DRV1	Direct drive input for channel 1: 3.3 V or 5.0 V logical levels.
27	DRV2	Direct drive input for channel 2: 3.3 V or 5.0 V logical levels.
28	DRV3	Direct drive input for channel 3: 3.3 V or 5.0 V logical levels.
29	VDD	Supply voltage; supplies digital circuits. Connected to 5.0 V supply voltage.
30	GND	Ground; signal ground. Internally connected to cooling tab.
31	GND	Ground; connect to GND
32	VBAT	Supply voltage; connected to battery voltage with reverse protection diode and filter against EMC.
33	GND	Ground; connect to GND.
34	GNDP3	Ground; for channel 3 power stage.
35	FWD3	Free wheeling diode; for channel 3.
36	LOAD3	Output; for channel 3.
37	Cooling Tap	Connect externally to GND and heat sink area

3 Electrical characteristics and parameters

3.1 Absolute maximum ratings

3.1.1 Absolute maximum voltage ratings

Table 2 Absolute maximum voltage ratings

$T_J = -40^{\circ}\text{C}$ to 150°C ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Max. supply voltage (VDD)	$V_{DD,max}$	-0.3	–	19	V	
Max. supply voltage (VBAT)	$V_{BAT,max}$	-0.3	–	40	V	
Max. supply voltage (VIO)	$V_{VIO,max}$	-0.3	–	19	V	
Max. digital input pin voltage (CLK, RESN, EN, DRVx, SCK, CSN, SI)	$V_{CLK,max}$ $V_{RESN,max}$ $V_{EN,max}$ $V_{DRVx,max}$ $V_{SCK,max}$ $V_{CSN,max}$ $V_{SI,max}$	-0.3	–	19	V	
Max. open drain output voltage (FAULTN)	$V_{FAULTN,max}$	-0.3	–	19	V	
Max. Push Pull Output (SO)	$V_{SO,max}$	-0.3	–	19	V	
Max. LOADx voltage	$V_{LOADx,max}$	-0.3 ¹⁾	–	40	V	¹⁾ During negative pulses ($V_{LOADx} < -0.3$ V) the maximum energy of $E_{LOADx} = V_{LOADx} * (I_{LOADx} + I_{FWDx}) * t_{pulse} \leq 2$ mJ shall not be violated.
Max. FWDx voltage	$V_{FWDx,max}$	-0.3 ¹⁾	–	40	V	¹⁾ During negative pulses ($V_{FWDx} < -0.3$ V) the maximum energy of $E_{FWDx} = V_{FWDx} * (I_{LOADx} + I_{FWDx}) * t_{pulse} \leq 2$ mJ shall not be violated.
Max. GNDPx voltage	$V_{GNDPx,max}$	-0.3	–	0.3	V	

Electrical characteristics and parameters

3.1.2 Absolute maximum current ratings

Table 3 Absolute maximum current ratings

$T_J = -40^{\circ}\text{C}$ to 150°C ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Max. current range	$I_{\text{FWDx,max}}$ $I_{\text{LOADx,max}}$	-2	–	2	A	DC In the case of an active overcurrent shutdown the specification at the LOADx pin can be exceeded.
Max. Output Current (FAULTN)	$I_{\text{FAULTN,max}}$	-5	–	0	mA	
Max. output current (SO)	$I_{\text{SO,max}}$	-5	-	5	mA	DC
Max. input current (CLK, RESN, EN, DRVx, SCK, CSN, SI)	$I_{\text{CLK,max}}$ $I_{\text{RESN,max}}$ $I_{\text{EN,max}}$ $I_{\text{DRVx,max}}$ $I_{\text{SCK,max}}$ $I_{\text{CSN,max}}$ $I_{\text{SI,max}}$	-5	0	5	mA	Maximum allowed forward and reverse current through ESD structure.

3.1.2.1 TDS_max_rating

Note: Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as “outside” normal operating range. Protection functions are not designed for continuous repetitive operation.

3.1.3 Absolute maximum temperature ratings

Table 4 Absolute maximum temperature ratings

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Junction temperature (T _J)	T_J	-40	–	150	°C	
Extended junction temperature (T _J extended)	T_{Jext}	150	–	175	°C	parameter deviations are possible

(table continues...)

Electrical characteristics and parameters

Table 4 (continued) **Absolute maximum temperature ratings**

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Storage temperature (TSTG)	T_{STG}	-55	–	150	°C	

3.1.4 ESD Robustness

Table 5 **ESD Robustness**

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
ESD robustness HBM (all pins)	V_{HBMall}	-2	–	2	kV	ESD robustness Human Body Model (HBM) according to ANSI/ESDA/JEDEC JS-001.
ESD robustness HBM (VBAT, LOADx)	$V_{HBMglobal}$	-4	–	4	kV	VBAT, LOADx vs. all Grounds shorted ESD robustness Human Body Model (HBM) according to ANSI/ESDA/JEDEC JS-001.
ESD robustness CDM (all pins)	V_{CDMall}	-500	–	500	V	ESD robustness Charged Device Model (CDM) according to JEDEC JESD22-C101
ESD robustness CDM (corner pins)	$V_{CDMcorner}$	-750	–	750	V	ESD robustness Charged Device Model (CDM) according to JEDEC JESD22-C101

3.2 Functional range

3.2.1 Functional range

Table 6 **Functional range**

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Functional range (VDD)	V_{DD}	4.5	–	5.5	V	
Extended Functional range (VDD)	$V_{DD,ext}$	3.5	–	19	V	Outside of the normal Functional Range of V_{DD} : $V_{DD} < V_{DD,UV,TH}$: SPI communication functional; Power-stage off $V_{DD} > V_{DD,OV,TH}$: SPI communication functional; Power-stage off
Functional range (VBAT)	V_{BAT}	6	–	18	V	

(table continues...)

Electrical characteristics and parameters

Table 6 (continued) **Functional range**

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Extended functional range (VBAT)	$V_{BAT,ext}$	4	–	38	V	Outside of the normal functional V_{BAT} range parameter deviations are possible: V_{BATL} 4 V...6 V: Parameter deviation possible V_{BATH} 18 V...38 V: Parameter deviation possible
Functional range (VIO)	V_{IO}	3.0	–	5.5	V	
Extended functional range (VIO)	$V_{IO,ext}$	5.5	–	19	V	Parameter deviation possible
Functional range (FWDx)	V_{FWDx}	-0.3 ¹⁾	–	40	V	¹⁾ During negative pulses ($V_{FWDx} < -0.3$ V) the maximum energy of $E_{FWDx} = -V_{FWDx} * (I_{LOADx} + I_{FWDx}) * t_{pulse} \leq 2$ mJ shall not be violated.
Functional range (LOADx)	V_{LOADx}	-0.3 ¹⁾	–	40	V	¹⁾ During negative pulses ($V_{LOADx} < -0.3$ V) the maximum energy of $E_{LOADx} = -V_{LOADx} * (I_{LOADx} + I_{FWDx}) * t_{pulse} \leq 2$ mJ shall not be violated.
Functional range clock frequency (CLK)	f_{CLK}	1	–	8	MHz	
System clock frequency	f_{SYS}	27.5	28	28.5	MHz	For use of external clock, clock divider must be set accordingly
System clock watchdog	$f_{SYS,WD}$	27	–	29	MHz	
Target PWM frequency	f_{PWM}	110	–	4000	Hz	PWM frequency control configuration range
Junction temperature	T_J	-40	–	150	°C	
Extended junction temperature	$T_{J,ext}$	150	–	175	°C	In the temperature range of 150 - 175°C parameter deviations are possible

3.2.1.1 TDS_functional_range

Note: Within the functional range, the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given by the related "electrical characteristics" table.

Electrical characteristics and parameters

3.2.2 Parameter above 150°C

Table 7 Parameter above 150°C

$T_J = 150^\circ\text{C}$ to 175°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Shunt resistance	R_{shunt}	-	-	190	mΩ	
ON resistance	$R_{\text{DS(on)}}$	-	-	215	mΩ	
Average current control error, absolut	$I_{\text{err,absolut}}$	-6	-	6	mA	$I_{\text{set}} = 10 - 500\text{mA}$ $V_{\text{BAT}} = 13\text{V}$ Single channel operation
Average current control error, absolut - parallel	$I_{\text{err,absolut,par}}$	-12	-	12	mA	$I_{\text{set,par}} = 20 - 1000\text{ mA}$ $V_{\text{BAT}} = 13\text{V}$ Parallel channel operation
Average current control error, relative	$I_{\text{err,relative}}$	-1.2	-	1.2	%	$I_{\text{set}} > 500\text{mA}$; single channel operation $I_{\text{set,par}} > 1000\text{mA}$; parallel channel operation $V_{\text{BAT}} = 13\text{V}$
Diagnosis Current 0	I_{HS} I_{LS}	-	-	130	μA	<I_DIAG> = 00 _B

3.2.3 Thermal resistance

Table 8 Thermal resistance

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Junction to case	R_{thJC}	-	-	3	K/W	
Junction to ambient	R_{thJA}	-	18.5	-	K/W	Depending on the mounting conditions. Specified R_{thJA} value is according to JEDEC JESD51 -5, -7 at natural convection on FR4 2s2p board; the product (chip and package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70 μm, 2 x 35 μm CU).

4 Functional description

4.1 Power supply

4.1.1 TDS_Power Supply

VDD pin

The VDD pin and GND pin are the supply and ground pins for the digital circuit blocks. The current through these pins contain high frequency components. Decoupling with ceramic capacitors and careful PCB layout are required to obtain good EMC performance.

VIO pin

The VIO pin supplies the SPI output pin (SO). It should be connected to the I/O supply of the microcontroller (3.3 V or 5.0 V). The VIO voltage level can be configured by the <VIO_SEL> bit in the GLOBAL_CONFIG register.

VBAT pin

The VBAT pin is an input pin used to measure and monitor the battery voltage and feed diagnosis current source. The pin should be connected to the reverse protected battery rail and decoupled with a ceramic capacitor.

GND/GNDP pin

GND pins are the ground pins for the logic while the GNDP pins are the power ground pins for the power stages. It is recommended to connect all GNDP pins to the GND net externally.

Power On Reset

An internal power on reset (POR) circuit holds the device in a reset state if the internal logic is not operational due to undervoltage. The power on reset is released after all supplies are within their functional range and the Reset Duration Time t_{POR} has elapsed. The SPI interface can be accessed after the power on reset time. Any power on reset will set the bit <POR_EVENT> in the GLOBAL_DIAG0 register to 1. This can be used to check whether a power on reset has happened since the bit was set to 0.

4.1.2 TDS_Voltage monitoring

The voltage levels of the supply pins V_{BAT} , V_{IO} and V_{DD} and all internal voltages (ADC reference voltages, internal supply voltages) are monitored. A voltage fault is detected if a voltage exceeds the corresponding overvoltage (OV) threshold or falls below the respective undervoltage (UV) threshold. Apart from a VBAT OV/UV, an under/overvoltage fault disables the output stages by setting all <EN_CH> bits to "0". Apart from a V_{BAT} and internal pre-regulator (<VPRE_OV>) fault, an OV/UV fault condition causes the device to enter the Operation State Config Mode.

External supply voltage (V_{BAT} , V_{IO} , V_{DD}) faults are indicated by setting the corresponding indication bit in the GLOBAL_DIAG0 register to 1 while IC internal voltage faults are listed in the GLOBAL_DIAG1 register. Voltage fault indication bits are cleared on write only. The bit <SUP_NOK_INT> and <SUP_NOK_EXT> in the FB_STAT register provide a summarized indication if any internal or external voltage fault has been detected.

The under and overvoltage thresholds of V_{BAT} can be adapted and be set in the VBAT_TH register.

$$V_{BAT,UV,TH} = <VBAT_UV_TH> \cdot 0.16208V$$
$$V_{BAT,OV,TH} = <VBAT_OV_TH> \cdot 0.16208V$$

Equation 1

The measured voltages of V_{IO} and V_{DD} are provided in the FB_VOLTAGE1 register. The V_{BAT} voltage level can be readout from the FB_VOLTAGE2 register.

The voltage monitoring mechanism of external and internal voltages can be tested by setting the <UV_OV_SWAP> bit in the GLOBAL_CONFIG register to "1". If the test is successful, the OV/UV detection bits <VDD_OV/UV>, <VIO_OV/UV>, <VBAT_OV/UV>, <VDD2V5_OV/UV>, <VR_IREF_OV/UV>, <VPRE_OV> and

Functional description

<REF_OV/UV> are set. The power on reset (POR) due to an under or overvoltage can be tested by setting the bits <V1V5_OV_TEST> or <V1V5_UV_TEST> in the GLOBAL_CONFIG register to "1".

4.1.3 Electrical characteristics power supply

Table 9 Electrical characteristics power supply

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
VBAT current consumption normal mode	I_{VBAT}	–	–	1	mA	$V_{BAT} = 18\text{ V}$ Diagnosis off
VBAT current consumption inactive mode	$I_{VBAT,inactive}$	–	–	10	μA	$V_{BAT} = 18\text{ V}$ $V_{DD} = 0\text{ V} = V_{IO}$
VDD current consumption	I_{VDD}	10	21	30	mA	$V_{DD} = 5.5\text{ V}$
VIO current consumption	I_{VIO}	–	–	1	mA	$V_{DD} = 5.5\text{ V}$ $V_{CSN} > V_{CSN,high}$
VBAT undervoltage threshold	$V_{BAT,UV,TH}$	$(x*8-17)*0.01965$	$x*0.16208$	$(x*8+17)*0.02087$	V	$x = \text{<VBAT_UV_TH>}$ V_{BAT} voltage is falling.
VBAT overvoltage threshold	$V_{BAT,OV,TH}$	$(x*8-17)*0.01965$	$x*0.16208$	$(x*8+17)*0.02087$	V	$x = \text{<V_BAT_OV_TH>}$ V_{BAT} voltage rising.
VDD undervoltage threshold	$V_{DD,UV,TH}$	3.7	–	4.5	V	V_{DD} falling
VDD overvoltage threshold	$V_{DD,OV,TH}$	5.5	–	6.4	V	V_{DD} rising
VIO undervoltage threshold 3.3 V	$V_{IO,UV,3V3,TH}$	2.6	–	3	V	V_{IO} falling
VIO overvoltage threshold 3.3 V	$V_{IO,OV,3V3,TH}$	3.6	–	4.1	V	V_{IO} rising
VIO undervoltage threshold 5 V	$V_{IO,UV,5V,TH}$	3.7	–	4.5	V	V_{IO} falling
VIO overvoltage threshold 5 V	$V_{IO,OV,5V,TH}$	5.5	–	6.4	V	V_{IO} rising
Power on reset time initialized with RESN	t_{RESN}	–	–	0.1	ms	Logic circuits are functional after t_{RESN}

(table continues...)

Functional description

Table 9 (continued) Electrical characteristics power supply

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Power on reset time initialized with undervoltage reset	t_{POR}	–	–	10	ms	Logic circuits are functional after t_{POR}

4.2 Input / Output

4.2.1 TDS_Clock

The chip system clock f_{SYS} is generated by an integrated PLL (phase locked loop) and is used to clock the internal analog to digital converters and logic. The PLL can be either sourced by an internal oscillator or an external rectangular clock signal applied on the CLK-pin. The PLL clock source f_{CLK} can be selected by programming the <EXT_CLK> bit in the CLK_DIV register. Changing the clock source can only be done in Operation State Config Mode. During a change of the clock source, the clock watchdog is disabled and the <INIT_DONE> bit is cleared. After a successful transition of the clock source, the <INIT_DONE> bit in the FB_STAT register is set to 1 and the clock watchdog is enabled.

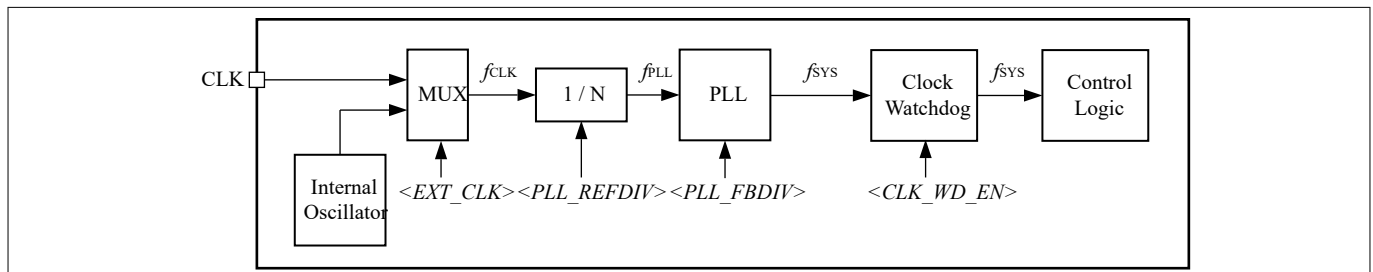


Figure 3 Clock Generation

The system clock frequency f_{SYS} is given by

$$f_{SYS} = f_{CLK} \cdot \frac{\langle PLL_FBDIV \rangle}{2 \cdot \langle PLL_REFDIV \rangle}$$

Equation 2

By selecting an external clock input, the PLL divider must be set to meet the system clock frequency f_{SYS} (see table "Clock control register settings"). If the internal clock oscillator is used, the contents of the divider bit fields are ignored. The values of PLL reference divider <PLL_REFDIV> and PLL feedback divider <PLL_FBDIV> are located in the CLK_DIV register.

$$\begin{aligned} \langle PLL_REFDIV \rangle &= \text{round}\left(\frac{f_{CLK}}{1\text{MHz}}\right) \\ \langle PLL_FBDIV \rangle &= \frac{56\text{MHz} \cdot \langle PLL_REFDIV \rangle}{f_{CLK}} \end{aligned}$$

Equation 3

Table 10 **Clock control register settings**

f_{CLK} (MHz)	<PLL_REFDIV>	<PLL_FBDIV>	f_{SYS} (MHz)	Error (%)
1	1	56	28	0.00
1.5	1	37	27.75	-0.89
2	2	56	28	0.00
2.5	2	45	28.13	0.45
3	3	56	28	0.00
3.5	3	48	28	0.00
4	4	56	28	0.00
4.5	4	50	28.13	0.45
5	5	56	28	0.00
5.5	5	51	28.05	0.18
6	6	56	28	0.00
6.5	6	52	28.17	0.60
7	7	56	28	0.00
7.5	7	52	27.86	-0.51
8	8	56	28	0.00

4.2.2 **TDS_Clock Watchdog**

The internal system clock f_{SYS} can be supervised by a separate clock watchdog. The clock watchdog can be disabled by setting the <CLK_WD_EN> bit in the GLOBAL_CONFIG register to 0. A change of the clock watchdog configuration is only possible in Config Mode and if the <INIT_DONE> bit in the FB_STAT register is 1. If the system clock f_{SYS} is outside of the allowed frequency range $f_{SYS,WD}$, a clock watchdog fault is indicated by setting <CLK_NOK> in the GLOBAL_DIAG0 register to 1, all power stages are disabled and device enters the Config Mode. In case the clock watchdog detects a too fast clock, the device immediately enters the Critical Fault State.

4.2.3 **TDS_I/O Pins**

RESN pin

The RESN pin is an active low pin. If this pin is low, all channels are off, the device is in Reset State and all registers are set to their default values. The bit <RES_EVENT> in the GLOBAL_DIAG0 register indicates a reset triggered via the RESN pin. The RESN input pin is internally pulled low (GND).

EN pin

The EN pin is an active high pin. When this pin is low, all channels are turned off. The EN input pin is internally pulled low (GND).

FAULTN pin

The FAULTN pin is an open drain output. The FAULTN pin is initially high, if no fault is present after power up. The FAULTN pin is pulled low when the device transitions to the Critical Fault State, the RESN pin is low or an unmasked fault is detected. Fault indication on the FAULTN pin can be masked by setting the appropriate mask bit in the FAULT_MASK registers.

- Channel specific:
 - CHx ICC regulation warning

Functional description

- CHx PWM regulation warning
- CHx overtemperature warning
- CHx open load
- CHx short circuit battery
- CHx short circuit ground
- Central overtemperature warning
- Central overtemperature error
- SPI watchdog error
- Clock too slow error
- Data error
- EN pin status indication
- Internal/External supply fault

CLK pin

A digital input clock signal f_{CLK} must be applied on the CLK pin if an external clock input is used. Using the internal clock, the pin should be connected to GND. The CLK input pin is internally pulled low (GND).

DRV pins

The DRV pins enable a direct control of the output stages, if the channel is configured to Direct Drive Mode via DRV pin. The DRV input pins are internally pulled low (GND). Unused DRV pins should be connected to GND.

SI, SO, CSN, SCK pin

The SI, SO, CSN, and SCK pins comprise the SPI interface. See SPI chapter for details.

4.2.4 Electrical characteristics I/O

4.2.4.1 Control inputs EN, RESN, CLK, DRVx

Table 11 Control inputs EN, RESN, CLK, DRVx

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Digital high threshold voltage (EN, RESN, CLK, DRVx)	$V_{EN,high}$ $V_{RESN,high}$ $V_{CLK,high}$ $V_{DRVx,high}$	2	–	–	V	
Digital low threshold voltage (EN, RESN, CLK, DRVx)	$V_{EN,low}$ $V_{RESN,low}$ $V_{CLK,low}$ $V_{DRVx,low}$	–	–	0.8	V	
Digital input hysteresis (EN, RESN, CLK, DRVx)	$V_{IN_HYS,EN}$ $V_{IN_HYS,RESN}$ $V_{IN_HYS,CLK}$ $V_{IN_HYS,DRVx}$	–	50	–	mV	

(table continues...)

Functional description

Table 11 (continued) Control inputs EN, RESN, CLK, DRVx

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Pull down current (EN, RESN, CLK, DRVx)	$I_{PD,EN}$ $I_{PD,RESN}$ $I_{PD,CLK}$ $I_{PD,DRVx}$	10	–	50	μA	$V_{IN} = 0.8\text{ V}$

4.2.4.2 FAULTN**Table 12** FAULTN

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Output low threshold voltage (FAULTN)	$V_{FAULTN,LOW}$	0	–	0.4	V	$I_{FAULTN} = 2\text{ mA}$
Output leakage current (FAULTN)	$I_{FAULTN,LGK}$	-100	–	100	μA	No fault present $0\text{ V} < V_{FAULTN} < V_{IO}$

4.3 IC Operation states**4.3.1 TDS_IC Operation states****Reset state:**

- The answer to an SPI command is the 16 bit reply frame.
- All SPI register values are being reset to default when the product leaves the Reset State.

Config Mode:

- All channels are disabled. <EN_CH> bits are 0 and cannot be set.
- Channel diagnostic is disabled (HS and LS current source are disabled).
- The Channel Mode, the global configuration, the parallel channel operation and the PLL divider can only be configured in Config Mode.

Mission Mode:

- The channels and their respective diagnosis are only functional in Mission Mode.

Critical Fault state:

- The IC will reply all SPI interactions with the Critical Fault frame.
- The FAULTN pin is pulled low.

The following State Diagram gives an overview on the transition conditions.

Functional description

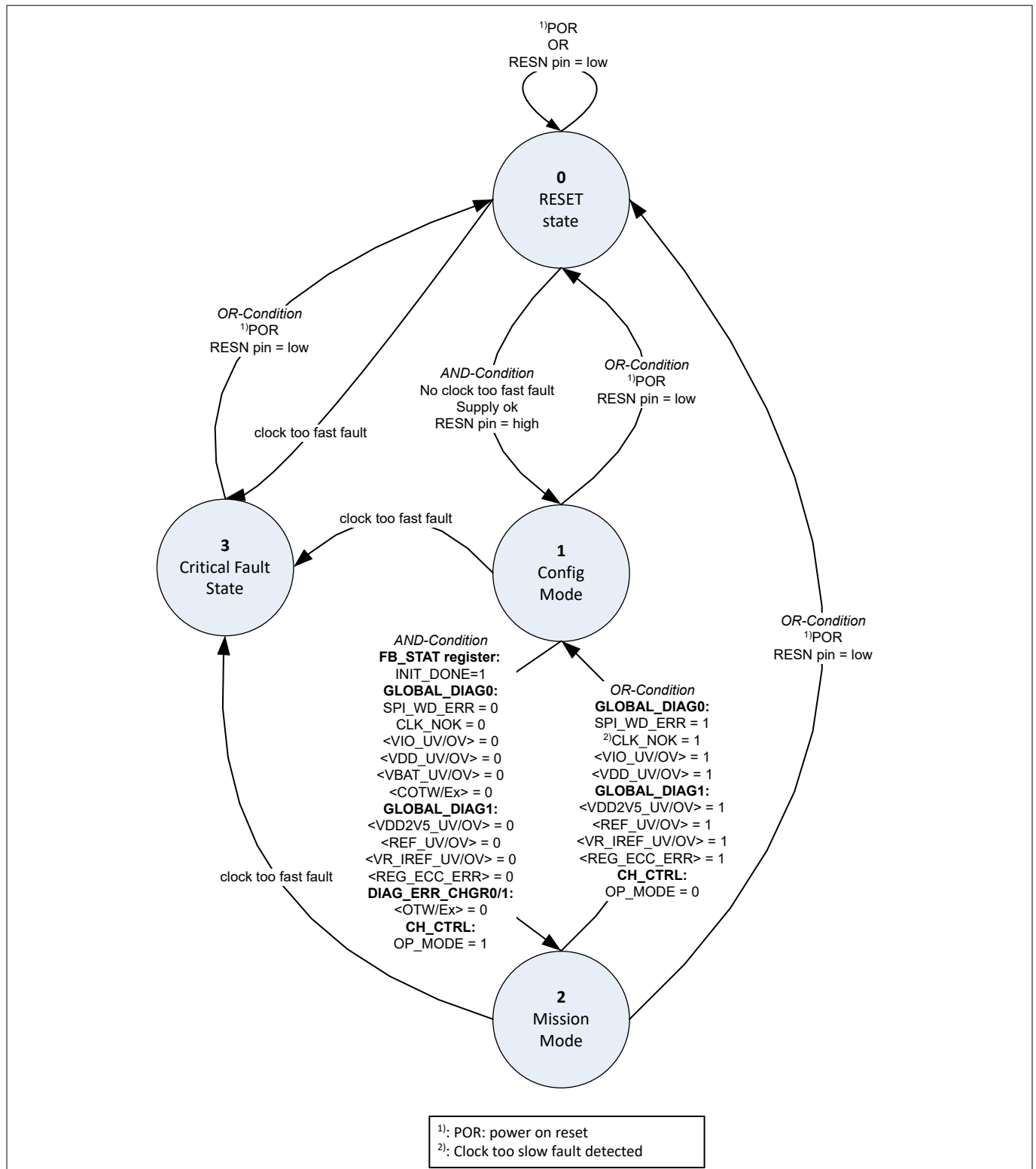


Figure 4 **Operation States and Transitions**

Functional description

4.4 Channel modes

4.4.1 TDS_Channel Modes

The IC offers different modes to control the output stage of a channel. The channel mode can be selected by programming the MODE register. A change of the channel mode is only possible in Config Mode. The measurement period T_{meas} for averaged feedback values depends on the selected channel mode (see chapter "current supervision").

4.4.2 Channel Modes

Channel Mode	Measurement Period T_{meas} for Feedback Values
Channel off	No measurement active
Current Control ICC	Dither Period T_{Dither}
Direct Drive via on-time (TON register)	Dither Period T_{Dither}
Direct Drive via DRV pin	- If configured Dither Period T_{Dither}, else - Time between two rising edges at DRV pin
Measurement Mode*	Dither Period T_{Dither}

4.4.3 TDS_Measurement Mode - (4/6CHx)

Note: The current measurement over the shunt can be used for high-precision current measurement applications. In measurement mode the internal low-side switch is non-conductive.

4.4.4 TDS_Additional Information Channel Modes

Note: For more details on the "Current Control" and "Direct Drive" Mode please refer to the respective chapters.

4.5 Power stages

4.5.1 TDS_Channel overview - (4CHx)

There are four independent output channels implemented in this device. The output powerstage of each channel consists of a low side n-channel DMOS transistor and a current sensing resistor. The switch and shunt resistor are protected from external failures by built in overcurrent and overtemperature detection circuits. A high-side load can be connected to the LOADx pin. For inductive loads a diode must be applied at the FWDx pin for external freewheeling. The output voltage slew rate of the power stages can be programmed in the CH_CONFIG register.

Functional description

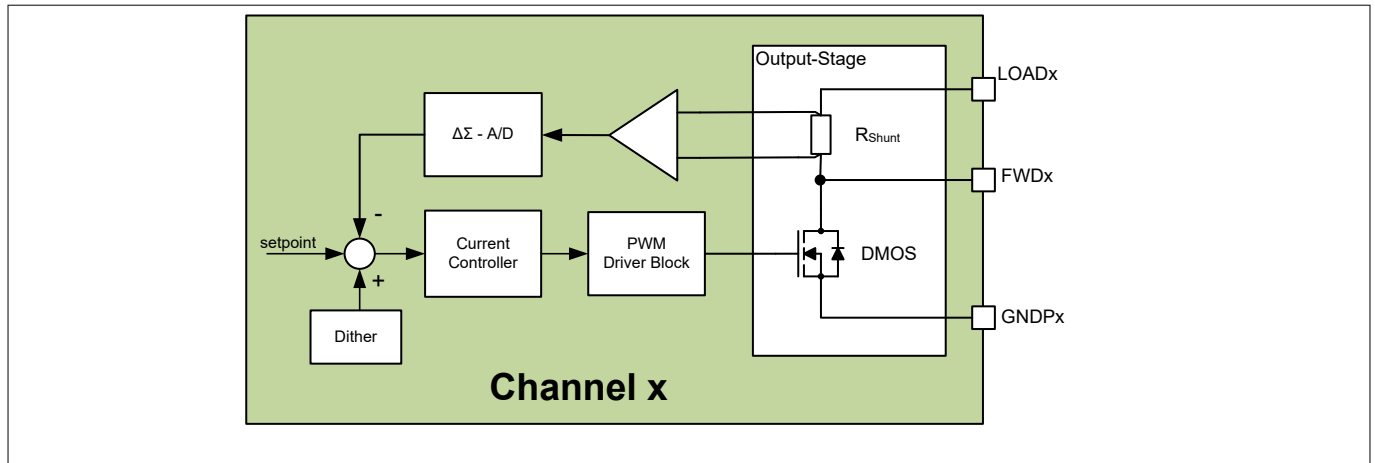


Figure 5 Channel Block Diagram

4.5.2 TDS_Parallel channel operation - (4CHx)

The IC features a parallel mode of output stages to increase the maximum current capability of the device. The channels 0 and 3 and the channels 1 and 2 can be connected in parallel. Channel 0 and 1 are the master channels and channel 2 and 3 are the slave channels. Only the master channels can be configured via SPI. The parallel channel mode can be enabled or disabled in the CH_CTRL register when the device is in Config Mode.

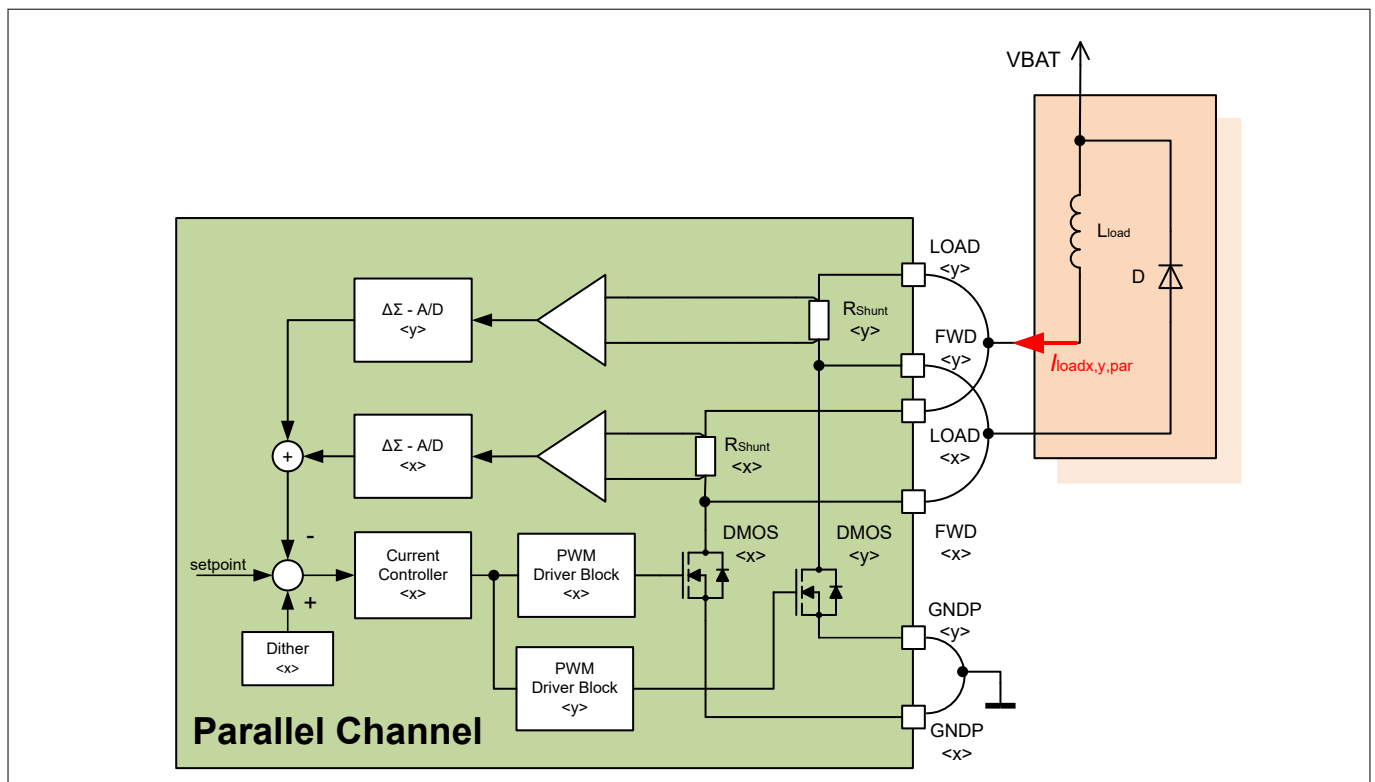


Figure 6 Parallel Channel Configuration

Slave channel

The current controller and the OFF-state diagnosis of the slave channel are disabled. A write access to the MODE register of the slave channel is ignored and reads back zero. The slave channel's SETPOINT register cannot be set and is read back as zero. All feedback registers of the slave channel have to be disregarded. A write to a slave <EN_CH> bit is ignored and 0 is read back. After disabling the parallel channel mode the slave channel must be re-configured to the desired channel behaviour.

Setpoint

Functional description

In parallel channel mode, the programmed setpoint of the master channel is used. Hence the LSB (least significant bit) of the setpoint is doubled.

Diagnostic functions

The LSB of the fixed OLSG (open load/short to GND) threshold is scaled by a factor of two. The OC (overcurrent) protection feature is active on the master as well as on the slave channel. If either the master or the slave channel detects an OC fault, both channels are disabled.

Feedback functions

The current feedback in the FB_I_AVG register represent the summed up current over the shunt resistors of the master and slave channel. The duty cycle feedback can be read from the master channel.

4.5.3 Electrical characteristics power stages

Table 13 Electrical characteristics power stages

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Shunt resistance	R_{shunt}	–	140	185	mΩ	
ON resistance	$R_{DS(on)}$	–	115	200 ¹⁾	mΩ	¹⁾ $T_J = 150^{\circ}\text{C}$, $I_{LOADx} = 2.0\text{ A}$
Leakage current (LOADx, FWDx)	$I_{LOADx,LKG}$ $I_{FWDx,LKG}$	-100	–	100	μA	$V_{BAT} = 18\text{ V}$; Setpoint = 0 mA; Diagnosis off
Slew rate 0	SR0	0.5	1	2	V/μs	$V_{BAT}=14\text{V}$; $R_{LOAD}=10\Omega$ 20% to 80% of applied load voltage <SLEWR> = 00 _B
Slew rate 1	SR1	1.25	2.5	5	V/μs	$V_{BAT}=14\text{V}$; $R_{LOAD}=10\Omega$ 20% to 80% of applied load voltage <SLEWR> = 01 _B
Slew rate 2	SR2	2.5	5	10	V/μs	$V_{BAT}=14\text{V}$; $R_{LOAD}=10\Omega$ 20% to 80% of applied load voltage <SLEWR> = 10 _B
Slew rate 3	SR3	5	10	20	V/μs	$V_{BAT}=14\text{V}$; $R_{LOAD}=10\Omega$ 20% to 80% of applied load voltage <SLEWR> = 11 _B

4.6 Current control

4.6.1 Current accuracy overview

The average current setpoint is determined by the content of <TARGET> in the SETPOINT register. The accuracy band of the current regulation is illustrated in the figure below. The current accuracy includes the junction temperature range T_J , battery voltage range V_{BAT} and device aging (AEC-Q100 HTOL, TC). The device supports a high precision current accuracy within a reduced battery range. For more details refer to [Table 14](#).

Functional description

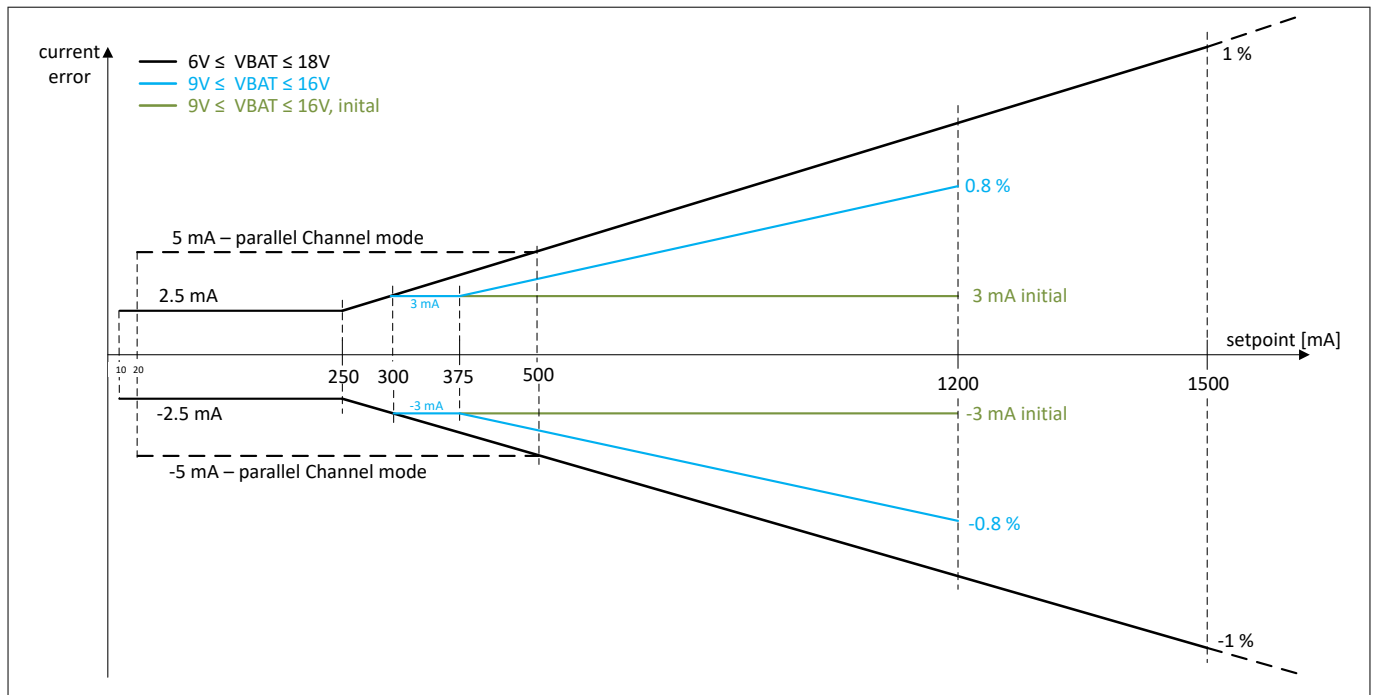


Figure 7 Current accuracy specification overview

4.6.2 Integrating Current Controller (ICC)

4.6.2.1 TDS_Integrating Current Controller (ICC)

The current controller regulates the load current automatically to a user defined setpoint by turning on and off the internal transistor. If the internal transistor is switched on, the current through the inductive load will increase. If the internal transistor is turned off, the current will continue to flow through the recirculation diode gradually decay.

The Integrating Current Controller (ICC) is based on the requirement that the integrated current error over one PWM cycle is zero. This means that the average current after one PWM cycle exactly equals the targeted current. The controller integrates the current deviation (difference between load current and the setpoint) and switches the output stage accordingly: While the integrated current deviation is below a configurable integrator threshold, the power stage is turned on. In this phase the load current will increase. When the integrated current error exceeds the determined integrator threshold the power stage is turned off and the current recirculates through the freewheeling diode. The average current is reached when the integrated current deviation crosses zero which determines the start of a new PWM cycle. The ICC switching characteristic provides the physically fastest current response which makes it very robust against load voltage dips.

Functional description

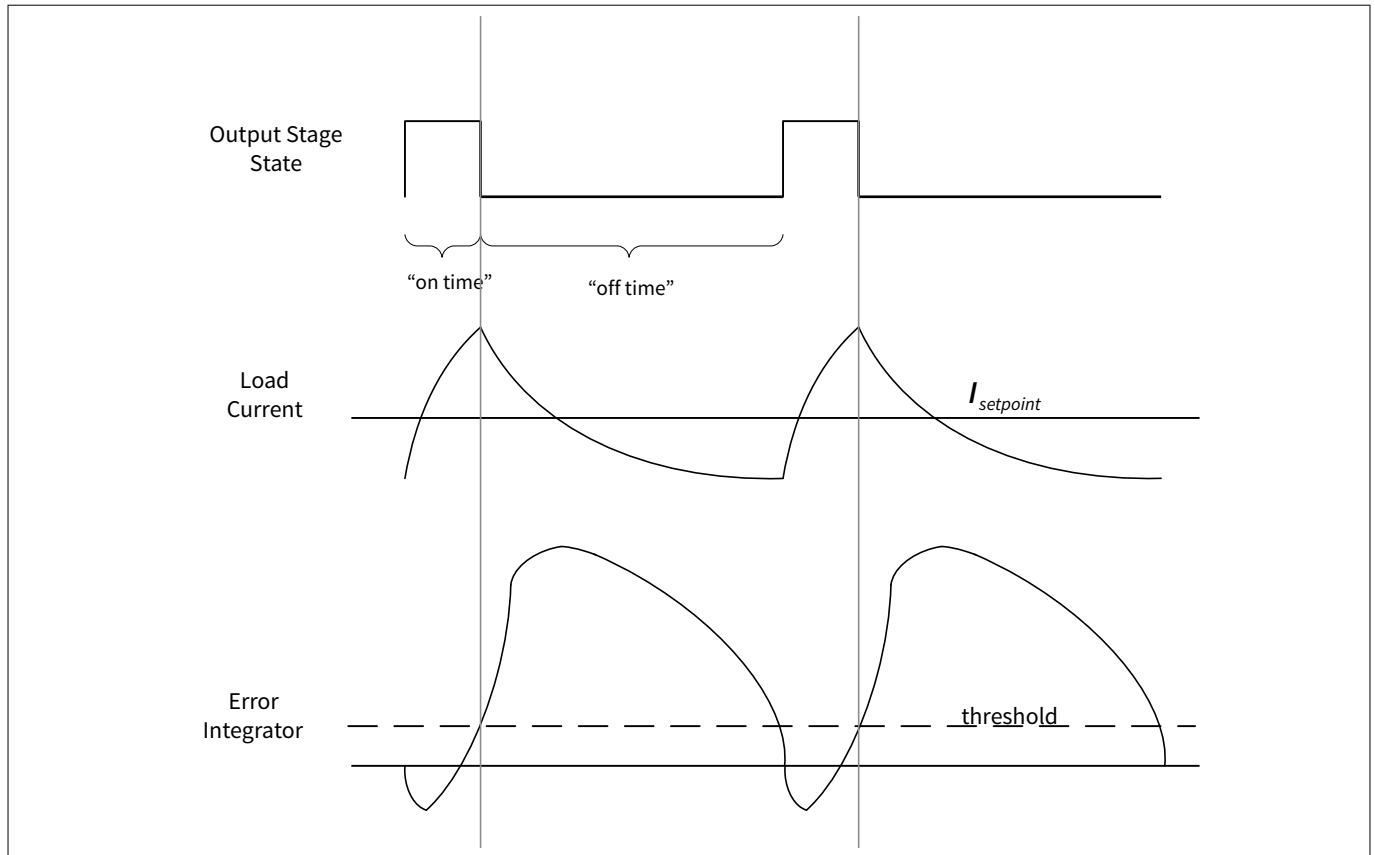


Figure 8 **Current Control Waveform**

4.6.2.2 TDS_Integrator Limits

The ICC integrator can be saturated in order to avoid an integrator windup. The integrator limits are configurable via +/-<LIM_VALUE_ABS> in the INTEGRATOR_LIMIT register.

In order to avoid current overshoots after setpoint changes the Autolimit feature is introduced. The device limits the integrator value to +/-<AUTO_LIM_VALUE_ABS> (INTEGRATOR_LIMIT register) for a maximum of two PWM cycles after a setpoint change. After the completion of Autolimit, the ICC automatically revert back to the normal integrator limit values +/-<LIM_VALUE_ABS>. The Autolimit feature is disabled by writing a 1 to the <AUTO_LIMIT_DIS> bit in the SETPOINT register.

Functional description

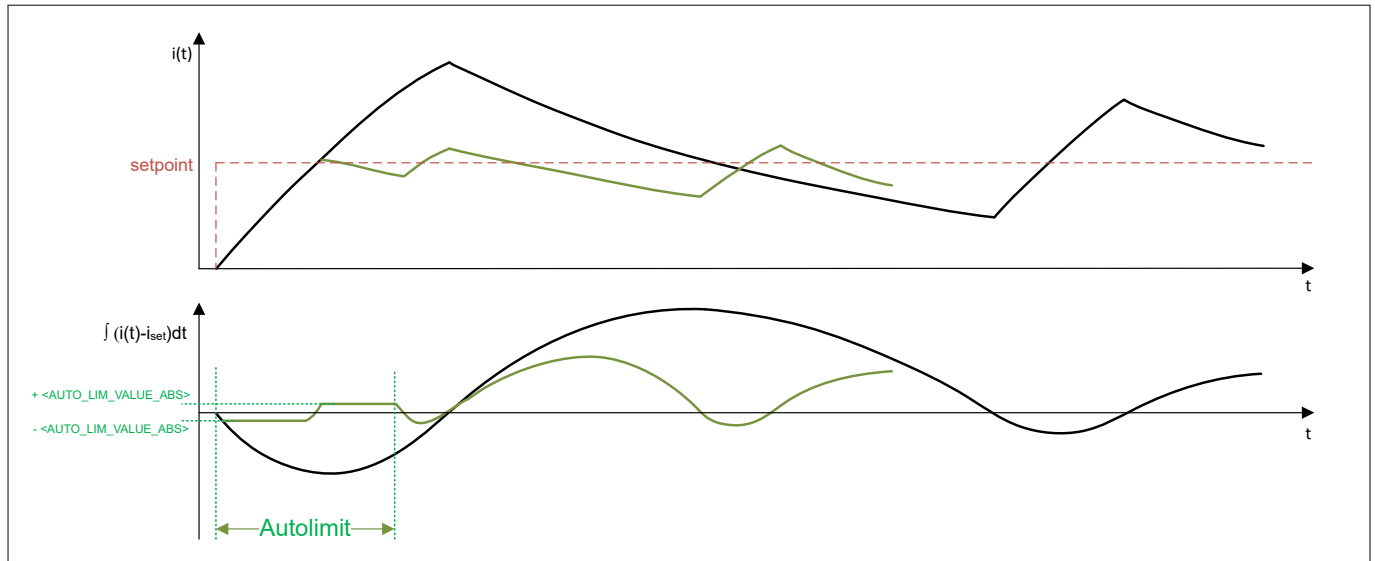


Figure 9 Autolimit feature

4.6.2.3 TDS_PWM Frequency Control

The load characteristic and load supply voltage affecting the PWM output frequency of the ICC controller. The on-time of the LS-FET and therefore the PWM cycle can be adjusted by modifying the integrator threshold value. A greater integrator threshold ends up in a longer on-time. Although the configured integrator threshold value is positive, the actual threshold can get negative since it is referenced to the lowest current deviation integral value captured during the on-phase. This means very short on-time configurations are possible. The shortest on-time is determined by limiting the integrator threshold to a minimum value configurable via `<MIN_INT_THRESH>` in the CTRL register.

There are two options to set the integrator threshold to adjust the PWM frequency.

Manual setting of On-time

The driver on-time and therefore a target PWM period can be set manually by programming a fixed integrator threshold `<INT_THRESH>` in the CTRL_INT_THRESH register. The PWM frequency controller has to be disabled by setting `<PERIOD_MANT>` in the PERIOD register to 0.

Automatic PWM control

The PWM frequency controller regulates the PWM frequency using an “Integral” control loop with a programmable gain, KI. This control loop monitors the actual PWM period and compares subtracts it from the PWM period target setting in the PWM period register. The error in the PWM period is multiplied by the gain KI and then integrated at each PWM cycle. The output of the controller adjusts the on-time of the PWM signal until the actual PWM period matches the programmed PWM period. The internal PWM frequency controller can be activated by setting a target PWM period T_{period} in the PERIOD register.

$$T_{period} = \frac{\langle PERIOD_MANT \rangle \cdot 2^{\langle PERIOD_EXP \rangle}}{f_{SYS}}$$

Equation 4

By setting the bit `<LOW_FREQ_RANGE_EN>` the range of the configurable target PWM frequency is lower and can be calculated as follow.

$$T_{period} = \frac{\langle PERIOD_MANT \rangle \cdot 8 \cdot 2^{\langle PERIOD_EXP \rangle}}{f_{SYS}}$$

Equation 5

Functional description

The bitfield $\langle \text{INT_THRESH} \rangle$ in the CTRL_INT_THRESH register determines the integrator threshold used after setpoint changes or activation of the PWM controller. The $\langle \text{INT_THRESH} \rangle$ value must be configured before applying the new setpoint. The resulting threshold calculated by the PWM frequency controller can be retrieved from the FB_INT_THRESH register. The threshold calculated by the PWM frequency controller can be read back from the FB_INT_THRESH register. The threshold value can be used to program $\langle \text{INT_THRESH} \rangle$ to reduce the settling time of the PWM frequency controller e.g. after a setpoint change.

Note: The Autolimit threshold must be greater than the lower threshold limit configuration for a correct ICC functioning ($\langle \text{AUTO_LIM_VALUE_ABS} \rangle > \langle \text{MIN_INT_THRESH} \rangle + 0x3$).

The PWM frequency control parameter KI can be set by $\langle \text{PWM_CTRL_PARAM} \rangle$ in the PERIOD register. The integrator parameter KI determines the gain and therefore the speed of the PWM frequency control loop. A KI value of 0 results in a slower but more stable PWM control.

During steep dither settings, long off-times can appear which end up in high frequencies in the next rising dither slope. The frequency controller does not consider falling dither slopes by setting the $\langle \text{PWM_PERIOD_CALC_MODE} \rangle$ in the CTRL register.

4.6.2.4 TDS_PWM regulation warning

An ICC PWM regulation warning is issued if the ICC integrator value drops below the minimum integral value, which was captured during the on-phase. This can happen i.e. if a negative absolute integrator threshold is calculated from the PWM control and the inertia of the load is too large. This means the integrated current deviation could not exceed the zero level and therefore the power stage would not switch on anymore. A negative integrator threshold can be avoided by programming $\langle \text{MIN_INT_THRESH} \rangle$ in the CTRL register to a value greater than 1. A recovery process maintains the current regulation by triggering the Autolimit feature. After finishing Autolimit, the integrator threshold configured in $\langle \text{INT_THRESH} \rangle$ bitfield is used. The PWM regulation warning is signaled by asserting the $\langle \text{PWM_REG_WARN} \rangle$ bit in the DIAG_WARN_CHGR register.

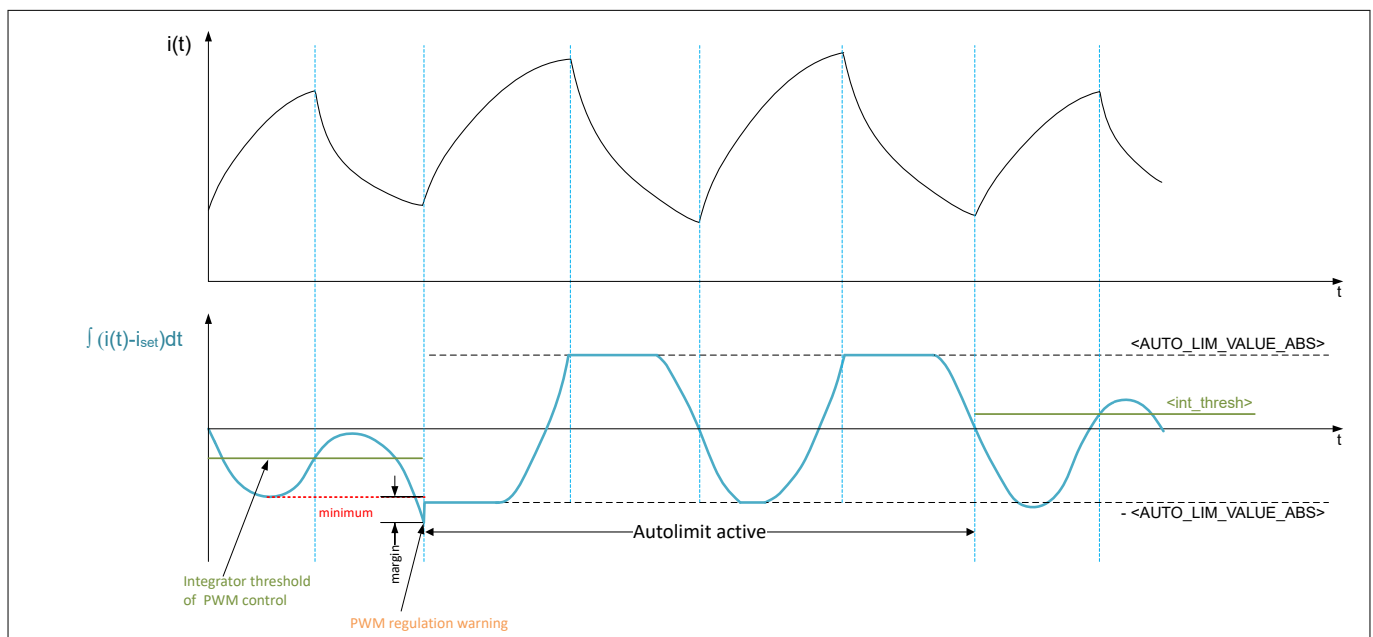


Figure 10 ICC PWM regulation warning

4.6.2.5 TDS_Current regulation warning

An ICC current regulation warning occurs if the ICC integrator value reaches the absolute integrator limit $\langle \text{LIM_VALUE_ABS} \rangle$ located in the INTEGRATOR_LIMIT register. This can happen for example during a voltage supply dip. A recovery process maintains the current regulation by triggering the Autolimit feature. The integrator threshold will be reset to $\langle \text{INT_THRESH} \rangle$ located in the CTRL_INT_THRESH register. The warning is signaled by asserting the respective $\langle \text{I_REG_WARN} \rangle$ bit in the DIAG_WARN_CHGR register.

Functional description

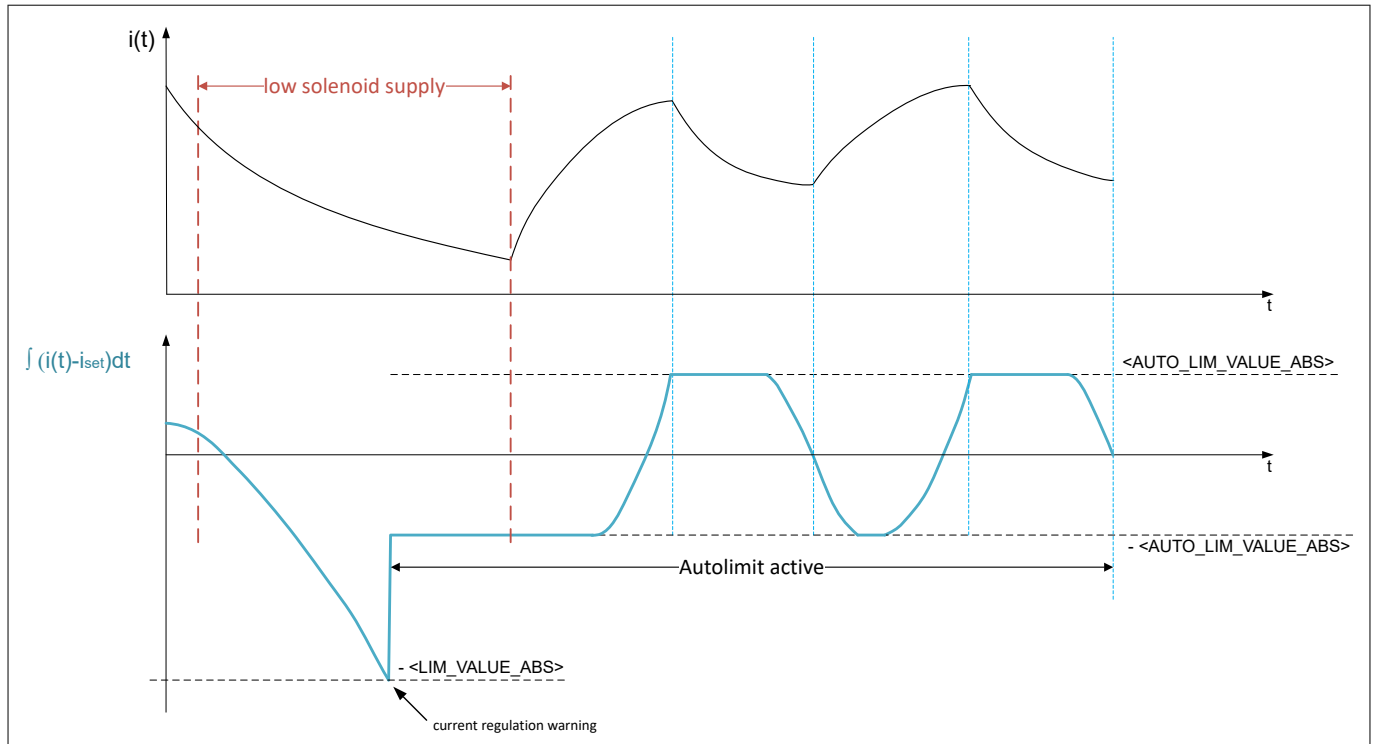


Figure 11 ICC current regulation warning

4.6.3 Electrical characteristics current control

Table 14 Electrical characteristics current control

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Average current control error, absolute	$I_{err,abs,1}$	-2.5	–	2.5	mA	$I_{set} = 10 - 250\text{ mA}$ includes aging single channel operation
Average current control error, absolute - parallel	$I_{err,abs,1,par}$	-5	–	5	mA	$I_{set} = 20 - 500\text{ mA}$ includes aging parallel channel operation
Average current control error, relative	$I_{err,rel,1}$	-1	–	1	%	$250\text{ mA} < I_{set} \leq 1500\text{ mA}$; single channel operation $500\text{ mA} < I_{set} \leq 2700\text{ mA}$; parallel channel operation includes aging
Average current control error, absolute - reduced battery	$I_{err,abs,2}$	-3	–	3	mA	$300\text{ mA} < I_{set} \leq 375\text{ mA}$ $9.0\text{ V} \leq V_{BAT} \leq 16\text{ V}$ includes aging single channel operation

(table continues...)

Functional description

Table 14 (continued) Electrical characteristics current control

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Initial average current control error, absolute - reduced battery	$I_{err,abs,2,init}$	-3	-	3	mA	$375\text{ mA} < I_{set} \leq 1200\text{ mA}$ $9.0\text{ V} \leq V_{BAT} \leq 16\text{ V}$ single channel operation
Average current control error, relative - reduced battery	$I_{err,rel,2}$	-0.8	-	0.8	%	$375\text{ mA} < I_{set} \leq 1200\text{ mA}$ $9.0\text{ V} \leq V_{BAT} \leq 16\text{ V}$ includes aging single channel operation
Load current	I_{set}	0	-	1500	mA	DC setpoint current Single channel operation
Dither current	$I_{set} + I_{Dither}$	0	-	1800	mA	DC setpoint current incl. dither current amplitude Single channel operation
Measurement current	I_{LOADx}	0	-	2000	mA	DC setpoint incl. dither current amplitude and overshoot Single channel operation The user must take care that the maximum value is not exceeded
Measurement current - parallel	$I_{LOADx,y,par}$	0	-	2700	mA	DC setpoint current incl. dither current amplitude and overshoot Parallel channel operation Single channel measurement range I_{LOADx} of each Channel shall not be violated

4.7 Dither

4.7.1 TDS_Dither configuration

A configurable dither waveform can be added to the average current setpoint in order to reduce the hysteresis of a driven solenoid valve. The dither operation is an overlay of a triangular or trapezoidal waveform over the current setpoint. The dither waveform is generated by permanently changing the setpoint according to the programmed shape.

The dither shape can be configured by setting the <STEPS>, <STEP_SIZE> and <FLAT> values in the DITHER_STEP and DITHER_CTRL register. The <STEP_SIZE> value scales the height of each dither step where the LSB is equal to <TARGET> in the setpoint register. The value of <STEPS> determines the number of steps for the rising and falling edge of each half cycle of the dither waveform. The value of <FLAT> determines the number of flat steps at the minimum and maximum plateau of the dither waveform.

The amplitude of the dither waveform overlay I_{Dither} can be calculated as follows.

Functional description

$$I_{Dither} = \langle \text{STEPS} \rangle \cdot \langle \text{STEP_SIZE} \rangle \cdot \frac{2A}{2^{15} - 1}$$

Equation 6

Care should be taken that no negative dither amplitude ($I_{\text{set}} - I_{\text{Dither}} > 0$) is configured and possible overshoots are not violating the specified measurement current range I_{LOADx} or $I_{\text{LOADx,par}}$ (parallel channel operation). The dither overlay I_{Dither} is deactivated if the target setpoint is set to 0.

The Dither period T_{Dither} is a multiple of the Dither reference clock determined by the values of $\langle \text{MANT} \rangle$, $\langle \text{EXP} \rangle$ of the DITHER_CLK_DIV register. The dither period T_{Dither} and dither reference clock $t_{\text{ref_clk}}$ can be calculated as follows.

$$T_{\text{Dither}} = (4 \cdot \langle \text{STEPS} \rangle + 2 \cdot \langle \text{FLAT} \rangle) \cdot t_{\text{ref_clk}}$$

Equation 7

$$t_{\text{ref_clk}} = \frac{\langle \text{MANT} \rangle \cdot 2^{\langle \text{EXP} \rangle}}{f_{\text{SYS}}}$$

Equation 8

$$t_{\text{flat}} = \langle \text{FLAT} \rangle \cdot t_{\text{ref_clk}}$$

Equation 9

Note: If $\langle \text{STEPS} \rangle = 0$ and $\langle \text{FLAT} \rangle = 0$, the dither period $T_{\text{Dither}} = t_{\text{ref_clk}}$

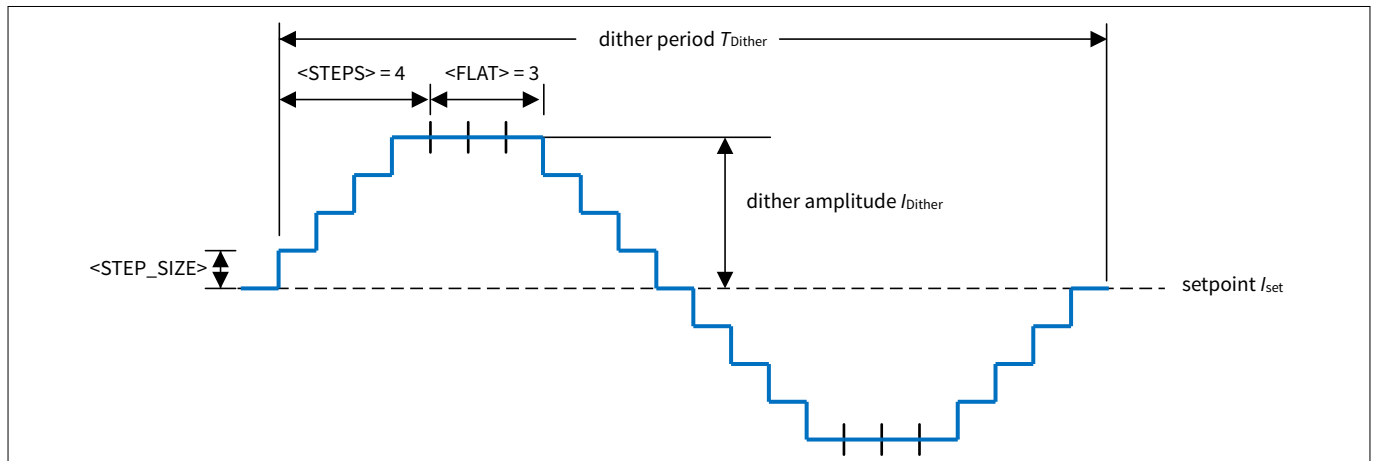


Figure 12 Dither Waveform Configuration

4.7.2 TDS_Dither parameter update

All dither parameters located in registers DITHER_STEP and DITHER_CTRL become active at the start of the next dither period after writing to the DITHER_CTRL register. After triggering an update event (write to DITHER_CTRL) within the active dither period, the dither configuration (DITHER_STEP/ DITHER_CTRL) that was transmitted last within the active dither period is taken over. An update of the reference clock $t_{\text{ref_clk}}$ controlled by the DITHER_CLK_DIV register takes immediate effect. If the dither amplitude is disabled by clearing $\langle \text{STEP_SIZE} \rangle$, the active dither period will be completed. The configured dither period and overlay is immediately (re)-started if the $\langle \text{EN_CH} \rangle$ bit transitions to 1.

4.7.3 TDS_Dither PWM synchronization

The dither-PWM synchronization starts a new dither period synchron with the start of the next PWM cycle to enable the same starting conditions for each dither period. The start of a PWM cycle period is defined as a turn on of the output stage. The start of a dither period is defined to be when the dither increases one step above zero on this rising slope of the dither waveform. The dither-PWM synchronization can be enabled by setting the <DITHER_PWM_SYNC_EN> bit in the DITHER_CLK_DIV register. When the <DITHER_PWM_SYNC_EN> bit is set to 0, the dither waveform is free-running and asynchronous to the PWM frequency.

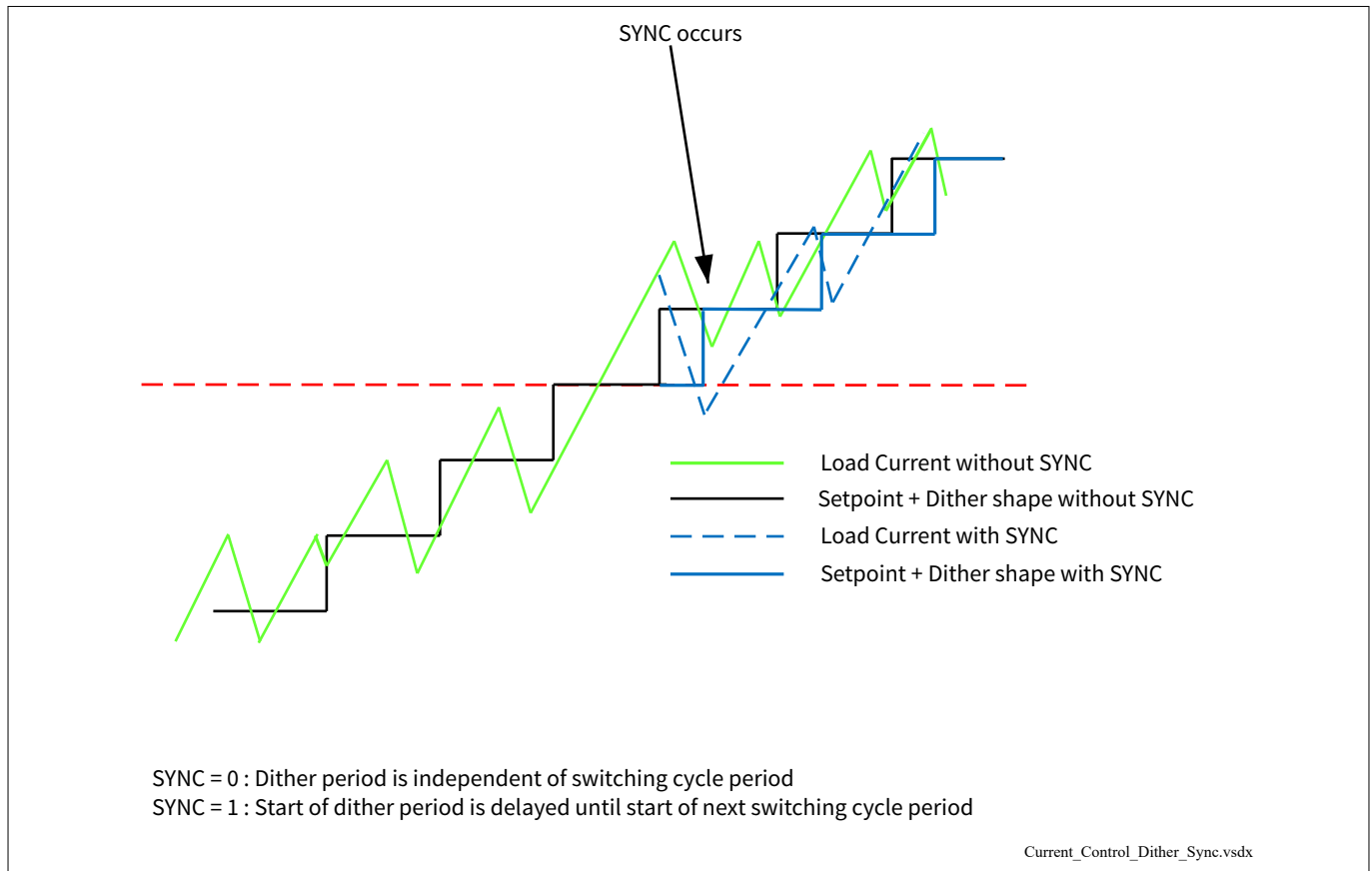


Figure 13 Dither sync

4.7.4 TDS_Only ICC

Note: This feature is only available in ICC Channel Mode.

4.7.5 TDS_Dither setpoint synchronization

The dither-setpoint synchronization feature updates the averaged feedback values of a channel (FB_DC, FB_I_AVG, FB_VBAT) after a change in setpoint in the shortest possible time. The dither-setpoint synchronization restarts the dither period when the newly applied setpoint has been reached. Therefore, the measurement period T_{meas} (dither period) for the feedback values is always in lockstep with a setpoint change and no latency of the averaged feedback values (FB_DC, FB_I_AVG, FB_VBAT) is present. The synchronization of the dither period to a setpoint change can be enabled by programming the <DITHER_SETPOINT_SYNC_EN> bit in the DITHER_CLK_DIV register. An enabled setpoint synchronization freezes the average feedback registers (FB_DC, FB_I_AVG, FB_VBAT) with the last valid measurement result if the channel is disabled with setpoint "0".

Functional description

4.7.6 TDS_Only ICC

Note: This feature is only available in ICC Channel Mode.

4.7.7 TDS_Deep dither

A steep and deep dither command is comparable to great changes of setpoint. The deep dither function reduces the over- and undershoot of very steep dither overlays by permanently enabling the Autolimit feature. The deep dither feature can be enabled by setting the <DEEP_DITHER> bit in DITHER_CTRL register.

4.7.8 TDS_ICC only

Note: This feature is only available in ICC Channel Mode.

4.8 Direct Drive

4.8.1 TDS_Direct Drive

In Direct Drive, the channel's output stage is controlled directly by the user. To enable a output stage switching, the respective channel must be activated by setting <EN_CH> bit to 1 and a target current setpoint value different to zero. The Direct Drive mode must be selected by programming the MODE register.

Direct Drive mode via DRV pin

In Direct Drive mode via DRV pin the channel's output stage is switched according to the logic level at the corresponding DRV pin. The channel is turned on if the DRV pin is high and is switched off if the DRV pin is low.

Direct Drive mode via SPI on-Time

In Direct Drive mode via SPI on-Time, the channel's output stage is switched according to a configurable period. The period T_{period} is set in the DITHER_CLK_DIV register by the bit fields <MANT> and <EXP>. The on-time t_{on} during a period can be configured with the <TON_MANT> bit field in the TON register.

$$T_{period} = \frac{\langle MANT \rangle \cdot 2^{\langle EXP \rangle}}{f_{SYS}}$$

$$t_{on} = \frac{\langle TON_MANT \rangle \cdot 2^{\langle EXP \rangle}}{f_{SYS}}$$

Equation 10

4.9 Diagnostic functions

4.9.1 TDS_Overview

Each IC channel has an independend open load (OL), overcurrent (OC) and short circuit to ground (SG) diagnosis.

The following points should be considered:

- All failure modes are only considered to occur on the off board routed LOAD-pin.
- The diagnosis indication bits are clear on write.
- The diagnosis is only enabled if the device is in Mission Mode

The diagnosis consists of an ON-state diagnosis and an OFF-state diagnosis. Both diagnosis states shall be used to enable a full fault analysis coverage.

ON-state diagnosis

Functional description

A channel is in ON-state if the <EN_CH> bit is set and the setpoint value is different to 0 mA. All diagnostic functions in ON-state rely on measuring the current through the shunt resistor. The ON-state diagnosis cannot distinguish between a short circuit to ground (SG) and an open load (OL) fault. Those faults are summarized to an Open Load/Short to Ground fault (OLSG) in the ON-state. A distinction whether an OL or SG is present needs to be done by the OFF-state diagnosis.

OFF-state diagnosis

A channel is in OFF-state if

1. the setpoint is 0 and the <EN_CH> bit is set to 1 (EN-pin must be high for use of OFF-state diagnosis state machine)
2. the setpoint is non-zero and the <EN_CH> bit is set to 0.

The first condition can be used to initially test the application circuit. The second condition is present after the ON-state diagnosis has detected a fault.

In OFF-state, the internal high and low side current sources I_{HS} and I_{LS} at the LOADx pin are active. The switching configuration and current strength of I_{HS} and I_{LS} can be configured in the CH_CONFIG register.

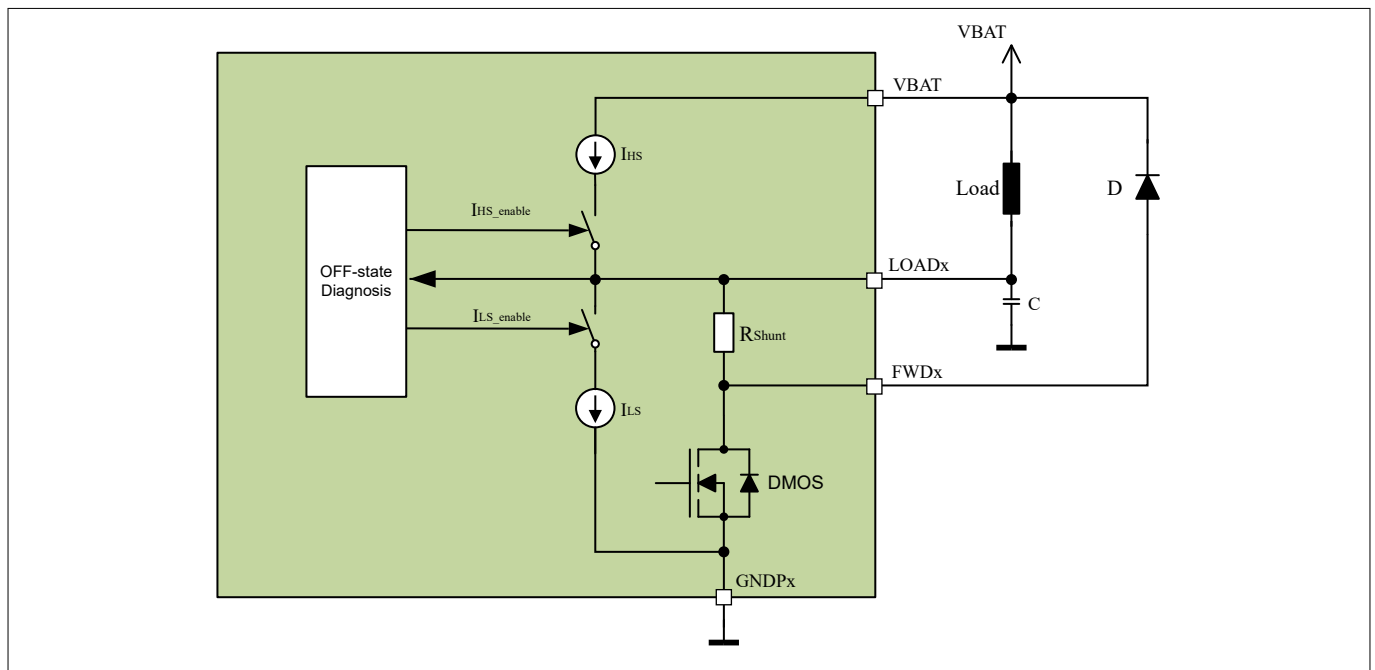


Figure 14 OFF-state diagnosis circuit

Setting <OFF_DIAG_CH> bit in the CH_CONFIG register to "0", activates the OFF-state diagnosis. The OFF-state diagnosis detects and indicates open load (OL) or short circuit to ground (SG) faults by performing following LOAD pin voltage checks.

1. The low side diagnostic current I_{LS} is enabled and the high side diagnostic current I_{HS} is disabled.
 - If $V_{LOAD} > V_{TH_BAT/2}$ no fault is detected.
 - If $V_{LOAD} < V_{TH_BAT/2}$ the sequence continues.
2. The high side diagnostic current I_{HS} is enabled and the low side diagnostic current I_{LS} is disabled.
 - If $V_{LOAD} > V_{TH_BAT/2}$ an OL is detected and indicated in the DIAG_ERR_CHGR register.
 - If $V_{LOAD} < V_{TH_BAT/2}$ a SG is detected and indicated in the DIAG_ERR_CHGR register.

The OFF-state diagnosis handles all channels sequentially. The OFF-state diagnosis sequence takes $T_{off,sequence}$.

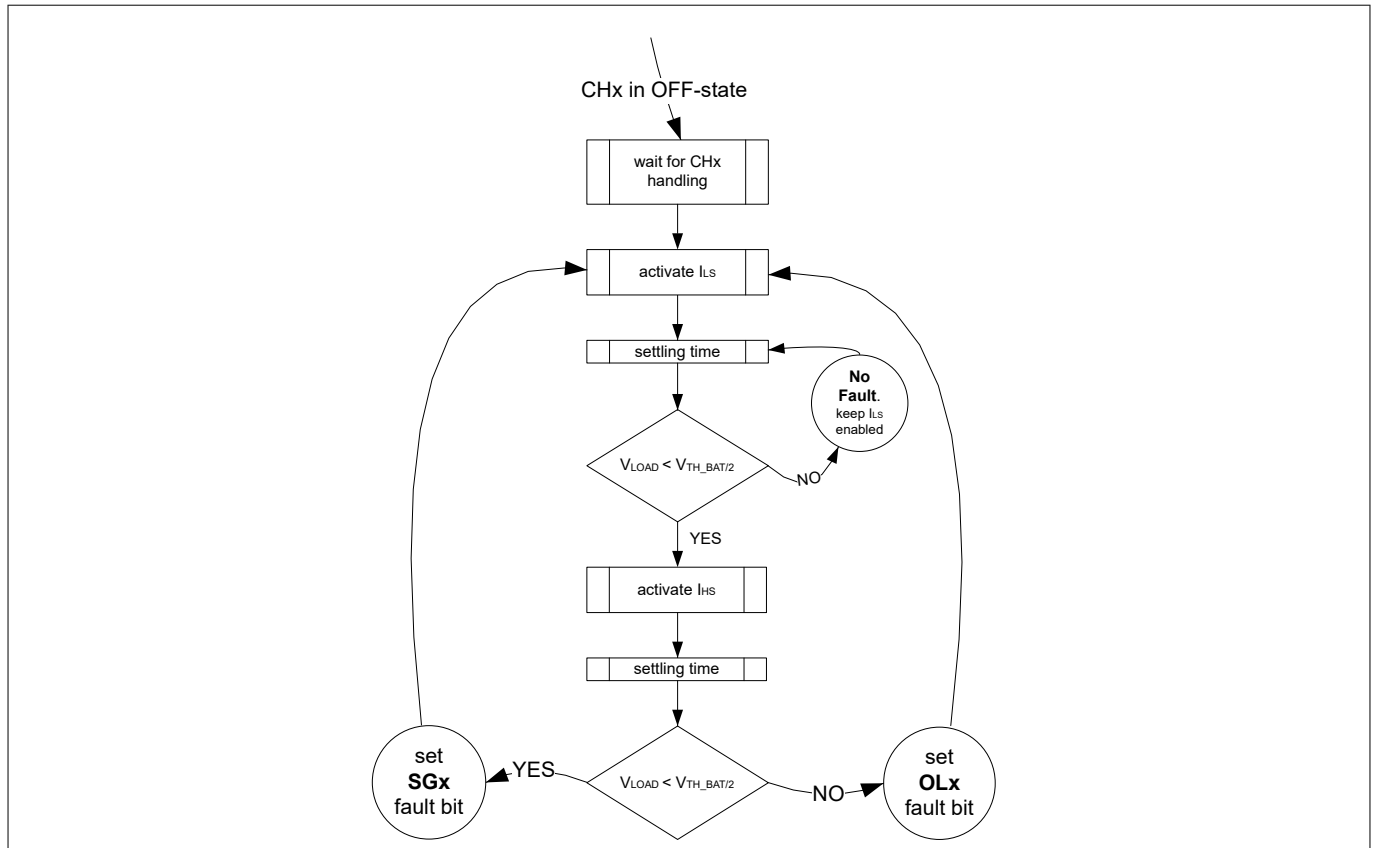


Figure 15 OFF-state diagnosis sequence

4.9.2 TDS_Open Load/Short to Ground (OLSG)

An open load (OL) and a short circuit to ground (SG) are both reducing the current flowing through the shunt resistor. Therefore the faults cannot be distinguished in ON-state and are summarized as OLSG fault. An OLSG is detected if the cumulated driver on-time equals T_{OLSGON} and the load current I_{LOAD} is below the open load threshold I_{OLTH} .

Functional description

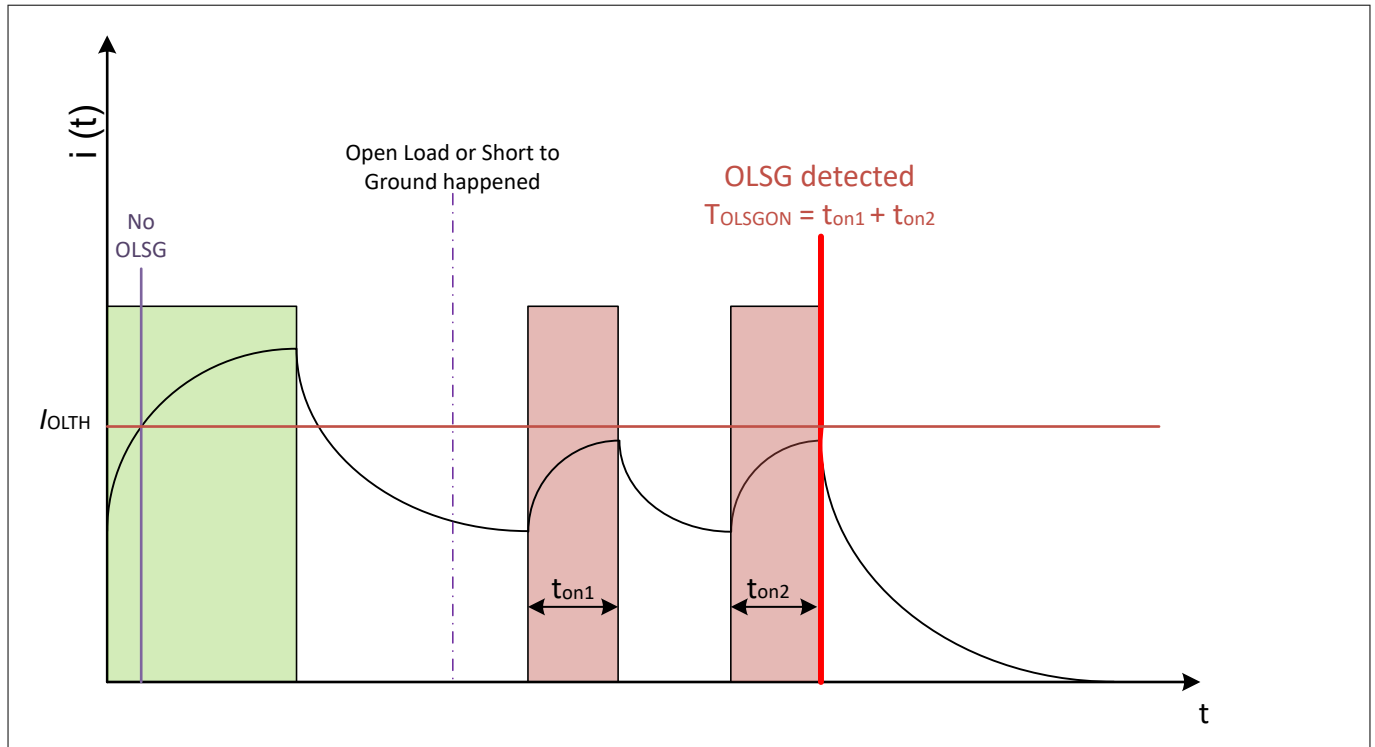


Figure 16 **Simplified OLSG detection mechanism**

An OLSG fault switches off the respective power stage and is indicated by setting the respective OLSG bit in the DIAG_ERR_CHGR register. The device keeps the channel disabled until the fault is removed, the diagnosis bit is cleared and the <EN_CH> bit is set to “1” again.

R_{OLmin} is the minimum impedance to detect an OL in ON-state via an OLSG fault.

$$R_{OLmin} = \frac{V_{BAT}}{I_{OLTH}} - (R_{LOAD} + R_{shunt} + R_{DSon})$$

Equation 11

R_{SGmax} is the maximum impedance to detect an SG in ON-state via an OLSG fault.

$$R_{SGmax} = \frac{R_{LOAD} \cdot (R_{shunt} + R_{DSon})}{R_{OLmin}}$$

Equation 12

4.9.2.1 TDS_OL-Threshold configuration

The open load threshold I_{OLTH} can be set to a fixed threshold and/or a threshold relative to the setpoint via the CH_CONFIG register. The OLSG diagnosis is disabled by setting both OL-thresholds to 0.

Fixed OL-Threshold

A fixed open load threshold is programmable via bitfield <OL_TH_FIXED>.

Functional description

$$I_{OLTH} = \frac{< OL_TH_FIXED > \cdot 128 \cdot 2000\text{mA}}{2^{15} - 1}$$

$$I_{OLTH, parallel} = \frac{< OL_TH_FIXED > \cdot 128 \cdot 4000\text{mA}}{2^{15} - 1}$$

Equation 13

Note: The OL detection in direct drive mode is only possible with the fixed threshold configuration.

Relative OL-Threshold

The relative threshold refers to the actual setpoint I_{set} including the dither amplitude I_{Dither} . A relative open load threshold is adjustable in bitfield <OL_TH>. The relative open load threshold is disabled by setting <OL_TH> to 0.

$$I_{OLTH} = (I_{set} + I_{Dither}) \cdot \frac{< OL_TH >}{8}$$

Equation 14

Note: The relative threshold is only available in a current control mode.

Transition phase

During a transition phase, the fixed OL-threshold is always used. A transition phase takes place after a channel activation or setpoint change. A transition phase lasts for one PWM cycle or maximum for a driver on-time of T_{OLSGON} (PWM cycle $> T_{OLSGON}$). The transition phase time out can be extended or shortened by configuring $t_{OLSG_TIMEOUT}$ in the TON register. After the transition phase has been finished, the OLSG detection swaps from fixed to relative OL-threshold. If the <OL_TH_FIXED> bitfield is set to 0, no OLSG will be detected during a transition phase.

$$t_{OLSG_TIMEOUT} = \frac{(< OLSG_TIMEOUT > \cdot 256 + 255) \cdot 64}{f_{SYS}}$$

Equation 15

4.9.3 TDS_OLSG Warning

An additional OLSG-Warning checks if the voltage at the LOAD pin is greater than $V_{TH_BAT/2}$ at the end of the freewheeling phase. The blanking time $t_{OLwindow}$ is triggered every time the outputstage is switched off. If the output stage is switched on within $t_{OLwindow}$, no voltage check is possible. This is indicated by setting <OLSG_WARN_CHK_NOK> in the DIAG_WARN_CHGR register to 1. The <OLSG_WARN_CHK_NOK> bit is cleared by reading.

If the check was successful, a detected OLSG-warning is indicated by setting <OLSG_WARN> in the DIAG_WARN_CHGR register to 1. The OLSG-warning is initially enabled and can be disabled by clearing the bit <OLSG_WARN_EN> in the CTRL register. The OLSG-warning check bit <OLSG_WARN_CHK_NOK> is set to 1 after clearing <OLSG_WARN> in the DIAG_WARN_CHGR register.

$t_{OLwindow}$ can be configured in the CTRL register.

$$t_{OLwindow} = \frac{(< OLSG_WARN_WINDOW > + 1) \cdot 64}{f_{SYS}}$$

Equation 16

Functional description

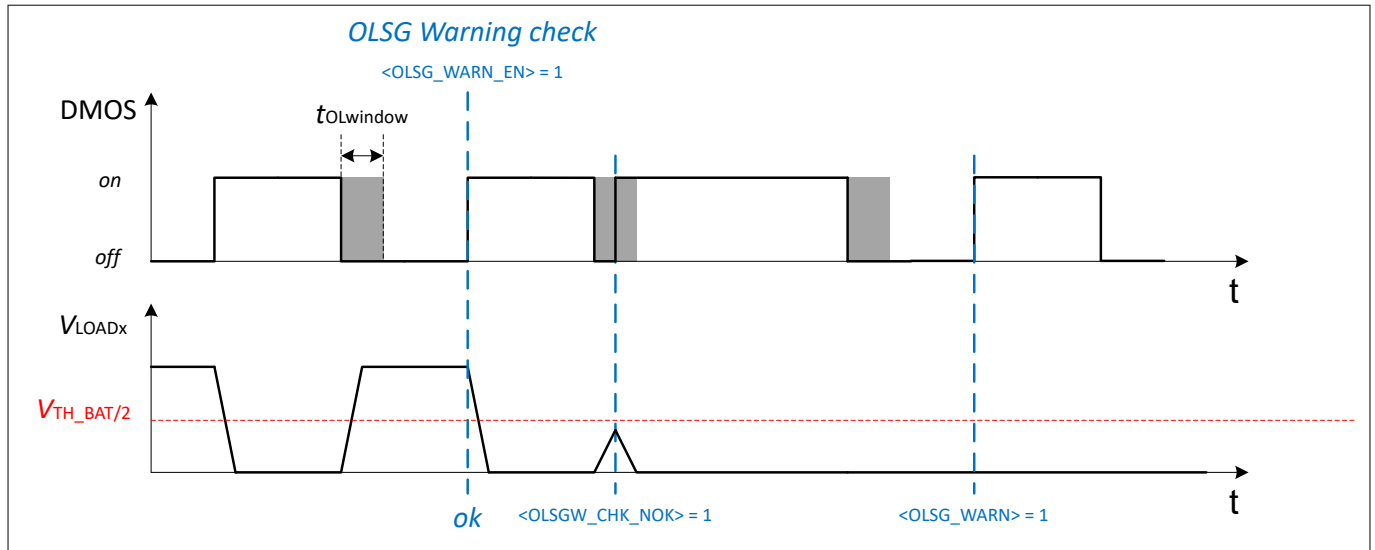


Figure 17 OLSG-Warning and OLSG warning check overview

4.9.4 TDS_Open load (OL)

In ON-state, an open load is indicated via the <OLSG> bit in the DIAG_ERR_CHGR register. The final fault discrimination to identify an open load is done by the OFF-state diagnostic. The device indicates the fault by setting the respective bit in the DIAG_ERR_CHGR register. The device keeps the channel disabled until the fault is removed, the diagnosis bit is cleared and the <EN_CH> bit is set to “1” again.

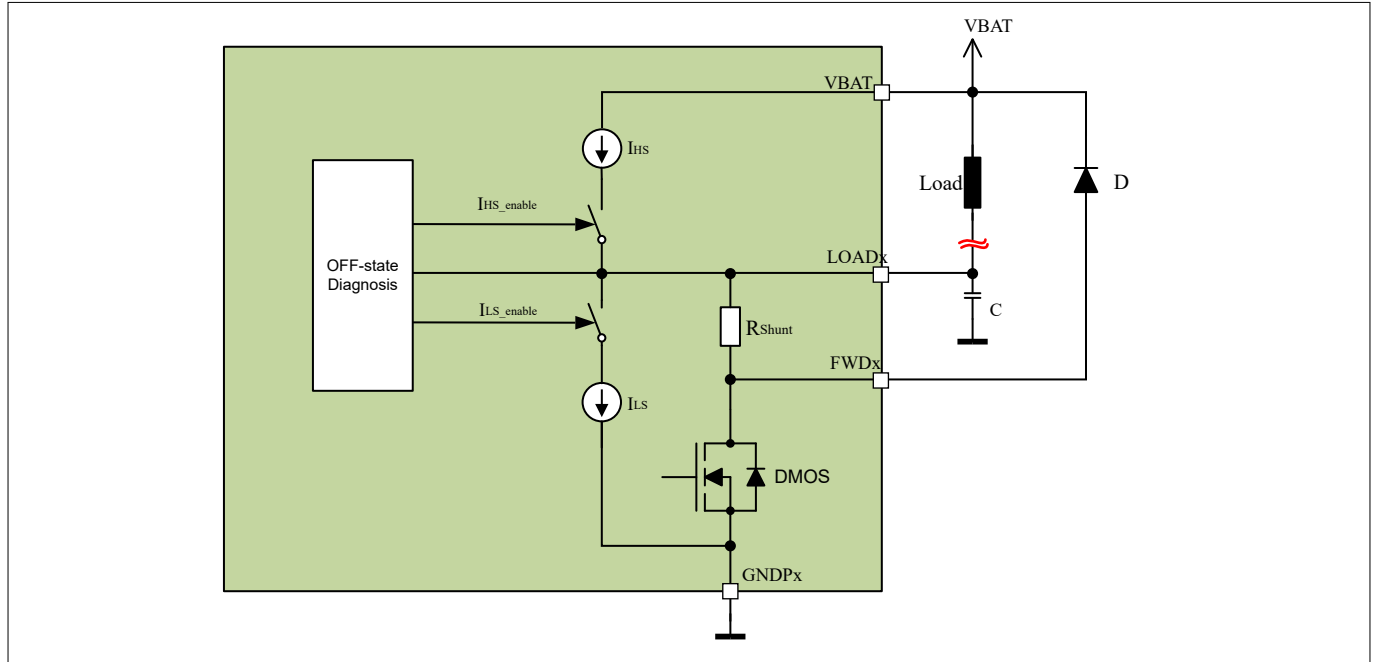


Figure 18 Open load

4.9.5 TDS_Short circuit ground (SG)

In the ON-state, a short circuit to ground is detected via the <OLSG> bit in the DIAG_ERR_CHGR register. The final fault discrimination to identify a short circuit to ground is done by the OFF-state diagnostic. The device indicates the fault by setting the respective <SG> bit in the DIAG_ERR_CHGR register. The device keeps the channel disabled until the fault is removed, the diagnosis bit is cleared and the <EN_CH> bit is set to “1” again.

Functional description

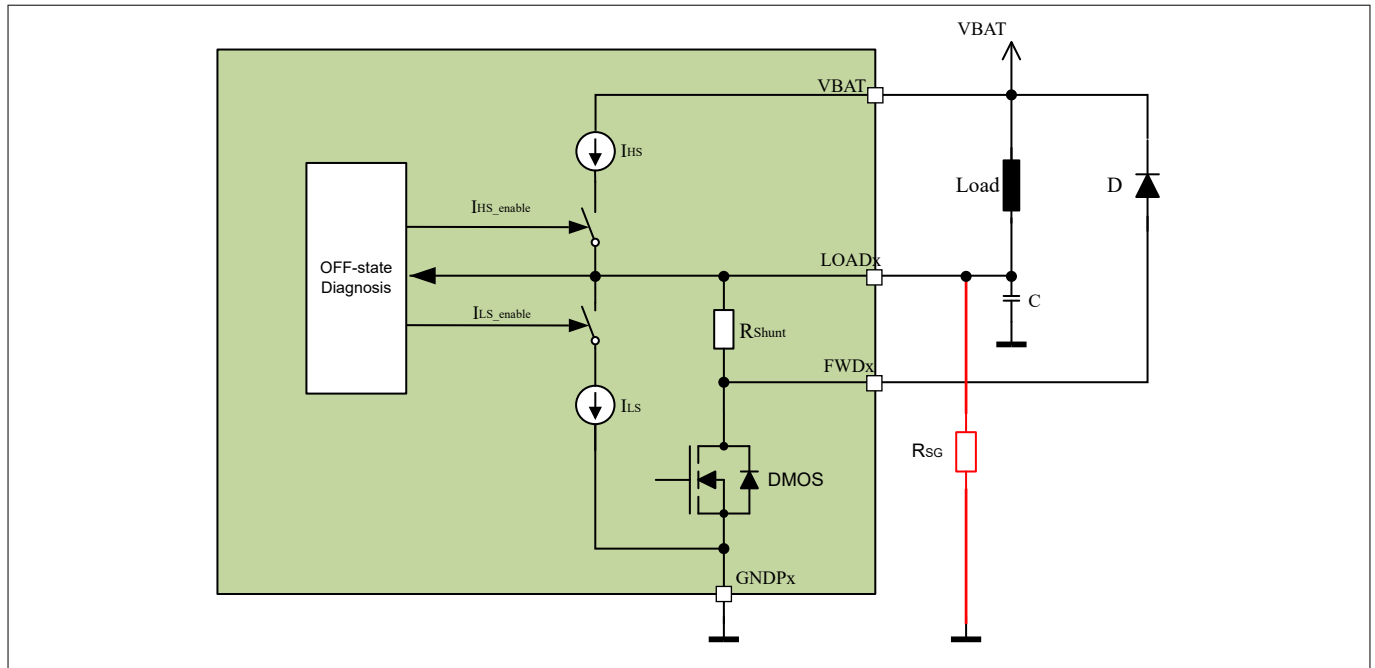


Figure 19 Short to Ground

4.9.6 TDS_Overcurrent (OC)

An overcurrent fault (OC) is an unintended low impedance connection between the LOAD terminal and the battery rail, therefore bypassing the load impedance.

An overcurrent is detected if a current flow through the power stage exceeds I_{OC} . Therefore the power stage must be turned on for a short period of time t_{OCOn} to detect an OC in OFF-state. The driver on-time t_{OCOn} can be triggered by setting the <OC_DIAG_EN> bit in the CH_CONFIG register and the respective <EN_CH> bit in the CH_CTRL register to 1. The driver on-time t_{OCOn} must be configured before executing the OC detection.

$$t_{OCOn} = \frac{(<TON_MANT> + 1) \cdot 2^{<EXP>}}{f_{SYS}}$$

Equation 17

The mantissa <TON_MANT> is located in the TON register and the exponent <EXP> is located in DITHER_CLK_DIV. An enabled OFF-state diagnosis is kept active during t_{OCOn} .

<OC_DIAG_EN> is reset after t_{OCOn} has expired. If an overcurrent is present, the <EN_CH> bit is cleared and the indication bit <OC> in the DIAG_ERR_CHGR register is set to 1. The device keeps the channel disabled until the fault is removed, the diagnosis bits are cleared by two clear commands and the <EN_CH> bit is set to "1" again.

Functional description

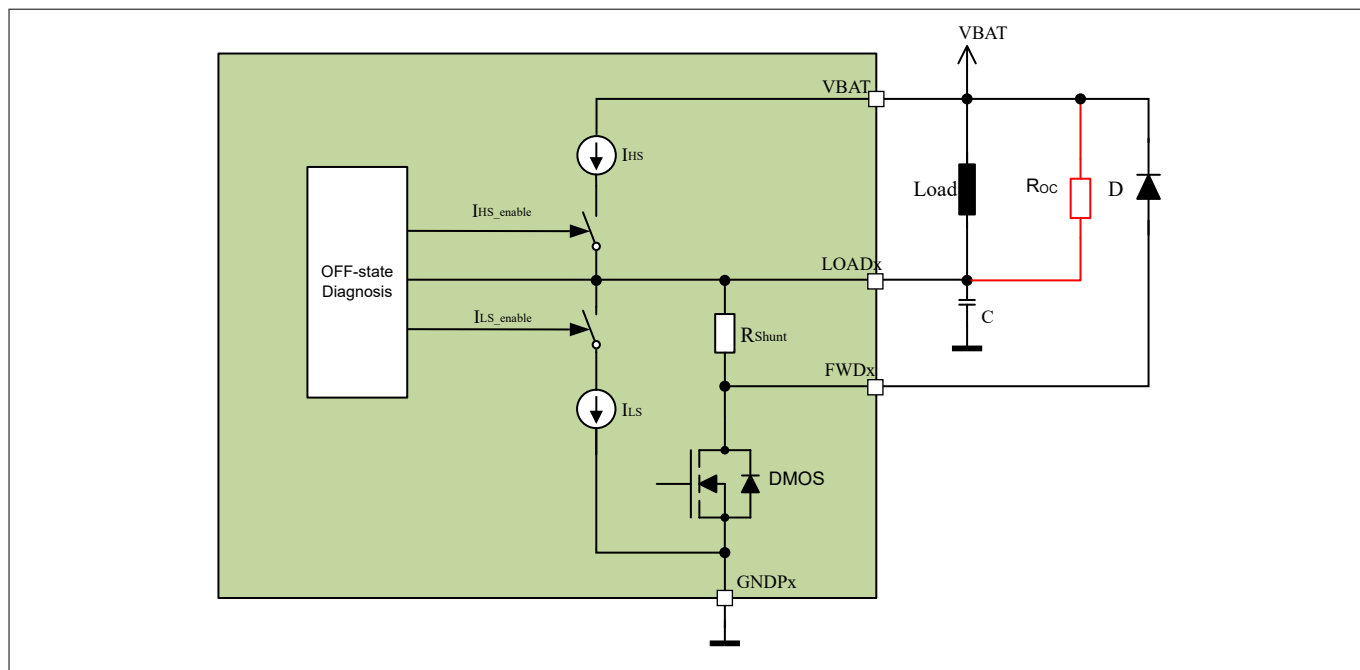


Figure 20 Overcurrent

4.9.7 TDS_Register/OTP ECC

A register/OTP (one time programmable memory) error will be detected by a continuous error checking and correction (ECC) mechanism. If a correction is not possible, a register/OTP ECC error is present and the <REG_ECC_ERR>/<OTP_ECC_ERR> bit in the GLOBAL_DIAG2 register will be set. The <OTP_ECC_ERR> can only be cleared by sending two clear commands. A register ECC error disables all power stages and the product enters the Operation State "Config Mode". The <OTP_VIRGIN> bit in the GLOBAL_DIAG2 indicates a non programmed OTP-memory. This bit must always be 0.

4.9.8 TDS_Built in Self Test (BIST)

The device provides a self-test in order to check the built in error detection and correction feature for safety critical registers. The BIST tests the ability to detect correctable and uncorrectable errors. The BIST can only be triggered in Config Mode by writing a '1' to the <SMU_SLF_TST_EN> bit in the SFF_BIST register. After the safety flip-flop BIST sequence is completed, the bits <SMU_SLF_TST_DONE>, <SMU_SLF_TST_UERR> and <SMU_SLF_TST_CERR> are set to indicate a finished test sequence.

The safety flip-flop BIST result is stored in the <SMU_SLF_TST_FAIL> bit in SFF_BIST register. All result and status bits in the SFF_BIST register are cleared on writing 0. A successfully tested safety flip-flop error (uncorrectable fault) sets the respective error bits <REG_ECC_ERR> in the GLOBAL_DIAG2 register.

4.9.9 Electrical characteristics diagnostic functions

Table 15 Electrical characteristics diagnostic functions

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
OLSG threshold single	I_{OLTH}	0	–	492	mA	fixed OLSG threshold in single channel mode

(table continues...)

Functional description

Table 15 (continued) Electrical characteristics diagnostic functions

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
OLSG threshold parallel	$I_{OLTH,parallel}$	0	-	984	mA	fixed OLSG threshold in parallel mode
OLSG filter detection time	T_{OLSGON}	-	2^{15}	-	cycles	f_{SYS} cycles
OFF-state $LOADx$ threshold voltage	$V_{TH_BAT/2}$	-	$V_{BAT}/2$	-	V	
OFF-state sequence time	$T_{off,sequence}$	1.2	-	4.8	ms	
Diagnosis Current 0	I_{HS} I_{LS}	30	80	120	μA	$\langle I_DIAG \rangle = 00_B$
Diagnosis Current 1	I_{HS} I_{LS}	105	190	275	μA	$\langle I_DIAG \rangle = 01_B$
Diagnosis Current 2	I_{HS} I_{LS}	510	720	910	μA	$\langle I_DIAG \rangle = 10_B$
Diagnosis Current 3	I_{HS} I_{LS}	910	1250	1520	μA	$\langle I_DIAG \rangle = 11_B$

4.10 Current supervision

4.10.1 TDS_Independent current feedback

The device provides independent current feedback paths to the microcontroller for plausibility checks on the load current. The average load current measured via the internal shunt can be read back directly. The independently measured duty cycle and battery voltage can be used to calculate the average load current using a load model.

Functional description

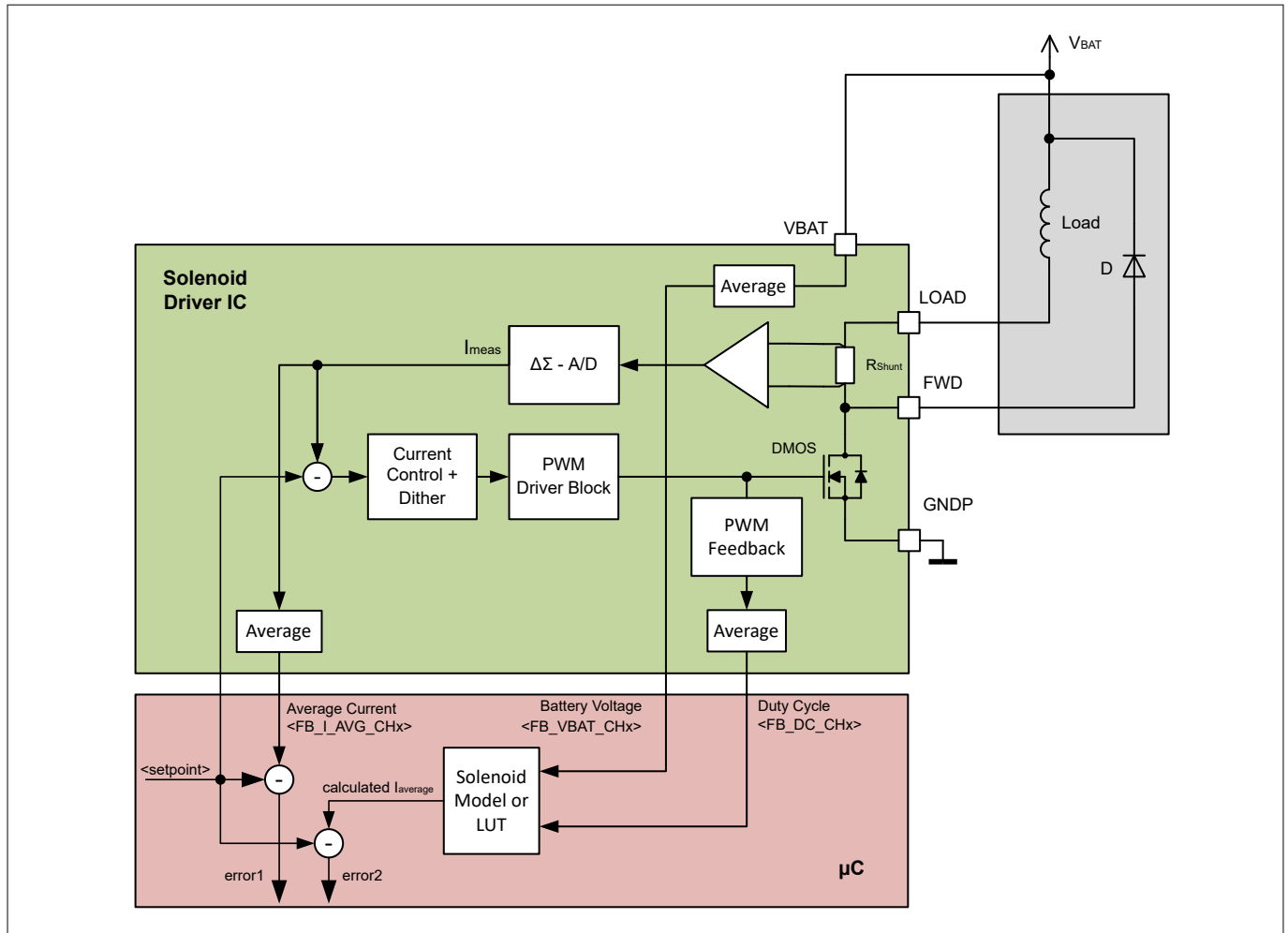


Figure 21 Current supervision

4.10.2 TDS_Average feedback values

The feedback values are provided in the registers FB_DC, FB_VBAT, FB_I_AVG. The feedback values averaged over the configured measurement period T_{meas} (see "Channel modes"). The register contents are updated after each measurement period T_{meas} .

The feedback values can be calculated as follows:

- Measurement period:

$$T_{meas} = \frac{\langle TP_MANT \rangle \cdot 2^{\langle EXP \rangle}}{f_{SYS}}$$

Equation 18

- PWM on time:

$$t_{on} = \frac{\langle TO_MANT \rangle \cdot 2^{\langle EXP \rangle}}{f_{SYS}}$$

Equation 19

- Duty cycle:

Functional description

$$DC = \frac{\langle TO_MANT \rangle}{\langle TP_MANT \rangle}$$

Equation 20

- Battery voltage:

$$V_{BAT} = 41.47V \cdot \frac{\langle VBAT_AVG_MANT \rangle}{\langle TP_MANT \rangle}$$

Equation 21

- Average load current (signed):

$$I_{avg} = 4A \cdot \frac{\langle I_AVG_MANT \rangle}{\langle TP_MANT \rangle}$$

Equation 22

The bitfields <TP_MANT> and <TO_MANT> are located in the FB_DC register. The bitfields <VBAT_AVG_MANT> and <EXP> are located in the FB_VBAT register. The bitfield <I_AVG_MANT> is located in the FB_I_AVG register. The bitfield <I_AVG_MANT> represents a signed current value (two's complement).

4.10.3 TDS_Update/Freeze Mechanism

The Update/Freeze mechanism should be applied for a correct readout of each measurement sample set. The IC indicates new feedback data by setting the respective <CH> bit in the FB_UPD register to 1. Setting <CH> bit in the FB_FRZ register to 1, stops the updating and freezes the latest measurement results of the feedback registers FB_DC, FB_VBAT, FB_I_AVG, FB_PERIOD_MIN_MAX, FB_IMIN_IMAX. Setting the <CH> bit in the FB_FRZ register to 0, also clears the respective <CH> bit in the FB_UPD register and enables the update of the feedback values. Following state diagram shows a recommendation for the readout of the feedback values.

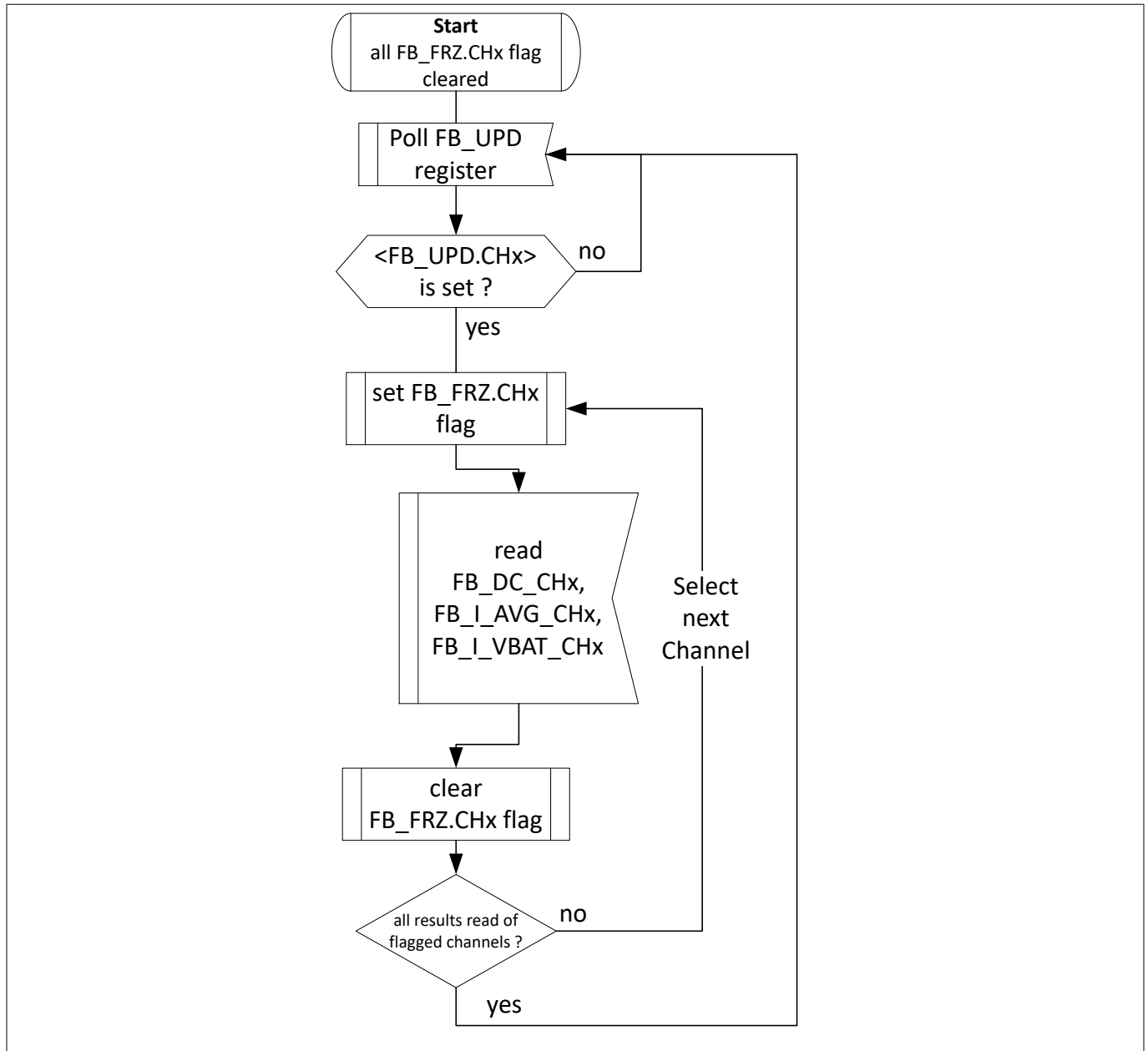


Figure 22 Readout proposal for feedback values

4.10.4 TDS_lavg16, minimum/maximum current/PWM feedback

The IC provides the average load current I_{avg16} over a free running period of 2^{16} system clocks, as a signed 16 bit value in the FB_I_AVG_s16 register. This value is not intended to be used while in closed loop operation or for current supervision. The value is provided as additional information and can be used for calibration purposes.

$$I_{avg16} = 4A \cdot \frac{\langle I_{AVG_s16} \rangle}{2^{16} - 1}$$

Equation 23

The IC provides measurements of the minimum (min) and maximum (max) current and PWM period. The min/max values represent the highest/lowest current and shortest/longest PWM period captured during a measurement period T_{meas} . If no measurement period T_{meas} is defined, the min/max registers are

Functional description

permanently updated when a new minimum or maximum current/PWM has been measured. The current values are held in the FB_IMIN_IMAX register and the PWM values can be read out from the FB_PERIOD_MIN_MAX register. The current values in the FB_IMIN_IMAX register are represented as a signed 9 bit value (two's complement).

$$I_{min} = 4A \cdot \frac{\langle IMIN \rangle}{2^9 - 1}$$

$$I_{max} = 4A \cdot \frac{\langle IMAX \rangle}{2^9 - 1}$$

Equation 24

$$T_{PWM_min} = \langle PMIN \rangle \cdot \frac{256}{f_{SYS}}$$

$$T_{PWM_max} = \langle PMAX \rangle \cdot \frac{256}{f_{SYS}}$$

Equation 25

4.11 Protection functions

4.11.1 TDS_Overtemperature protection

The device provides protection against overtemperature by measuring the central IC temperature and every power stage temperature. If an overtemperature $T_{J,ot}$ is measured, the respective power stage is switched off and the respective <OT> bit in the DIAG_ERR_CHGRx register is set. A central overtemperature of the IC disables all power stages and sets the <COTERR> bit in the GLOBAL_DIAG0 register.

If the respective power stage has cooled down to $T_{J,ot} - T_H$, the power stage can be re-enabled. A pre-warning bit in the diagnostic register is set, if the power stage temperature exceeds the pre-warning threshold T_p .

The overtemperature detection can be tested by setting the <OT_TEST> bit in the GLOBAL_CONFIG register to "1". This test sets the overtemperature threshold to the lowest possible value and the according overtemperature indication bits should be asserted.

The device provides a temperature feedback T_{FB} which can be read out from the bitfield <TEMP_VALUE> in the FB_VOLTAGE2 register. The temperature feedback T_{FB} is given by

$$T_{FB} = \frac{\langle TEMP_VALUE \rangle \cdot 0.000593 - 0.819^{*})}{-0.0016^{*})} ^\circ C$$

Equation 26

If a higher accuracy of the temperature feedback T_{FB} is required, a calibration of the parameters $^{*})$ have to be done on system level.

4.11.2 TDS_Overcurrent protection

The maximum current through every power stage of the device is limited. An overcurrent condition is detected if the load current exceeds I_{OC} . The detection of an overcurrent takes maximum $t_{OC,DETECT}$. An overcurrent causes the channel to be switched off and is indicated by setting the respective <OC> bit in the DIAG_ERR_CHGR register to 1. The <OC> bit must be cleared by two SPI write commands.

Functional description

4.11.3 Electrical characteristics protection functions

4.11.3.1 Overtemperature protection

Table 16 Overtemperature protection

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Overtemperature pre-warning threshold	T_P	150	-	175	$^{\circ}\text{C}$	
Overtemperature threshold	$T_{J,OT}$	175	-	200	$^{\circ}\text{C}$	
Thermal hysteresis	T_H	10	-	15	$^{\circ}\text{C}$	
Temperature feedback accuracy	T_{FB}	-20	-	20	$^{\circ}\text{C}$	

4.11.3.2 Overcurrent protection

Table 17 Overcurrent protection

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Overcurrent protection threshold	I_{OC}	2.05	-	6	A	
Overcurrent protection filter time	$t_{OC,DETECT}$	-	-	1.5	μs	$f_{SYS} = 28\text{ MHz}$

5 Serial peripheral interface (SPI)

5.1 Description of interface

5.1.1 TDS_General information

The communication interface is based on a standard serial peripheral interface (SPI). The SPI is a full duplex synchronous serial slave interface which uses four signal lines: SO, SI, SCK, and CSN. Data is transferred by the lines SI and SO at the data rate given by SCK. The falling edge of CSN indicates the beginning of a data access. Data is sampled in on line SI at the falling edge of SCK and shifted out on line SO at the rising edge of SCK. Each access must be terminated by a rising edge of CSN. A counter ensures that data is taken only when 32 bits have been transferred. If the number of bits transferred is not 32, the data frame is ignored.

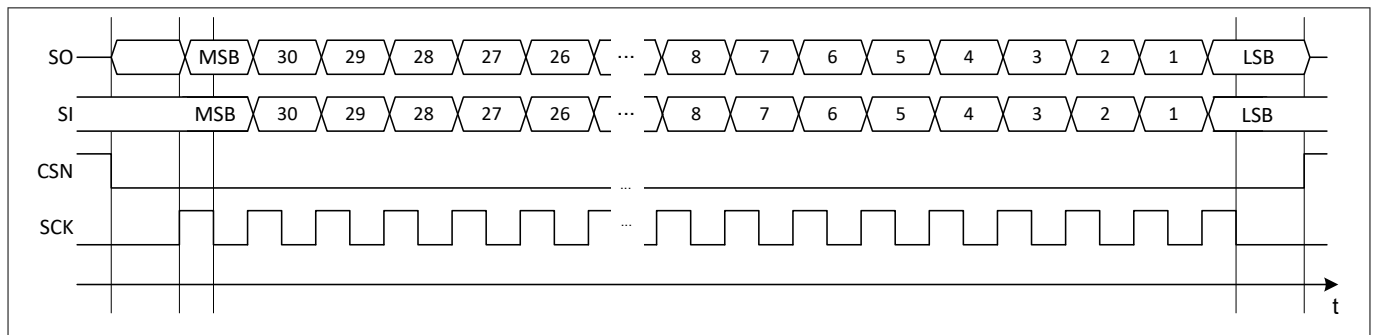


Figure 23 SPI signal overview

5.1.2 TDS_Cyclic redundancy check (CRC)

An 8-bits cyclic redundancy code (CRC-8 SAE-J1850) is added to all SPI communication frames to detect corrupt data and to avoid wrong configuration of the IC. The CRC-8 SAE-J1850 polynomial is used for the calculation:

$$x^8 + x^4 + x^3 + x^2 + 1 \text{ or } 0x1D$$

Note: CRC is supported by the flexible CRC engine (FCE) of Aurix TC26x, TC27x and TC29x.

The initial value of the CRC-byte is 0xFF. The CRC result is XOR operated with 0xFF. The CRC-byte is located in the most significant byte of the SPI frame. The byte-sequence for the CRC calculation is as follows:

1st byte: SPI frame[7:0]

2nd byte: SPI frame[15:8]

3rd byte: SPI frame[23:16]

Different generator polynomials are supported by the frame encoder/decoder entity definition, but the specific implementation is not part of the reuse module. The product designer has to modify the frame encoder/decoder source code within the project design environment accordingly.

The CRC byte is located in the most significant frame byte [31:24]. Whenever a SPI frame CRC error is detected, a SPI 16 bit reply frame indicating the SPI CRC error status is send in the subsequent SPI transaction.

The CRC check can be disabled by setting the <CRC_EN> bit in the GLOBAL_CONFIG register to "0".

5.1.3 TDS_Timing Diagram

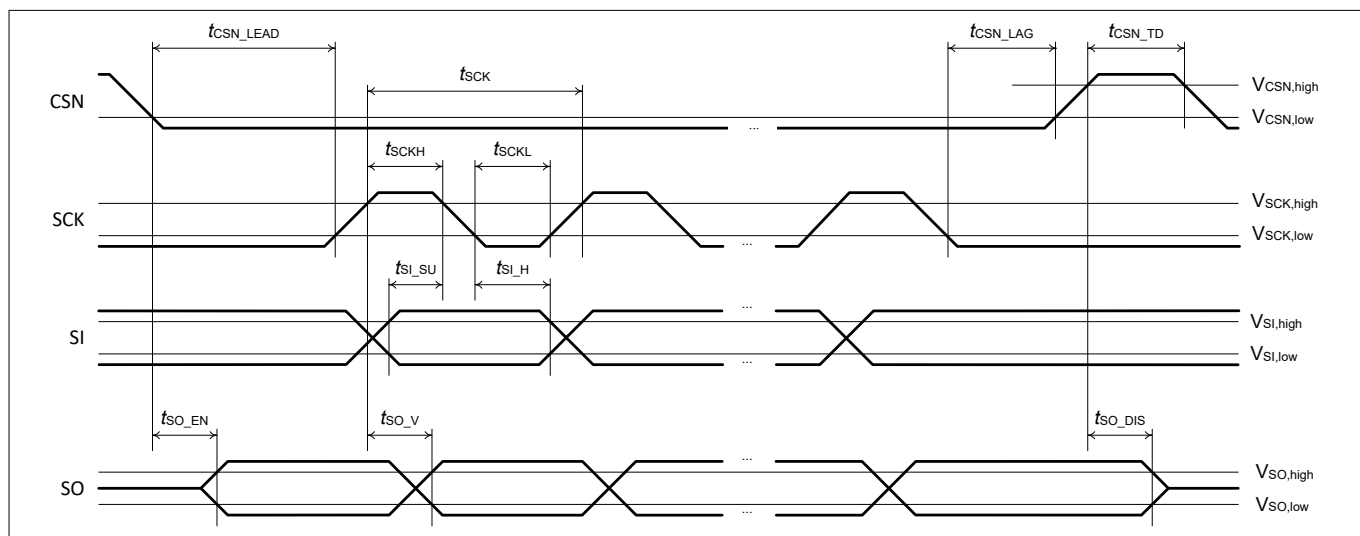


Figure 24 SPI Signal Timing Diagram

5.1.4 Electrical characteristics SPI interface

Table 18 Electrical characteristics SPI interface

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Serial clock high time	t_{SCKH}	50	–	–	ns	
Serial clock low time	t_{SCKL}	50	–	–	ns	
Enable lead time	t_{CSN_LEAD}	250	–	–	ns	falling CSN to rising SCK
Enable lag time	t_{CSN_LAG}	250	–	–	ns	falling SCK to rising CSN
Transfer delay time	t_{CSN_TD}	600	–	–	ns	rising CSN to falling CSN
Data setup time	t_{SI_SU}	20	–	–	ns	required time SI to falling SCK
Data hold time	t_{SI_H}	20	–	–	ns	required time falling SCK to SI
Output disable time	t_{SO_DIS}	–	–	200	ns	rising CSN to SO tri-state $C_L = 150\text{ pF}$
Output enable time	t_{SO_EN}	–	–	200	ns	falling CSN to SO valid $C_L = 150\text{ pF}$
Output data valid time	t_{SO_V}	–	–	100	ns	$C_L = 150\text{ pF}$

(table continues...)

Serial peripheral interface (SPI)

Table 18 (continued) Electrical characteristics SPI interface

$T_J = -40^{\circ}\text{C}$ to 150°C ; $V_{DD} = 4.5 - 5.5\text{ V}$; $V_{IO} = 3.0 - 5.5\text{ V}$; $V_{BAT} = 6 - 18\text{ V}$; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified).

Parameter	Symbol	Values			Unit	Note or condition
		Min.	Typ.	Max.		
Functional range SPI clock frequency (SCK)	f_{SCK}	–	–	8	MHz	
SPI watchdog decrement frequency	$f_{\text{SPI,WD}}$	–	$f_{\text{SYS}} / 2^{14}$	–	MHz	$f_{\text{SYS}} = 28\text{ MHz}$
Input pin capacitance (CSN, SCK, SI, CLK)	C_{IN}	–	–	10	pF	$V_{\text{bias}} = 2\text{ V}$; $V_{\text{test}} = 20\text{ mVpp}$; $f = 1\text{ MHz}$
Output pin capacitance (SO)	$C_{\text{SO,HIZ}}$	–	–	15	pF	Tri-state Output $V_{\text{bias}} = 2\text{ V}$; $V_{\text{test}} = 20\text{ mVpp}$; $f = 1\text{ MHz}$
SPI High Threshold Voltage (SI, SCK, CSN)	$V_{\text{SI,high}}$ $V_{\text{SCK,high}}$ $V_{\text{CSN,high}}$	–	–	2	V	
SPI Low Threshold Voltage (SI, SCK, CSN)	$V_{\text{SI,low}}$ $V_{\text{SCK,low}}$ $V_{\text{CSN,low}}$	0.8	–	–	V	
SPI Input hysteresis (SI, SCK, CSN)	$V_{\text{IN,HYS,SI}}$ $V_{\text{IN,HYS,SCK}}$ $V_{\text{IN,HYS,CSN}}$	–	50	–	mV	
SPI output high voltage (SO)	$V_{\text{SO,high}}$	$V_{\text{IO}} - 0.5$	–	V_{IO}	V	pull down current $I_{\text{SO}} = -0.5\text{ mA}$; $3.0\text{ V} < V_{\text{IO}} < 5.5\text{ V}$
SPI output low voltage (SO)	$V_{\text{SO,low}}$	0	–	0.5	V	pull up current $I_{\text{SO}} = 0.5\text{ mA}$
SPI output leakage current (SO)	$I_{\text{SO,OFF}}$	–10	–	10	μA	$V_{\text{CSN}} > V_{\text{CSN,high}}$ $0\text{ V} < V_{\text{SO}} < V_{\text{IO}}$
Pull down current (SI, SCK)	$I_{\text{PD,SI}}$ $I_{\text{PD,SCK}}$	10	–	50	μA	$V_{\text{IN}} = 2\text{ V}$
Pull up current (CSN)	$I_{\text{PU,CSN}}$	–50	–	–10	μA	$V_{\text{CSN}} = 0.8\text{ V}$

5.2 Description of protocol

5.2.1 TDS_Data flow

The message from the microcontroller must be sent MSB first. The data from the SO pin is sent MSB first. For each command received at the SI pin of the SPI interface, a serial data stream is returned at the same time on the SO pin. The content of the SO data frame is dependent on the command which was received on the SI pin during the previous frame. A READ command (R/W = 0) returns the contents of the addressed register one SPI frame later. The data bits in the READ command are ignored.

A WRITE command (R/W = 1) will write the data bits in the SPI word to the addressed register. The actual contents of addressed register will be returned to the SPI master (microcontroller) during the next SPI frame.

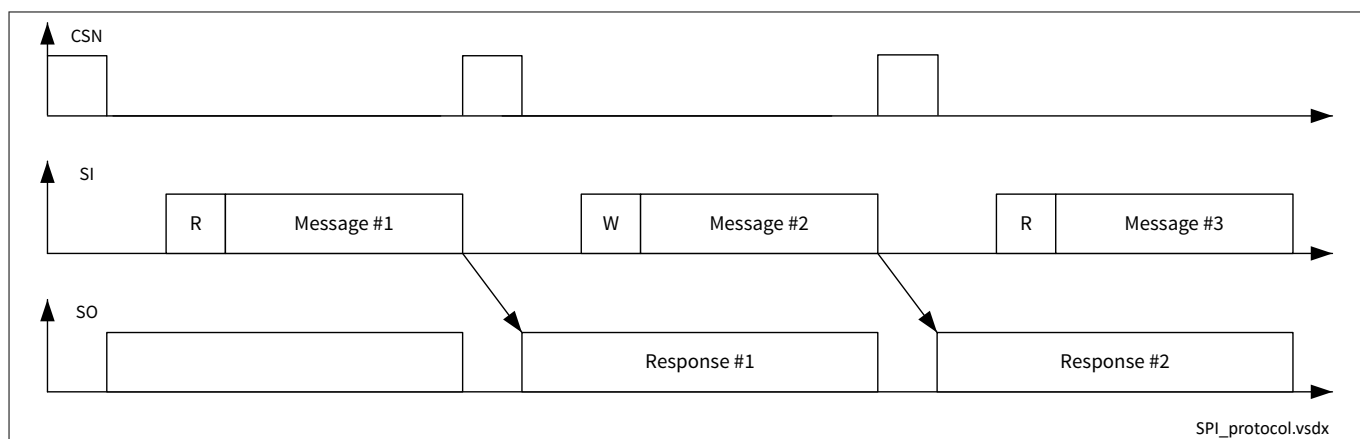


Figure 25 SPI protocol

5.2.2 TDS_SPI watchdog

An SPI watchdog checks the communication on the SPI bus. The SPI watchdog can be enabled by setting <SPI_WD_EN> in the GLOBAL_CONFIG register.

If the SPI watchdog is enabled, the <WD_TIME> value in the WD_RELOAD register is constantly decremented with $f_{SPI,WD}$. In order to avoid a SPI watchdog error, the WD_RELOAD register must be permanently updated.

If the <WD_TIME> value of the WD_RELOAD register transitions from 1 to 0, the <SPI_WD_ERR> bit in the GLOBAL_DIAG0 register is asserted and the IC transits to Config Mode.

As long as a SPI watchdog fault is present the device cannot enter Mission Mode. The SPI error indication bit <SPI_WD_ERR> is set to 0 if the WD_RELOAD register contains a non-zero value.

The SPI watchdog timeout $t_{SPI,WD}$ is given by:

$$t_{SPI,WD} = \frac{\langle WD_TIME \rangle}{f_{SPI,WD}}$$

Equation 27

5.2.3 SPI frame definition

5.2.3.1 TDS_MOSI - Write frame

MOSI SPI write frame

Data in frame of slave device

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
----	----	----	----	----	----	----	----	----	----	----	----	----	----	----	----

Serial peripheral interface (SPI)

CRC								Address							R/W
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Data															
Field		Bits	Description												
CRC		31:24	CRC check (SAE CRC8 J1850)												
Address		23:17	Address field												
R/W		16	MOSI Read/Write Indicator 0 _B : Read operation 1 _B : Write operation												
Data		15:0	Data bits are defined in register description												

5.2.3.2 TDS_MOSI - Read frame

MOSI SPI read frame
 Data in frame of slave device

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
CRC								-							R/W
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Address															
Field		Bits	Description												
CRC		31:24	CRC check (SAE CRC8 J1850)												
-		23:17	Don't care												
R/W		16	MOSI Read/Write Indicator 0 _B : Read operation 1 _B : Write operation												
Address		15:0	Read Address												

5.2.3.3 TDS_MISO - 16 bit reply frame

MISO SPI 16 bit reply frame
 16 bit data out frame of slave device

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
CRC								Reply Mode		Status					R/W
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Data															
Field		Bits	Description												
CRC		31:24	CRC check (SAE CRC8 J1850)												

Serial peripheral interface (SPI)

Field	Bits	Description
Reply Mode	23:22	Indicates type of reply frame: 00 _B : 16 bit Reply Frame 01 _B : 22 bit Reply Frame 10 _B : Critical Fault Frame
Status	21:17	Status indication of the current Frame: 00 _B : no error 01 _B : SPI frame error 10 _B : Parity/CRC error 11 _B : Write to read only register 100 _B /101 _B /110 _B : Internal bus fault <i>NOTE: The highest priority has the lowest encoding</i>
R/W	16	Indicator mirrored from previous MOSI frame 0 _B : Read indicator 1 _B : Write indicator
Data	15:0	Data bits are defined in register description

5.2.3.4 TDS_MISO - 22 bit reply frame

MISO SPI 22 bit reply frame

22 bit data out frame of slave device

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
CRC								0	1	Data					
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0

Data (cont'd)

Field	Bits	Description
CRC	31:24	CRC check (SAE CRC8 J1850)
Reply Mode	23:22	Indicates type of reply frame: 00 _B : 16 bit Reply Frame 01 _B : 22 bit Reply Frame 10 _B : Critical Fault Frame
Data	21:0	22 data bits used for feedback registers defined in register description

5.2.3.5 TDS_MISO - Critical fault reply frame

MISO SPI critical fault reply frame

Critical fault frame of slave device

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
Don't care								1	0	Don't care					

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Don't care (cont'd)								1V5	2V5	BG	CLK_ TOO _SLO W	CLK_ TOO _FAS T	DIG_ CLK_ TOO _SLO W	DIG_ CLK_ TOO _FAS T	WD_ REF_ CLK

Field	Bits	Description
Don't care	31:24	-
Reply Mode	23:22	Indicates type of reply frame: 00 _B : 16 bit Reply Frame 01 _B : 22 bit Reply Frame 10 _B : Critical Fault Frame
Don't care	21:8	-
1V5	7	0 _B : 1V5 supply not ok 1 _B : 1V5 supply ok
2V5	6	0 _B : 2V5 supply not ok 1 _B : 2V5 supply ok
BG	5	0 _B : ADC Bandgap not ok 1 _B : ADC Bandgap ok
CLK_TOO_SLOW	4	0 _B : No clock fault detected 1 _B : Clock is too slow for IC operation
CLK_TOO_FAST	3	0 _B : No clock fault detected 1 _B : Clock is too fast for IC operation
DIG_CLK_TOO_SLOW	2	0 _B : No clock fault detected 1 _B : Digital Clock is too slow <i>Note: clock watchdog must be enabled.</i>
DIG_CLK_TOO_FAST	1	0 _B : No clock fault detected 1 _B : Digital Clock is too fast <i>Note: clock watchdog must be enabled.</i>
WD_REF_CLK	0	0 _B : Clock watchdog reference clock is ok 1 _B : Clock watchdog reference clock is missing

5.3 Register description

5.3.1 Overview of Register Types

Bit type short name	Bit type description	Note
r	Bits are readable (read)	bitfields "RES" do not care
rh	Bits are readable (read) and modifiable by the IC (hardware)	bitfields "RES" do not care
rw	Bits are read- and writeable (read-write)	bitfields "RES" do not care, write "0"
rwh	Bits are read- and writeable (read-write) and modifiable by the IC (hardware)	bitfields "RES" do not care, write "0"

5.3.2 Central registers

5.3.2.1 Register overview - centralRegs (ascending offset address)

Table 19 Register overview - centralRegs (ascending offset address)

Short name	Long name	Offset address	Page number
CH_CTRL	Channel Control Register	0000 _H	55
GLOBAL_CONFIG	Global Configuration Register	0002 _H	55
GLOBAL_DIAG0	Global Diagnosis Register 0	0003 _H	56
GLOBAL_DIAG1	Global Diagnosis Register 1	0004 _H	57
GLOBAL_DIAG2	Global Diagnosis Register 2	0005 _H	58
VBAT_TH	VBAT Threshold Register	0006 _H	59
FB_FRZ	Feedback Freeze Register	0007 _H	59
FB_UPD	Feedback Update Register	0008 _H	60
WD_RELOAD	SPI Watchdog Register	0009 _H	61
DIAG_ERR_CHGR0	Diagnosis Error Register 0	000A _H	61
DIAG_ERR_CHGR1	Diagnosis Error Register 1	000B _H	62
DIAG_WARN_CHGR0	Diagnosis Warning Register 0	0010 _H	63
DIAG_WARN_CHGR1	Diagnosis Warning Register 1	0011 _H	64
FAULT_MASK0	Fault Mask Register 0	0016 _H	66
FAULT_MASK1	Fault Mask Register 1	0017 _H	66
FAULT_MASK2	Fault Mask Register 2	0018 _H	67
CLK_DIV	Clock Control Register	0019 _H	68
SFF_BIST	BIST Register	003F _H	68
ICVID	Version Register	0200 _H	69
PIN_STAT	Pin Status Register	0201 _H	70
FB_STAT	Feedback Status Register	0202 _H	70
FB_VOLTAGE1	Feedback Voltage Register 1	0203 _H	72
FB_VOLTAGE2	Feedback Voltage Register 2	0204 _H	73

5.3.2.2 Register address space - centralRegs

Table 20 Registers address space - centralRegs

Module	Base address	End address	Note
apb	00000000 _H	0000FFFF _H	

5.3.2.3 Channel Control Register

The channel enable bits EN_CHx can only be set in Mission mode. The parallel mode configuration bits CH_PAR_x can only be set in Config mode.

CH_CTRL Offset address: 0000_H
Channel Control Register value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
OP_M ODE	CH_ PAR_ 1_2	CH_ PAR_ 0_3	Res										EN_C H3	EN_C H2	EN_C H1	EN_C H0
undef	undef	undef	r										undef	undef	undef	undef

Field	Bits	Type	Description
EN_CH0	0	undef	Enable Channel 0 0 _B Disabled 1 _B Enabled
EN_CH1	1	undef	Enable Channel 1 0 _B Disabled 1 _B Enabled
EN_CH2	2	undef	Enable Channel 2 0 _B Disabled 1 _B Enabled
EN_CH3	3	undef	Enable Channel 3 0 _B Disabled 1 _B Enabled
CH_PAR_0_3	13	undef	Parallel Operation Channel 0/3 0 _B Disabled 1 _B Enabled
CH_PAR_1_2	14	undef	Parallel Operation Channel 1/2 0 _B Disabled 1 _B Enabled
OP_MODE	15	undef	Chip Operation Mode 0 _B Config Mode 1 _B Mission Mode

5.3.2.4 Global Configuration Register

Global Configuration Register: write access only possible in Config Mode

GLOBAL_CONFIG Offset address: 0002_H
Global Configuration Register value: 4005_H

TLE92464EDHP

High accuracy four channel low-side solenoid driver IC



Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	VIO_SEL	UV_OV_SWAP	OT_TEST	Res						V1V5_OV_TEST	V1V5_UV_TEST	Res	CRC_EN	SPI_WD_EN	CLK_WD_EN
r	undef	undef	undef	r						undef	undef	r	undef	undef	undef

Field	Bits	Type	Description
CLK_WD_EN	0	undef	Clock Watchdog 0 _B Disabled 1 _B Enabled
SPI_WD_EN	1	undef	SPI Watchdog 0 _B Disabled 1 _B Enabled
CRC_EN	2	undef	SPI CRC Check 0 _B Disabled 1 _B Enabled
V1V5_UV_TEST	4	undef	Test Internal Supply Undervoltage Detection 0 _B Disabled 1 _B Enabled
V1V5_OV_TEST	5	undef	Test Internal Supply Overvoltage Detection 0 _B Disabled 1 _B Enabled
OT_TEST	12	undef	Test Overtemperature Detection 0 _B Disabled 1 _B Enabled
UV_OV_SWAP	13	undef	Test Undervoltage/Overvoltage Detection 0 _B Disabled 1 _B Enabled
VIO_SEL	14	undef	VIO voltage selection 0 _B 3.3 V 1 _B 5.0 V

5.3.2.5 Global Diagnosis Register 0

Global Diagnosis Register 0

GLOBAL_DIAG0

Global Diagnosis Register 0

Offset address: 0003_H

value: 0600_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	SPI_WD_ERR	Res				POR_EVENT	RES_EVENT	COT_WARN	COTERR	CLK_NOK	VDD_OV	VDD_UV	VIO_OV	VIO_UV	VBAT_OV
r	undef	r				undef	undef	undef	undef	undef	undef	undef	undef	undef	undef

Field	Bits	Type	Description
VBAT_UV	0	undef	VBAT Undervoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VBAT_OV	1	undef	VBAT Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VIO_UV	2	undef	VIO Undervoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VIO_OV	3	undef	VIO Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VDD_UV	4	undef	VDD Undervoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VDD_OV	5	undef	VDD Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
CLK_NOK	6	undef	Clock Fault Detection 0 _B No Fault Detected 1 _B Fault Detected
COTERR	7	undef	Central Overtemperature Error 0 _B No Fault Detected 1 _B Fault Detected
COTWARN	8	undef	Central Overtemperature Warning 0 _B No Fault Detected 1 _B Fault Detected
RES_EVENT	9	undef	Reset occurred due to RESN-pin low 0 _B No Event Occurred 1 _B Event Occurred
POR_EVENT	10	undef	Event Occurred 0 _B No Event Occurred 1 _B A Power On Reset Event occurred since previous read out
SPI_WD_ERR	14	undef	SPI Watchdog Fault Detection 0 _B No Fault Detected 1 _B Fault Detected

5.3.2.6 Global Diagnosis Register 1

Global Diagnosis Register 1

GLOBAL_DIAG1

Offset address:

0004_H

Serial peripheral interface (SPI)

Global Diagnosis Register 1

value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
HVADC_ERR	Res								VPRE_OV	REF_OV	REF_UV	VDD2V5_OV	VDD2V5_UV	VR_IREF_OV	VR_IREF_UV
undef	r								undef	undef	undef	undef	undef	undef	undef

Field	Bits	Type	Description
VR_IREF_UV	0	undef	Internal Bias Current too Low Detection 0 _B No Fault Detected 1 _B Fault Detected
VR_IREF_OV	1	undef	Internal Bias Current too High Detection 0 _B No Fault Detected 1 _B Fault Detected
VDD2V5_UV	2	undef	Internal 2V5 Supply Undervoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VDD2V5_OV	3	undef	Internal 2V5 Supply Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
REF_UV	4	undef	Internal Reference Undervoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
REF_OV	5	undef	Internal Reference Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
VPRE_OV	6	undef	Internal Pre-Regulator Overvoltage Detection 0 _B No Fault Detected 1 _B Fault Detected
HVADC_ERR	15	undef	Internal Monitoring ADC Error Detection 0 _B No Fault Detected 1 _B Fault Detected

5.3.2.7 Global Diagnosis Register 2

Global Diagnosis Register 2

GLOBAL_DIAG2

Global Diagnosis Register 2

Offset address: 0005_H

value: 0000_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res											OTP_VIRG_IN	OTP_ECC_ERR	Res	REG_ECC_ERR	Res
r											undef	undef	r	undef	r

Field	Bits	Type	Description
REG_ECC_ERR	1	undef	Register ECC Error 0 _B No Error 1 _B Multi Bit Flip Detected
OTP_ECC_ERR	3	undef	OTP ECC Error 0 _B No Error 1 _B None Repairable Multi Bit Flip Detected
OTP_VIRGIN	4	undef	OTP Memory Configured Complete 0 _B OTP completely configured 1 _B Virgin OTP Address Detected

5.3.2.8 VBAT Threshold Register

VBAT Over and Under Voltage Threshold Register

VBAT_TH

VBAT Threshold Register

Offset address: 0006_H

value: FF19_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
VBAT_OV_TH								VBAT_UV_TH							
undef								undef							

Field	Bits	Type	Description
VBAT_UV_TH	7:0	undef	VBAT Undervoltage Threshold $V_{BAT_UV} = <VBAT_UV_TH> * 0.16208\text{ V}$
VBAT_OV_TH	15:8	undef	VBAT Overvoltage Threshold $V_{BAT_OV} = <VBAT_OV_TH> * 0.16208\text{ V}$

5.3.2.9 Feedback Freeze Register

Feedback Freeze Register

Feedback Values are provided in the registers FB_DC, FB_VBAT, FB_I_AVG

FB_FRZ

Feedback Freeze Register

Offset address: 0007_H

value: 0000_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res												FR_C H3	FR_C H2	FR_C H1	FR_C H0
r												rw	rw	rw	rw

Field	Bits	Type	Description
FR_CH0	0	rw	Freeze of CH0 Feedback Values 0 _B Disabled 1 _B Enabled
FR_CH1	1	rw	Freeze of CH1 Feedback Values 0 _B Disabled 1 _B Enabled
FR_CH2	2	rw	Freeze of CH2 Feedback Values 0 _B Disabled 1 _B Enabled
FR_CH3	3	rw	Freeze of CH3 Feedback Values 0 _B Disabled 1 _B Enabled

5.3.2.10 Feedback Update Register

Feedback Update Register

Feedback Values are provided in the registers FB_DC, FB_VBAT, FB_I_AVG

FB_UPD

Feedback Update Register

Offset address: 0008_H

value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res												UD_ CH3	UD_ CH2	UD_ CH1	UD_ CH0
r												undef	undef	undef	undef

Field	Bits	Type	Description
UD_CH0	0	undef	Indication of CH0 Feedback Values Update 0 _B No new Feedback Values available 1 _B New Feedback Values available
UD_CH1	1	undef	Indication of CH1 Feedback Values Update 0 _B No new Feedback Values available 1 _B New Feedback Values available
UD_CH2	2	undef	Indication of CH2 Feedback Values Update 0 _B No new Feedback Values available 1 _B New Feedback Values available

(table continues...)

Serial peripheral interface (SPI)

(continued)

Field	Bits	Type	Description
UD_CH3	3	undef	Indication of CH3 Feedback Values Update 0 _B No new Feedback Values available 1 _B New Feedback Values available

5.3.2.11 SPI Watchdog Register

SPI Watchdog Counter Reload Register

WD_RELOAD Offset address: 0009_H
SPI Watchdog Register value: 0001_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res					WD_TIME										
r					undef										

Field	Bits	Type	Description
WD_TIME	10:0	undef	Reload value of SPI watchdog timeout t_{SPI_WD} <WD_TIME> = rounddown($t_{SPI_WD} * f_{SYS} / 2^{14}$)

5.3.2.12 Diagnosis Error Register 0

Diagnosis Error Register Channel Group 0

DIAG_ERR_CHGR0 Offset address: 000A_H
Diagnosis Error Register 0 value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res		OTE1	SG1	OC1	OL1	OLS G1	Res		OTE0	SG0	OC0	OL0	OLS G0		
r		undef	undef	undef	undef	undef	r		undef	undef	undef	undef	undef		

Field	Bits	Type	Description
OLSG0	0	undef	Open Load or Short to Ground Detection CH0 0 _B No Fault Detected 1 _B Fault Detected
OL0	1	undef	Open Load Detection CH0 0 _B No Fault Detected 1 _B Fault Detected
OC0	2	undef	Overcurrent Detection CH0 0 _B No Fault Detected 1 _B Fault Detected

(table continues...)

(continued)

Field	Bits	Type	Description
SG0	3	undef	Short to Ground Detection CH0 0 _B No Fault Detected 1 _B Fault Detected
OTE0	4	undef	Overtemperature Error Detection CH0 0 _B No Fault Detected 1 _B Fault Detected
OLSG1	8	undef	Open Load or Short to Ground Detection CH1 0 _B No Fault Detected 1 _B Fault Detected
OL1	9	undef	Open Load Detection CH1 0 _B No Fault Detected 1 _B Fault Detected
OC1	10	undef	Overcurrent Detection CH1 0 _B No Fault Detected 1 _B Fault Detected
SG1	11	undef	Short to Ground Detection CH1 0 _B No Fault Detected 1 _B Fault Detected
OTE1	12	undef	Overtemperature Error Detection CH1 0 _B No Fault Detected 1 _B Fault Detected

5.3.2.13 Diagnosis Error Register 1

Diagnosis Error Register Channel Group 1

DIAG_ERR_CHGR1

Offset address: 000B_H

Diagnosis Error Register 1

value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res		OTE3	SG3	OC3	OL3	OLSG3		Res		OTE2	SG2	OC2	OL2	OLSG2	
r		undef	undef	undef	undef	undef		r		undef	undef	undef	undef	undef	

Field	Bits	Type	Description
OLSG2	0	undef	Open Load or Short to Ground Detection CH2 0 _B No Fault Detected 1 _B Fault Detected
OL2	1	undef	Open Load Detection CH2 0 _B No Fault Detected 1 _B Fault Detected

(table continues...)

(continued)

Field	Bits	Type	Description
OC2	2	undef	Overcurrent Detection CH2 0 _B No Fault Detected 1 _B Fault Detected
SG2	3	undef	Short to Ground Detection CH2 0 _B No Fault Detected 1 _B Fault Detected
OTE2	4	undef	Overtemperature Error Detection CH2 0 _B No Fault Detected 1 _B Fault Detected
OLSG3	8	undef	Open Load or Short to Ground Detection CH3 0 _B No Fault Detected 1 _B Fault Detected
OL3	9	undef	Open Load Detection CH3 0 _B No Fault Detected 1 _B Fault Detected
OC3	10	undef	Overcurrent Detection CH3 0 _B No Fault Detected 1 _B Fault Detected
SG3	11	undef	Short to Ground Detection CH3 0 _B No Fault Detected 1 _B Fault Detected
OTE3	12	undef	Overtemperature Error Detection CH3 0 _B No Fault Detected 1 _B Fault Detected

5.3.2.14 Diagnosis Warning Register 0

Diagnosis Warning Register Channel Group 0

DIAG_WARN_CHGR0

Offset address: 0010_H

Diagnosis Warning Register 0

value: 1010_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res		OLS G_W ARN 1_CH K_N OK	OLS G_W ARN 1	OTW 1	I_RE G_W ARN 1	PWM _REG _WA RN1	Res		OLS G_W ARN 0_CH K_N OK	OLS G_W ARN 0	OTW 0	I_RE G_W ARN 0	PWM _REG _WA RN0		
r		undef	undef	undef	undef	undef	r		undef	undef	undef	undef	undef		

Field	Bits	Type	Description
PWM_REG_WARN0	0	undef	ICC PWM Regulation Warning Detection CH0 0 _B No Warning Detected 1 _B Warning Detected
I_REG_WARN0	1	undef	ICC Current Regulation Warning CH0 0 _B No Warning Detected 1 _B Warning Detected
OTW0	2	undef	Overtemperature Warning Detection CH0 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN0	3	undef	Open Load or Short to Ground Warning Detection CH0 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN0_CHK_NOK	4	undef	Open Load or Short to Ground Warning Detection performed CH0 0 _B OLSG Warning Detection performed 1 _B OLSG Warning Detection not possible
PWM_REG_WARN1	8	undef	ICC PWM Regulation Warning Detection CH1 0 _B No Warning Detected 1 _B Warning Detected
I_REG_WARN1	9	undef	ICC Current Regulation Warning CH1 0 _B No Warning Detected 1 _B Warning Detected
OTW1	10	undef	Overtemperature Warning Detection CH1 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN1	11	undef	Open Load or Short to Ground Warning Detection CH1 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN1_CHK_NOK	12	undef	Open Load or Short to Ground Warning Detection performed CH1 0 _B OLSG Warning Detection performed 1 _B OLSG Warning Detection not possible

5.3.2.15 Diagnosis Warning Register 1

Diagnosis Warning Register Channel Group 1

DIAG_WARN_CHGR1

Diagnosis Warning Register 1

Offset address: 0011_H

value: 1010_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res		OLS G_W ARN 3_CH K_N OK	OLS G_W ARN 3	OTW 3	I_RE G_W ARN 3	PWM _REG _WA RN3	Res		OLS G_W ARN 2_CH K_N OK	OLS G_W ARN 2	OTW 2	I_RE G_W ARN 2	PWM _REG _WA RN2		
r		undef	undef	undef	undef	undef	r		undef	undef	undef	undef	undef	undef	

Field	Bits	Type	Description
PWM_REG_WARN2	0	undef	ICC PWM Regulation Warning Detection CH2 0 _B No Warning Detected 1 _B Warning Detected
I_REG_WARN2	1	undef	ICC Current Regulation Warning CH2 0 _B No Warning Detected 1 _B Warning Detected
OTW2	2	undef	Overtemperature Warning Detection CH2 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN2	3	undef	Open Load or Short to Ground Warning Detection CH2 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN2_CHK_NOK	4	undef	Open Load or Short to Ground Warning Detection performed CH2 0 _B OLSG Warning Detection performed 1 _B Warning Detected
PWM_REG_WARN3	8	undef	ICC PWM Regulation Warning Detection CH3 0 _B No Warning Detected 1 _B Warning Detected
I_REG_WARN3	9	undef	ICC Current Regulation Warning CH3 0 _B No Warning Detected 1 _B Warning Detected
OTW3	10	undef	Overtemperature Warning Detection CH3 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN3	11	undef	Open Load or Short to Ground Warning Detection CH3 0 _B No Warning Detected 1 _B Warning Detected
OLSG_WARN3_CHK_NOK	12	undef	Open Load or Short to Ground Warning Detection performed CH3 0 _B OLSG Warning Detection performed 1 _B OLSG Warning Detection not possible

5.3.2.16 Fault Mask Register 0

FAULTN-pin Mask 0 Register

FAULT_MASK0

Fault Mask Register 0

Offset address: 0016_H

value: C00F_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
SUP_NOK_EXT_MASK	SUP_NO_K_IN_T_MASK	EN_PIN_MASK	Res										CH3_ERR_MASK	CH2_ERR_MASK	CH1_ERR_MASK	CH0_ERR_MASK
rw	rw	rw	r										rw	rw	rw	rw

Field	Bits	Type	Description
CH0_ERR_MASK	0	rw	OC0, SG0, OL0, OTE0, OLSG0 FAULTN-pin Indication 0 _B Disabled 1 _B Enabled
CH1_ERR_MASK	1	rw	OC1, SG1, OL1, OTE1, OLSG1 FAULTN-pin Indication 0 _B Disabled 1 _B Enabled
CH2_ERR_MASK	2	rw	OC2, SG2, OL2, OTE2, OLSG2 FAULTN-pin Indication 0 _B Disabled 1 _B Enabled
CH3_ERR_MASK	3	rw	OC3, SG3, OL3, OTE3, OLSG3 FAULTN-pin Indication 0 _B Disabled 1 _B Enabled
EN_PIN_MASK	13	rw	EN-pin Status at FAULTN-pin Indication 0 _B Disabled 1 _B Enabled
SUP_NOK_INT_MASK	14	rw	Internal Supply UV/OV at FAULTN-pin Indication (SUP_NOK_INT) 0 _B Disabled 1 _B Enabled
SUP_NOK_EXT_MASK	15	rw	External Supply UV/OV at FAULTN-pin Indication (SUP_NOK_EXT) 0 _B Disabled 1 _B Enabled

5.3.2.17 Fault Mask Register 1

FAULTN-pin Mask 1 Register

FAULT_MASK1

Fault Mask Register 1

Offset address: 0017_H

value: 700F_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	CLK_ LOW _MA SK	COTE RR_ MAS K	COT WAR N_M ASK	Res								CH3_ WAR N_M ASK	CH2_ WAR N_M ASK	CH1_ WAR N_M ASK	CH0_ WAR N_M ASK
r	rw	rw	rw	r								rw	rw	rw	rw

Field	Bits	Type	Description
CH0_WARN_M ASK	0	rw	CH0 Warning at FAULTN-pin Indication (OTW, I_REG_WARN, PWM_REG_WARN, OLSG_WARN) 0 _B Disabled 1 _B Enabled
CH1_WARN_M ASK	1	rw	CH1 Warning at FAULTN-pin Indication (OTW, I_REG_WARN, PWM_REG_WARN, OLSG_WARN) 0 _B Disabled 1 _B Enabled
CH2_WARN_M ASK	2	rw	CH2 Warning at FAULTN-pin Indication (OTW, I_REG_WARN, PWM_REG_WARN, OLSG_WARN) 0 _B Disabled 1 _B Enabled
CH3_WARN_M ASK	3	rw	CH3 Warning at FAULTN-pin Indication (OTW, I_REG_WARN, PWM_REG_WARN, OLSG_WARN) 0 _B Disabled 1 _B Enabled
COTWARN_MA SK	12	rw	Central Overtemperature Warning at FAULTN-pin Indication (COTWRN) 0 _B Disabled 1 _B Enabled
COTERR_MAS K	13	rw	Central Overtemperature Error at FAULTN-pin Indication (COTERR) 0 _B Disabled 1 _B Enabled
CLK_LOW_MA SK	14	rw	Clock too Slow at FAULTN-pin Indication (DIG_CLK_TOO_SLOW, CLK_TOO_SLOW) 0 _B Disabled 1 _B Enabled

5.3.2.18 Fault Mask Register 2

FAULTN-pin Mask 2 Register

FAULT_MASK2

Fault Mask Register 2

Offset address: 0018_H
value: C000_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
SPI_WD_MASK	DATA_ERR_MASK	Res													
rw	rw	r													

Field	Bits	Type	Description
DATA_ERR_MASK	14	rw	Data Error at FAULTN-pin Indication (DATA_ERR) 0 _B Disabled 1 _B Enabled
SPI_WD_MASK	15	rw	SPI Watchdog Fault at FAULTN-pin Indication (SPI_WD_ERR) 0 _B Disabled 1 _B Enabled

5.3.2.19 Clock Control Register

Clock Control Register: write access only possible in Config Mode

CLK_DIV Offset address: 0019_H
Clock Control Register value: 0438_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
EXT_CLK	PLL_REFDIV						PLL_FBDIV								
undef	undef						undef								

Field	Bits	Type	Description
PLL_FBDIV	8:0	undef	PLL feedback divider $\langle \text{PLL_FBDIV} \rangle = 56 \text{ MHz} * \langle \text{PLL_REFDIV} \rangle / f_{\text{CLK}}$
PLL_REFDIV	14:9	undef	PLL reference divider $\langle \text{PLL_REFDIV} \rangle = \text{round}(f_{\text{CLK}} / 1 \text{ MHz})$
EXT_CLK	15	undef	Clock Source Selection 0 _B Internal Clock 1 _B External clock (CLK-pin)

5.3.2.20 BIST Register

Built In Self Test (BIST) register: write access only possible in Config Mode

SFF_BIST Offset address: 003F_H
BIST Register value: 0000_H

Serial peripheral interface (SPI)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res											SMU _SLF _TST _CER _R	SMU _SLF _TST _UE _RR	SMU _SLF _TST _FAI _L	SMU _SLF _TST _DO _NE	SMU _SLF _TST _EN
r											undef	undef	undef	undef	undef

Field	Bits	Type	Description
SMU_SLF_TST_EN	0	undef	BIST Enable 0 _B BIST not triggered 1 _B BIST triggered
SMU_SLF_TST_DONE	1	undef	BIST Done 0 _B BIST not done 1 _B BIST done
SMU_SLF_TST_FAIL	2	undef	BIST Sequence 0 _B Passed 1 _B Failed
SMU_SLF_TST_UERR	3	undef	BIST Uncorrectable Errors 0 _B Not Tested 1 _B Tested
SMU_SLF_TST_CERR	4	undef	BIST Correctable Errors 0 _B Not Tested 1 _B Tested

5.3.2.21 Version Register

IC version and ID

ICVID

Offset address: 0200_H

Version Register

value: C1XX_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
MANUFACTURER								VERSION							
undef								undef							

Field	Bits	Type	Description
VERSION	7:0	undef	Chip Version FC _H B11 Design Step FD _H B12 Design Step FE _H B13 Design Step FF _H B15 Design Step
MANUFACTURER	15:8	undef	Manufacturer ID

5.3.2.22 Pin Status Register

Pin Status Feedback Register

PIN_STAT

Pin Status Register

Offset address: 0201_H

value: 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res									FAUL TN_F B	FAUL TN	EN	DRV3	DRV2	DRV1	DRV0
r									undef	undef	undef	undef	undef	undef	undef

Field	Bits	Type	Description
DRV0	0	undef	Logic Level of DRV0-pin 0 _B Low 1 _B High
DRV1	1	undef	Logic Level of DRV1-pin 0 _B Low 1 _B High
DRV2	2	undef	Logic Level of DRV2-pin 0 _B Low 1 _B High
DRV3	3	undef	Logic Level of DRV3-pin 0 _B Low 1 _B High
EN	4	undef	Logic Level of EN-pin 0 _B Low 1 _B High
FAULTN	5	undef	Internal Status of FAULTN-pin according to Fault Mask Configuration 0 _B Fault detected 1 _B No Fault detected
FAULTN_FB	6	undef	Logic Level of FAULTN-pin 0 _B Low 1 _B High

5.3.2.23 Feedback Status Register

General status register

FB_STAT

Feedback Status Register

Offset address: 0202_H

Reset values see: [Table 21](#)

											21	20	19	18	17	16
											INIT_DON E	SPI_WD_ ERR	Res			
											undef	undef	r			
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
ERR_ CHGR 1	ERR_ CHGR 0	SUP_ NO K_IN T	SUP_ NO K_EX T	DATA_ _err	POR_ _eve nt	RES_ _eve nt	COT WAR N	COTE RR	CLK_ NOK	Res	OLS G_W ARN_ _CH _K_N OK_ CHG R1	OLS G_W ARN_ _CH _K_N OK_ CHG R0	Res	DIAG_ WA RN_ CHG R1	DIAG_ WA RN_ CHG R0	
undef	undef	undef	undef	undef	undef	undef	undef	undef	undef	r	undef	undef	r	undef	undef	

Field	Bits	Type	Description
DIAG_WARN_C HGR0	0	undef	Current status of DIAG_WARN_CHGR0 register (excluding <OLSG_WARNx_CHK_NOK>) 0 _B No Warning detected 1 _B Warning detected
DIAG_WARN_C HGR1	1	undef	Current status of DIAG_WARN_CHGR1 register (excluding <OLSG_WARNx_CHK_NOK>) 0 _B No Warning detected 1 _B Warning detected
OLSG_WARN_ CHK_NOK_CH GR0	3	undef	Current status of <OLSG_WARNx_CHK_NOK> bit in the DIAG_WARN_CHGR0 register 0 _B No Warning detected 1 _B Warning detected
OLSG_WARN_ CHK_NOK_CH GR1	4	undef	Current status of <OLSG_WARNx_CHK_NOK> bit in the DIAG_WARN_CHGR1 register 0 _B No Warning detected 1 _B Warning detected
CLK_NOK	6	undef	Current status of CLK_NOK in GLOBAL_DIAG0 register 0 _B No Fault detected 1 _B Fault detected
COTERR	7	undef	Current status of COTERR in GLOBAL_DIAG0 register 0 _B No Fault detected 1 _B Fault detected
COTWARN	8	undef	Current status of COTWARN in GLOBAL_DIAG0 register 0 _B No Warning detected 1 _B Warning detected
RES_event	9	undef	Current status of RES_event in GLOBAL_DIAG0 register 0 _B No Reset Event 1 _B Reset occurred

Datasheet

Serial peripheral interface (SPI)

(continued)

Field	Bits	Type	Description
POR_event	10	undef	Current status of POR_event in GLOBAL DIAG0 register 0 _B No power on Reset 1 _B Power on Reset occurred
DATA_err	11	undef	Current status of <OTP_ECC_ERR>, <OTP_VIRGIN>, <HV_ADC_ERR> 0 _B No Fault detected 1 _B Fault detected
SUP_NOK_EXT	12	undef	Current status of <VIO_UV/OV>, <VDD_UV/OV>, <VBAT_UV/OV> 0 _B No Fault detected 1 _B Fault detected
SUP_NOK_INT	13	undef	Current status of <VDD2V5_UV/OV>, <REF_UV/OV>, <VR_IREF_UV/OV>, <VPRE_OV> 0 _B No Fault detected 1 _B Fault detected
ERR_CHGR0	14	undef	Current status of DIAG_ERR_CHGR1 register 0 _B No Fault detected 1 _B Fault detected
ERR_CHGR1	15	undef	Current status of DIAG_ERR_CHGR2 register 0 _B No Fault detected 1 _B Fault detected
SPI_WD_ERR	20	undef	Current status of <SPI_WD_ERR> 0 _B No Fault detected 1 _B Fault detected
INIT_DONE	21	undef	Chip Initialization 0 _B Not Done 1 _B Done

Table 21 Reset values of **FB_STAT**

Reset type	Reset value	Note
	10 0000 0000 0110 0001 1000 _B	

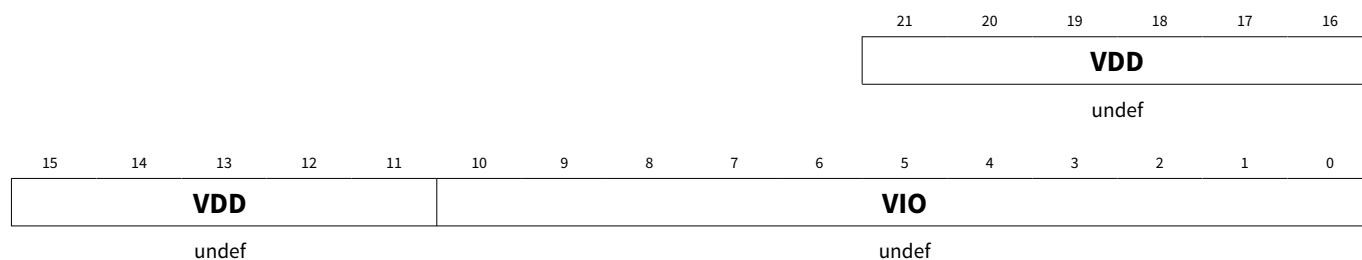
5.3.2.24 Feedback Voltage Register 1

Supply Voltage Feedback Register 1

FB_VOLTAGE1

Feedback Voltage Register 1

Offset address: 0203_H
value: XX XXXX_H



Field	Bits	Type	Description
VIO	10:0	undef	VIO Voltage $V_{IO} = 0.0034534 \text{ V} * <VIO>$
VDD	21:11	undef	VDD Voltage $V_{DD} = 0.0034534 \text{ V} * <VDD>$

5.3.2.25 Feedback Voltage Register 2

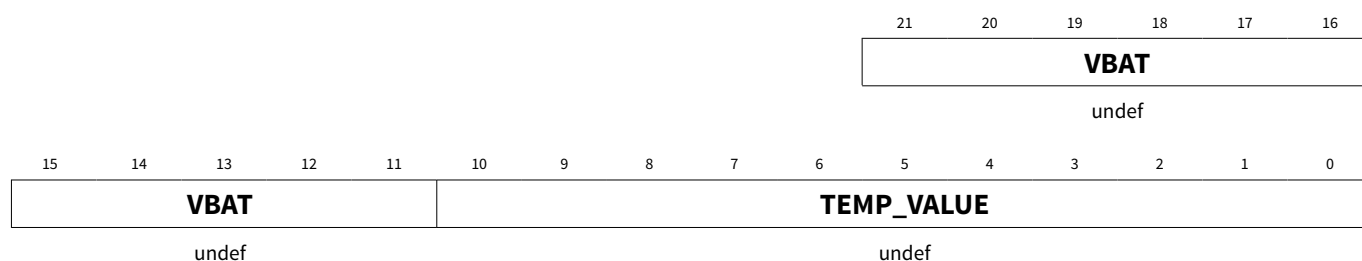
Supply Voltage Feedback Register 2

FB_VOLTAGE2

Feedback Voltage Register 2

Offset address: 0204_H

value: XX XXXX_H



Field	Bits	Type	Description
TEMP_VALUE	10:0	undef	Temperature Feedback $T_{FB} = (<TEMP_VALUE> * 0.000593 - 0.819) / (-0.0016) \text{ [Celsius]}$
VBAT	21:11	undef	VBAT Voltage $V_{BAT} = 41.47 \text{ V} * <VBAT> / (2^{11} - 1)$

5.3.3 Channel registers

5.3.3.1 Register Overview - channelRegs (ascending Offset Address)

Table 22 Register Overview - channelRegs (ascending Offset Address)

Short Name	Long Name	Offset Address	Page Number
SETPOINT	Setpoint Register	0000 _H	75
CTRL	Control Register	0001 _H	76
PERIOD	ICC PWM Frequency Controller Register	0002 _H	77
INTEGRATOR_LIMIT	ICC Integrator Limitation Register	0003 _H	78
DITHER_CLK_DIV	Dither Clock Register	0004 _H	79
DITHER_STEP	Dither Step Register	0005 _H	80
DITHER_CTRL	Dither Control Register	0006 _H	81
CH_CONFIG	Channel Configuration Register	0007 _H	82
MODE	Channel Mode Register	000C _H	84
TON	On-Time Register	000D _H	85
CTRL_INT_THRESH	ICC Integrator Threshold Control Register	000E _H	86
FB_DC	Feedback Duty Cycle Register	0200 _H	87
FB_VBAT	Feedback Average VBAT	0201 _H	88
FB_I_AVG	Feedback Average Current	0202 _H	89
FB_IMIN_IMAX	Feedback Min/Max Current	0203 _H	90
FB_I_AVG_s16	Feedback signed Current	0204 _H	91
FB_INT_THRESH	Feedback ICC Integrator Threshold	0205 _H	92
FB_PERIOD_MIN_MAX	Feedback Min/Max PWM Period	0206 _H	93

5.3.3.2 Register Address Space - channelRegs

Table 23 Registers Address Space - channelRegs

Module	Base Address	End Address	Note
CH0	00000040 _H	0001003E _H	
CH1	00000050 _H	0001004E _H	
CH2	00000060 _H	0001005E _H	
CH3	00000070 _H	0001006E _H	

5.3.3.3 Setpoint Register

Current Setpoint Register

SETPOINT Offset address: 0000_H
Setpoint Register Value 0000_H



Field	Bits	Type	Description
TARGET	14:0	rwh	Current Setpoint Target $I_{set} = 2A * <TARGET> / (2^{15} - 1)$ $I_{set,par} = 4A * <TARGET> / (2^{15} - 1)$ NOTE: Values higher than 0x6000 are saturated
AUTO_LIMIT_D IS	15	rwh	Autolimit Feature 0 _B Enabled 1 _B Disabled

5.3.3.4 Control Register

Channel Control Register

CTRL

Control Register

Offset address: 0001_H

Value 4600_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	OLSG_WARN_EN	OLSG_WARN_WINDOW						PWM_PERIOD_CALC_MODE	MIN_INT_THRESH						
r	rw	rw						rw	rw						

Field	Bits	Type	Description
MIN_INT_THRESHOLD	7:0	rw	Minimum limit for ICC integrator threshold The value is signed: -128 to 127
PWM_PERIOD_CALC_MODE	8	rw	ICC PWM controller does not consider falling Dither Slope 0 _B No disabling of threshold calculation 1 _B Skip threshold calculation on falling dither
OLSG_WARN_WINDOW	13:9	rw	OLSG Warning Detection Blanking Time $t_{OLwindow} = (<OLSG_WARN_WINDOW> + 1) * 64 * 1 / f_{sys}$
OLSG_WARN_EN	14	rw	OLSG Warning Detection 0 _B Disable warning 1 _B Enable warning

5.3.3.5 ICC PWM Frequency Controller Register

ICC PWM Frequency Controller Register

PERIOD Offset address: 0002_H
 ICC PWM Frequency Controller Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
PWM_CTRL_PARAM				LOW_FREQ_RANGE_EN	PERIOD_EXP			PERIOD_MANT							
rw				rw	rw			rw							

Field	Bits	Type	Description
PERIOD_MANT	7:0	rw	Mantissa of PWM Target Frequency $t_{\text{PWM}} = \text{<PERIOD_MANT>} * 2^{\text{<PERIOD_EXP>}} * 1/f_{\text{sys}}$ <PERIOD_MANT> = 0 disables the ICC PWM Frequency Controller
PERIOD_EXP	10:8	rw	Exponent of PWM Target Frequency $t_{\text{PWM}} = \text{<PERIOD_MANT>} * 2^{\text{<PERIOD_EXP>}} * 1/f_{\text{sys}}$
LOW_FREQ_RANGE_EN	11	rw	Low PWM Frequency Range $t_{\text{PWM}} = \text{<PERIOD_MANT>} * 8 * 2^{\text{<PERIOD_EXP>}} * 1/f_{\text{sys}}$ 0 _B Disabled 1 _B Enabled
PWM_CTRL_PARAM	15:12	rw	Control parameter ki of PWM Frequency Controller

5.3.3.6 ICC Integrator Limitation Register

ICC Integrator Limitation Register

INTEGRATOR_LIMIT

Offset address: 0003_H

ICC Integrator Limitation Register

Value 43FF_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	AUTO_LIM_VALUE_ABS					LIM_VALUE_ABS									
r	rw					rw									

Field	Bits	Type	Description
LIM_VALUE_ABS	9:0	rw	Absolut Integrator Limit of ICC
AUTO_LIM_VALUE_ABS	14:10	rw	Integrator Limit of ICC after a setpoint update (Autolimit)

5.3.3.7 Dither Clock Register

Dither Period Configuration

DITHER_CLK_DIV Offset address: 0004_H
Dither Clock Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
DITHER_SETPOINT_SYNC_EN	DITHER_PWM_SYNC_EN	EXP				MANT									
rw	rw	rw				rw									

Field	Bits	Type	Description
MANT	9:0	rw	Mantissa of Dither Reference Clock $t_{ref_clk} = (<MANT> * 2^{<EXP>}) * 1/f_{sys}$
EXP	13:10	rw	Exponent of Dither Reference Clock $t_{ref_clk} = (<MANT> * 2^{<EXP>}) * 1/f_{sys}$
DITHER_PWM_SYNC_EN	14	rw	Synchronization of Dither Period with PWM Period 0 _B Disabled 1 _B Enabled
DITHER_SETPOINT_SYNC_EN	15	rw	Synchronization of the Dither Period to a setpoint change 0 _B Disabled 1 _B Enabled

5.3.3.8 Dither Step Register

Dither Amplitude Configuration

DITHER_STEP Offset address: 0005_H
Dither Step Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
STEPS								FLAT							
rw								rw							

Field	Bits	Type	Description
FLAT	7:0	rw	Number of flat Dither Reference Clocks tref_clk on top and bottom of the Dither waveform $t_{\text{flat}} = \text{<FLAT>} * t_{\text{ref_clk}}$
STEPS	15:8	rw	Number of Dither steps within a quarter Dither Period $T_{\text{Dither}} = [4 * \text{<STEPS>} + 2 * \text{<FLAT>}] * t_{\text{ref_clk}}$ $I_{\text{Dither}} = \text{<STEPS>} * \text{<STEP_SIZE>} * 2 A / (2^{15} - 1)$ NOTE: If <STEP_SIZE> = 0, the dither overlay I_{Dither} is disabled. NOTE: If <STEPS> = 0, the dither overlay I_{Dither} is disabled and the dither period T_{Dither} is determined by <FLAT> NOTE: If <STEPS> = 0 and <FLAT> = 0, the dither period $T_{\text{Dither}} = t_{\text{ref_clk}}$

5.3.3.9 Dither Control Register

Dither Control Register

DITHER_CTRL Offset address: 0006_H
Dither Control Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res	DEE P_DI THE R	Res	STEP_SIZE												
r	rw	r	rw												

Field	Bits	Type	Description
STEP_SIZE	11:0	rw	Size of Dither Steps resulting in a Dither Amplitude IDither $I_{Dither} = \langle STEPS \rangle * \langle STEP_SIZE \rangle * 2 A / (2^{15}-1)$
DEEP_DITHER	13	rw	Deep Dither Feature 0 _B Disabled 1 _B Enabled

5.3.3.10 Channel Configuration Register

Channel Configuration Register

CH_CONFIG

Channel Configuration Register

Offset address: 0007_H

Value 0003_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
OFF_DIAG_C H		OC_ DIAG _EN	OL_TH_FIXED					OL_TH			I_DIAG		SLEWR		
rwh		rwh	rw					rw			rw		rw		

Field	Bits	Type	Description
SLEWR	1:0	rw	Channel Slew Rate 00 _B 1.0 V/us 01 _B 2.5 V/us 10 _B 5.0 V/us 11 _B 10.0 V/us
I_DIAG	3:2	rw	OFF-state Diagnosis Current Strength 00 _B 80 uA 01 _B 190 uA 10 _B 720 uA 11 _B 1250 uA
OL_TH	6:4	rw	Open Load Threshold relative to Setpoint 000 _B Disabled 001 _B 1/8 of Current Setpoint 010 _B 2/8 of Current Setpoint 011 _B 3/8 of Current Setpoint 100 _B 4/8 of Current Setpoint 101 _B 5/8 of Current Setpoint 110 _B 6/8 of Current Setpoint 111 _B 7/8 of Current Setpoint
OL_TH_FIXED	12:7	rw	Fixed Open Load Threshold $I_{OLTH} = \langle OL_TH_FIXED \rangle * 128 * 2000mA / (2^{15} - 1)$ $I_{OLTH,parallel} = \langle OL_TH_FIXED \rangle * 128 * 4000mA / (2^{15} - 1)$
OC_DIAG_EN	13	rwh	OC Diagnosis in OFF-state 0 _B Disabled 1 _B Enable Output Stage for t _{OCon} $t_{OCon} = [(\langle TON_MANT \rangle + 1) * 2^{\langle EXP \rangle}] * 1/f_{sys}$ NOTE: <TON_MANT> is located in the TON register. NOTE: <EXP> is located in the DITHER_CLK_DIV register.

(table continues...)

(continued)

Field	Bits	Type	Description
OFF_DIAG_CH	15:14	rwh	OFF-state Diagnosis Current Sources Control 00 _B OFF-state Diagnosis Enabled 01 _B Low Side Current Source Enabled 10 _B High Side Current Source Enabled 11 _B OFF-state Diagnosis Disabled

5.3.3.11 Channel Mode Register

Channel Mode Register: write access only possible in Config Mode

MODE Offset address: 000C_H
Channel Mode Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res												CH_MODE			
r												rw			

Field	Bits	Type	Description
CH_MODE	3:0	rw	Channel Operation Mode 0 _H Off 1 _H ICC Current Control 2 _H Direct Drive Mode via SPI on-time setting (TON register) 3 _H Direct Drive Mode via DRVx-pin C _H Free running Measurement (2 ¹⁶ samples)

5.3.3.12 On-Time Register

Driver On-Time Configuration Register

TON Offset address: 000D_H
On-Time Register Value 0000_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
OLSG_TIMEOUT						TON_MANT									
rw						rw									

Field	Bits	Type	Description
TON_MANT	9:0	rw	On-Time of Output stage (SPI Direct Drive Mode/OC-Detection) $t_{OCon} = [(<TON_MANT>+1) * 2^{<EXP>}] * 1/f_{sys}$ NOTE: For OC detection in OFF-state the maximum t_{on} period is 300ms and $<TON_MANT>$ must be different to 0. $t_{on} = (<TON_MANT> * 2^{<EXP>}) * 1/f_{sys}$ NOTE: The Period is derived from the Dither Period (DITHER_CLK_DIV) NOTE: $<EXP>$ is located in the DITHER_CLK_DIV register
OLSG_TIMEOUT	15:10	rw	Time out period for OLSG detection $t_{OLSG_TIMEOUT} = (<OLSG_TIMEOUT> * 256 + 255) * 64 * 1/f_{sys}$

5.3.3.13 ICC Integrator Threshold Control Register

ICC Integrator Threshold Control Register

CTRL_INT_THRESH

Offset address: 000E_H

ICC Integrator Threshold Control Register

Value 0003_H

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Res								INT_THRESH							
r								rw							

Field	Bits	Type	Description
INT_THRESH	8:0	rw	ICC Integrator Threshold which determines the on-time of the PWM period NOTE: <INT_THRESH> is used as initial threshold value for the ICC PWM Frequency Controller.

5.3.3.14 Feedback Duty Cycle Register

Duty Cycle Feedback Value

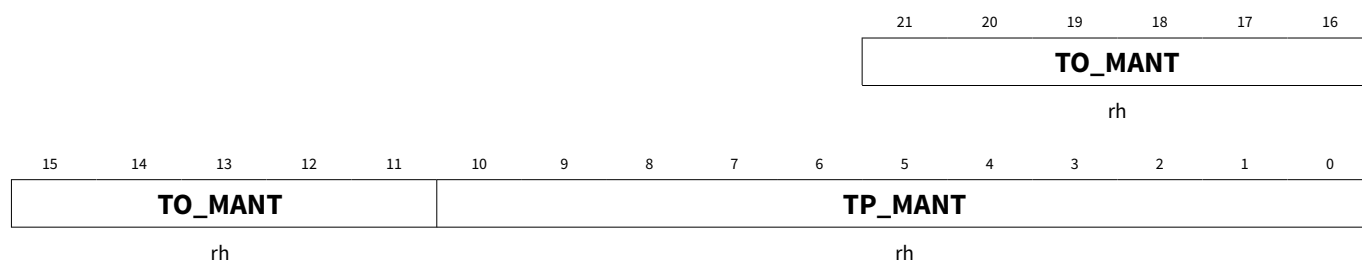
Read Only Register

FB_DC

Feedback Duty Cycle Register

Offset address: 0200_H

Value 00 0000_H



Field	Bits	Type	Description
TP_MANT	10:0	rh	Period Mantissa $T_{\text{meas}} = \text{TP_MANT} * 2^{\text{EXP}} * 1/f_{\text{sys}}$ NOTE: <EXP> is located in the FB_VBAT or FB_I_AVG register.
TO_MANT	21:11	rh	On-time Mantissa $t_{\text{ON}} = \text{TO_MANT} * 2^{\text{EXP}} * 1/f_{\text{sys}}$ $DC = \text{TO_MANT} / \text{TP_MANT}$ NOTE: <EXP> is located in the FB_VBAT or FB_I_AVG register.

5.3.3.15 Feedback Average VBAT

Average Battery Voltage (VBAT) Feedback Register

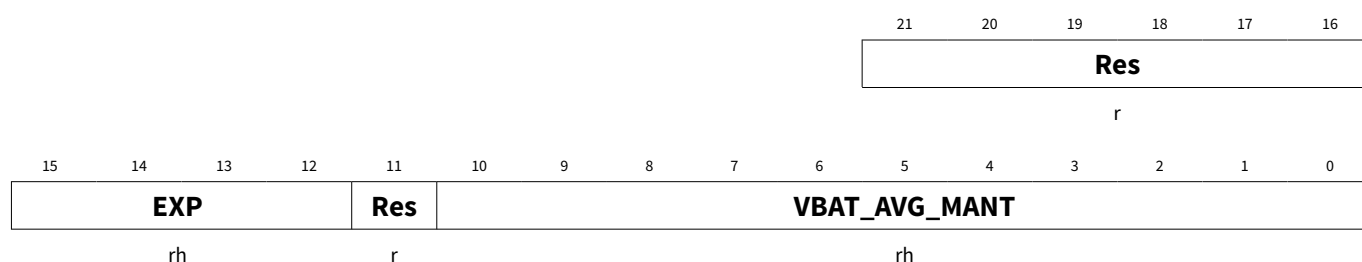
Read Only Register

FB_VBAT

Feedback Average VBAT

Offset address: 0201_H

Value 00 0000_H



Field	Bits	Type	Description
VBAT_AVG_MANT	10:0	rh	Average Battery Voltage Mantissa $V_{BAT} = 41.47V * <VBAT_AVG_MANT> / <TP_MANT>$ NOTE: <TP_MANT> is located in the FB_DC register
EXP	15:12	rh	Measurement Exponent

5.3.3.16 Feedback Average Current

Average Current Feedback Value

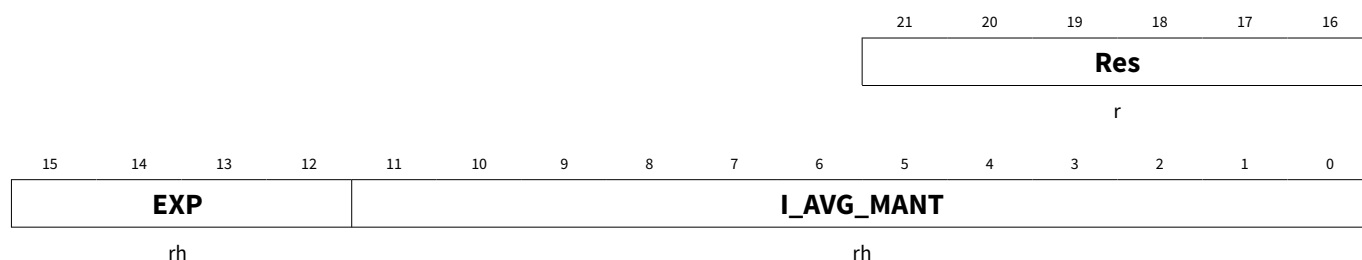
Read Only Register

FB_I_AVG

Feedback Average Current

Offset address: 0202_H

Value 00 0000_H



Field	Bits	Type	Description
I_AVG_MANT	11:0	rh	Signed Mantissa of Average Current Feedback (two's complement) $I_{avg} = 4A * <I_AVG_MANT> / <TP_MANT>$ NOTE: <TP_MANT> is located in the FB_DC register
EXP	15:12	rh	Measurement Exponent

5.3.3.17 Feedback Min/Max Current

Minimum/Maximum Current Feedback Register

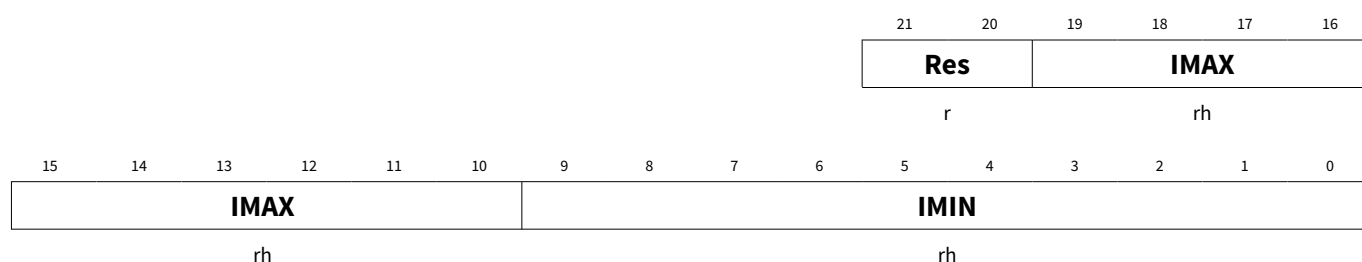
Read Only Register

FB_IMIN_IMAX

Feedback Min/Max Current

Offset address: 0203_H

Value 00 0000_H



Field	Bits	Type	Description
IMIN	9:0	rh	Signed Minimum Current of last measurement period (two's complement) $I_{min} = <IMIN> * 4A / (2^9 - 1)$
IMAX	19:10	rh	Signed Maximum Current of last measurement period (two's complement) $I_{max} = <IMAX> * 4A / (2^9 - 1)$

5.3.3.18 Feedback signed Current

Signed Average Current Measurement over free running period ($2^{16} f_{sys}$ cycles)

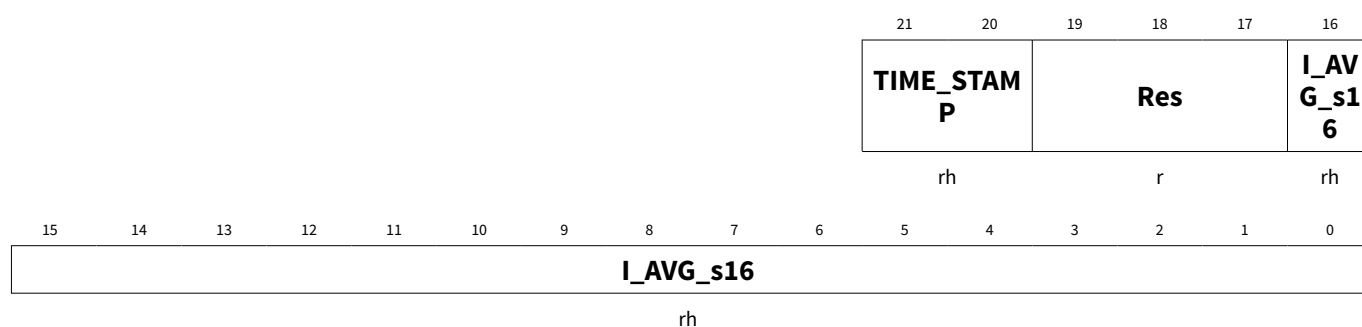
Read Only Register

FB_I_AVG_s16

Feedback signed Current

Offset address: 0204_H

Value 00 0000_H



Field	Bits	Type	Description
I_AVG_s16	16:0	rh	Average Current Measurement over free running period ($2^{16} f_{sys}$ cycles) - two's complement $I_{avg16} = 4A \cdot \langle I_AVG_s16 \rangle / (2^{16}-1)$
TIME_STAMP	21:20	rh	Time Stamp for signed Average Current Measurement over free running period

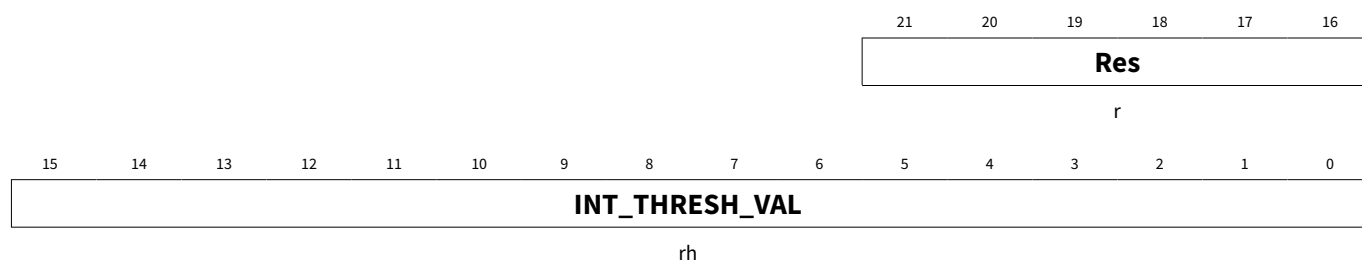
5.3.3.19 Feedback ICC Integrator Threshold

ICC PWM Frequency Controller Integrator Thershold Feedback
Read Only Register

FB_INT_THRESH

Feedback ICC Integrator Threshold

Offset address: 0205_H
Value 00 0180_H



Field	Bits	Type	Description
INT_THRESH_VAL	15:0	rh	ICC PWM Frequency Controller Calculated Integrator Threshold Value

5.3.3.20 Feedback Min/Max PWM Period

Minimum and Maximum PWM Frequency Feedback of last Measurement period

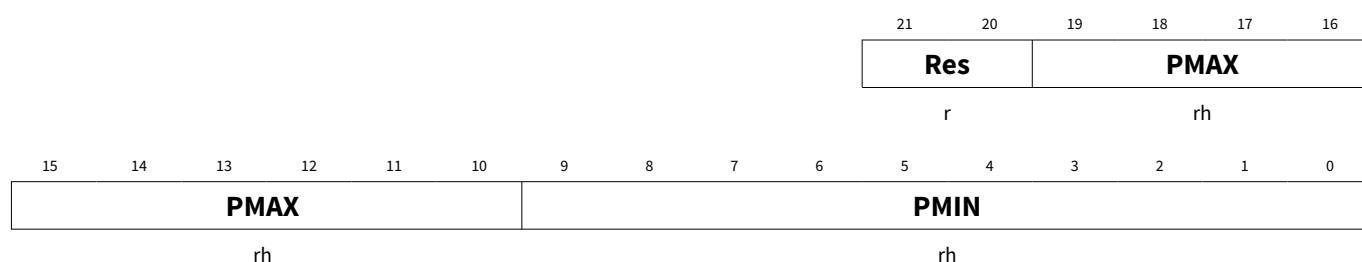
Read Only Register

FB_PERIOD_MIN_MAX

Feedback Min/Max PWM Period

Offset address: 0206_H

Value 00 0000_H



Field	Bits	Type	Description
PMIN	9:0	rh	Minimum PWM period of last Measurement period $f_{PWM_min} = f_{sys} / (<PMIN> * 256)$
PMAx	19:10	rh	Maximum PWM period of last Measurement period $f_{PWM_max} = f_{sys} / (<PMAx> * 256)$

Application information

6 Application information

6.1 TDS_Application information

The following application diagram shows how the IC is used in its environment.

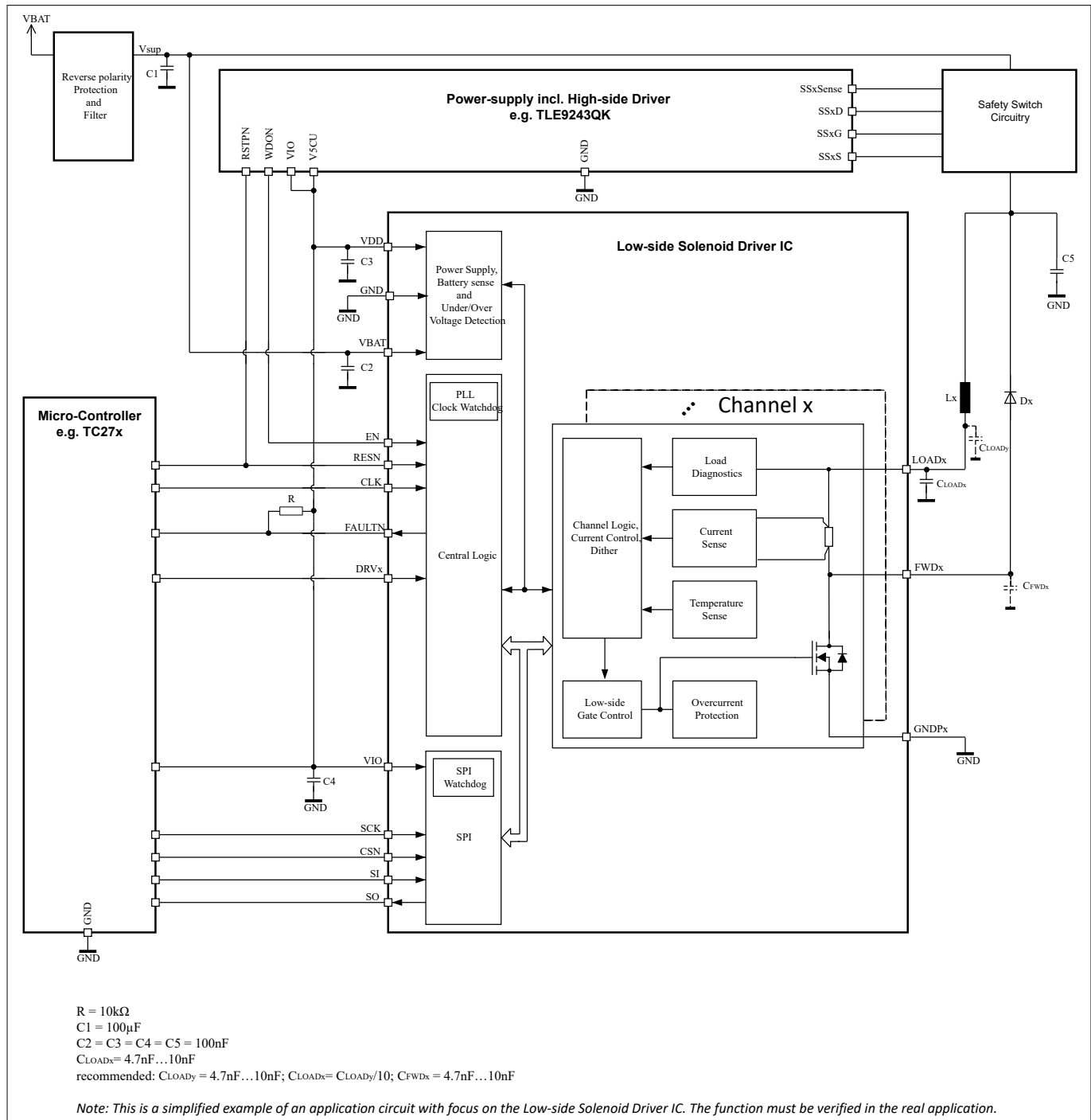


Figure 26 Simplified Application Circuit

Package dimensions

7 Package dimensions

7.1 TDS_Package dimensions

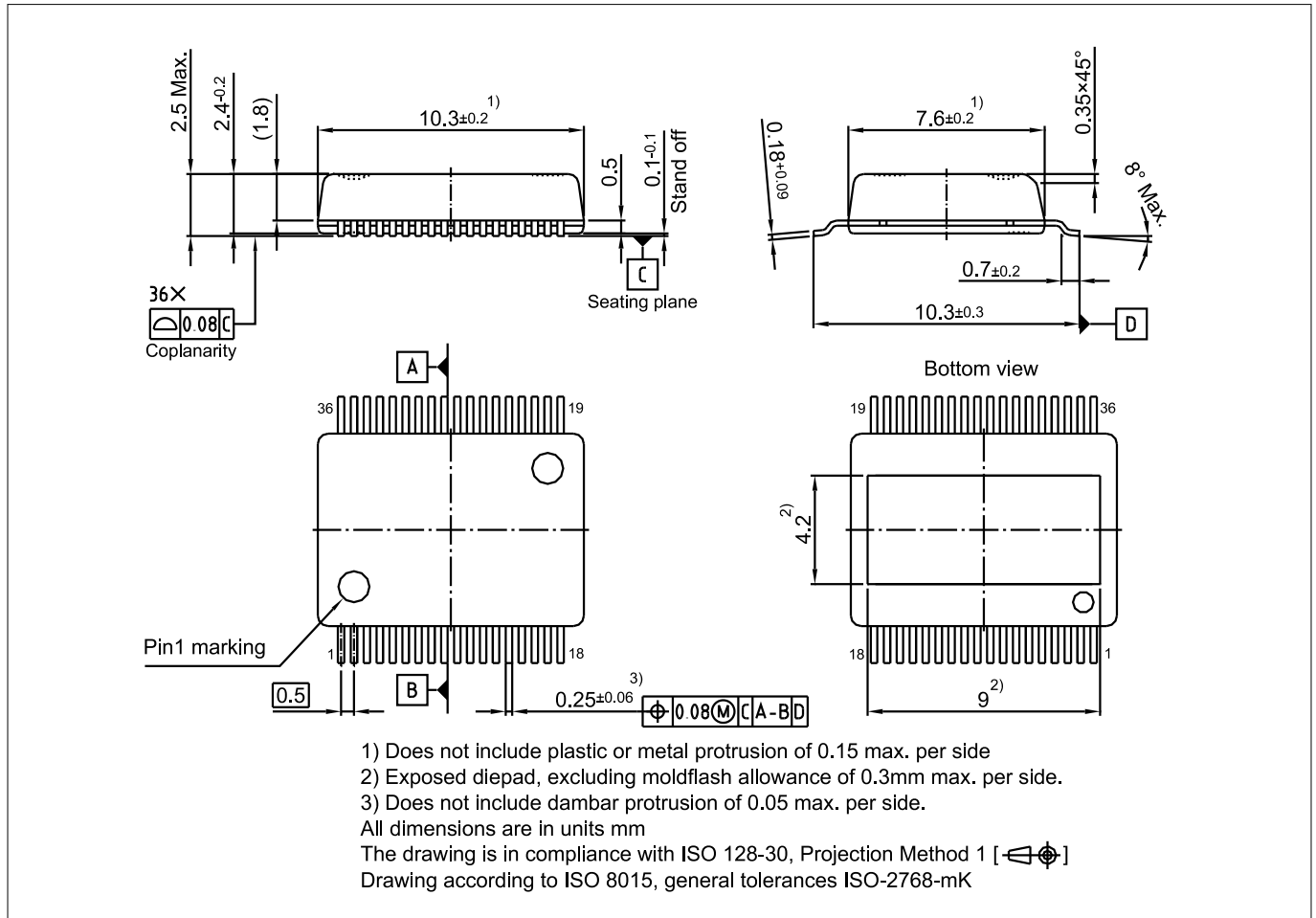


Figure 27 Package outlines

Green Product

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with the government regulations the device is available as a Green Product. Green Products are RoHS compliant (Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020).

Revision history

Revision history

Revision	Date	Changes
Datasheet v1.0	2021-12-15	Initial release

Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

Edition 2021-12-15

Published by
Infineon Technologies AG
81726 Munich, Germany

© 2021 Infineon Technologies AG
All Rights Reserved.

Do you have a question about any
aspect of this document?
Email: erratum@infineon.com

Document reference
IFX-ntz1491827137291

IMPORTANT NOTICE

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenhheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

[Infineon:](#)

[TLE92464EDHPXUMA1](#)